

LM5171-Q1 Dual Channel Bidirectional Controller

1 Features

- AEC-Q100 qualified for automotive applications:
 - Device temperature grade 1: -40°C to $+125^{\circ}\text{C}$ ambient operating range
 - Device HBM ESD classification level 2
 - Device CDM ESD classification level C4B
- [Functional Safety-Capable](#)
- 85-V HV-port and 80-V LV-port max ratings
- 1% Typical Accuracy of bidirectional current regulation
- 1% Typical Accuracy of channel current monitoring
- I²C Interface for monitoring and diagnosis
- Built-in 3.5V 1% reference voltage
- Integrated 5V 10mA bias supply
- 5-A Peak half-bridge gate drivers
- Programmable or adaptive dead-time control
- Programmable oscillator frequency up to 1MHz with optional synchronization to external clock
- Independent channel enabling control inputs
- Integrated both current and voltage loop control
- Programmable cycle-by-cycle peak current limit
- Over-temperature shutdown
- HV and LV port overvoltage protection
- Dynamically selectable diode emulation and forced PWM operation modes
- Programmable soft-start timer
- Support both multiphase and independent channel operations
- Support urgent shutdown latch

2 Applications

- [Automotive, Industrial dual-battery systems](#)
- [Battery Testing System \(BTS\)](#)
- [Super-cap or battery backup power converter](#)
- [Stackable high-power buck or boost applications](#)

3 Description

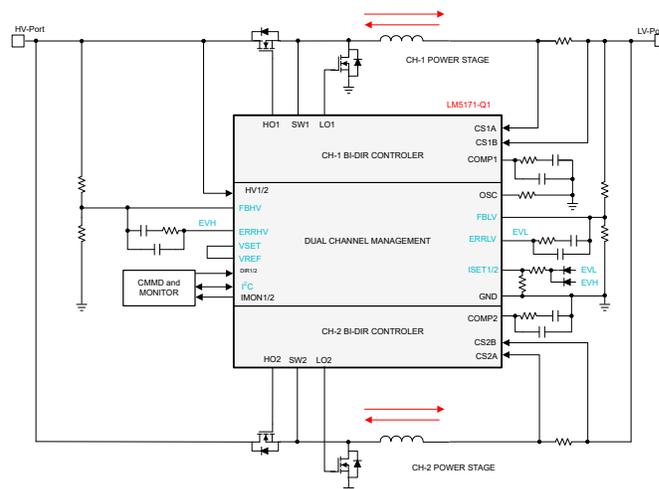
The LM5171-Q1 controller provides the essential high voltage and precision elements of a dual-channel bidirectional converter for example is automotive 48-V and 12-V dual battery systems. It supports multiphase parallel operation with balanced current sharing in each phase, and it can also support independent channel bi-directional operations making it versatile as standalone controller operating as Multiphase Buck / Boost or independent Buck or Boost.

The dual-channel differential current sense amplifiers and dedicated channel current monitors achieve typical accuracy of 1%. The robust 5-A half-bridge gate drivers are capable of driving parallel MOSFETs for scaling more power per channel. The controller can be dynamically programmed to operate in either the diode emulation mode (DEM) or forced PWM (FPWM) mode. Versatile protection features include cycle-by-cycle current limiting, overvoltage protection at both HV and LV ports, and overtemperature protection and urgent shutdown latch.

Device Information⁽¹⁾

PART NUMBER	PACKAGE	BODY SIZE (NOM)
LM5171-Q1	TQFP (48)	7.00 mm × 7.00 mm

(1) For all available packages, see the orderable addendum at the end of the data sheet.



Simplified Application Circuit

ADVANCE INFORMATION

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4 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

DATE	REVISION	NOTES
April 2023	*	Advance Information

5 Pin Configuration and Functions

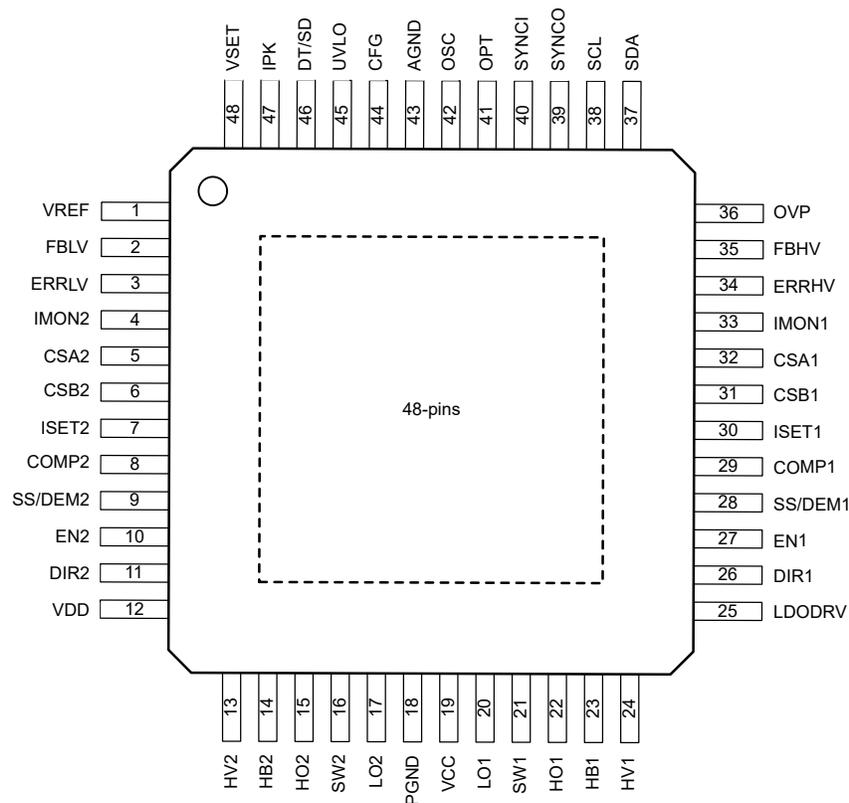


Figure 5-1. PHP Package 48-Pin TQFP Top View

Table 5-1. Pin Functions

PIN		I/O ⁽¹⁾	DESCRIPTION
NO.	NAME		
1	VREF	P	Output of the built-in 3.5V +/- 1% reference voltage.
2	FBLV	I	The inverting input pin for the buck error voltage amplifier.
3	ERRLV	O	Output pin of the buck error voltage amplifier.
4	IMON2	O	CH-2 current monitor pin.
5	CSA2	I	CH-2 differential current sense inputs.
6	CSB2	I	
7	ISET2	I	CH-2 analog current programming pin.
8	COMP2	O	Output of the CH-2 transconductance (gm) error amplifier and the inverting input of the CH-2 PWM comparator.
9	SS/DEM2	I	The soft-start programming pin for CH-2 controller. It also sets CH-2 in either DEM or FPWM.
10	EN2	I	CH-2 enable pin.
11	DIR2	I	CH-2 direction command input.
12	VDD	P	Output of 5V internal LDO.
13	HV2	I	The input pin connecting to the HV-Port line voltage for CH-2 controller.
14	HB2	I	CH-2 high-side gate driver bootstrap supply input.
15	HO2	O	CH-2 high-side gate driver output.
16	SW2	P	CH-2 switch node.
17	LO2	O	CH-2 low-side gate driver output.
18	PGND	G	Power ground connection pin.

Table 5-1. Pin Functions (continued)

PIN		I/O ⁽¹⁾	DESCRIPTION
NO.	NAME		
19	VCC	P	VCC bias supply pin.
20	LO1	O	CH-1 low-side gate driver output.
21	SW1	P	CH-1 switch node.
22	HO1	O	CH-1 high-side gate driver output.
23	HB1	I	CH-1 high-side gate driver bootstrap supply input.
24	HV1	I	The input pin connecting to the HV-Port line voltage for CH-1 controller.
25	LDODRV	O	Control pin for the external VCC LDO MOSFET.
26	DIR1	I	CH-1 direction command input.
27	EN1	I	CH-1 enable pin.
28	SS/DEM1	I	The soft-start programming pin for CH-1 controller. It also sets CH-1 in either DEM or FPWM.
29	COMP1	O	Output of the CH-1 trans-conductance (gm) error amplifier and the inverting input of the CH-1 PWM comparator.
30	ISET1	I	CH-1 analog current programming pin.
31	CSB1	I	CH-1 differential current sense inputs.
32	CSA1	I	
33	IMON1	O	CH-1 current monitor pin.
34	ERRHV	O	Output pin of the boost error voltage amplifier.
35	FBHV	I	The inverting input pin for the boost error voltage amplifier.
36	OVP	I	Input of the built-in over-voltage comparator.
37	SDA	I/O	Data of I ² C interface.
38	SCL	I	Clock of I ² C interface.
39	SYNCO	O	Clock synchronization output pin.
40	SYNCI	I	Clock synchronization input pin.
41	OPT	I	Multiphase configuration pin.
42	OSC	I	The internal oscillator frequency programming pin.
43	AGND	G	Analog ground reference.
44	CFG	I	The I ² C address setting and current monitor mode selection pin.
45	UVLO	I	The UVLO pin, which also serves as the Controller-Peripheral enable pin.
46	DT/SD	I	Dead-time programming and emergent latched shutdown pin.
47	IPK	I	Peak current limit programming pin.
48	VSET	I	Voltage error amplifier reference input pin.
—	EP	—	Exposed pad of the package.

(1) Note: G = Ground, I = Input, O = Output, P = Power

6 Specifications

6.1 Absolute Maximum Ratings

Over the recommended operating junction temperature range⁽¹⁾

		MIN	MAX	UNIT
Input	HV1, HV2 to AGND	-0.3	85	V
	HV1, HV2 to AGND (50ns Transient)		90	
	SW1, SW2 to PGND	-5	85	
	SW1, SW2 to PGND (20ns Transient)		90	
	SW1, SW2 to PGND (50ns Transient)	-16		
	HB1 to SW1, HB2 to SW2	-0.3	14	
	HO1 to SW1, HO2 to SW2	-0.3	HB+0.3	
	HO1 to SW1, HO2 to SW2 (20ns Transient)	-2		
	LO1, LO2 to PGND	-0.3	VCC+0.3	
	LO1, LO2 to PGND (20ns Transient)	-2		
	CSA1, CSB1, CSA2, CSB2 to PGND	-5.0	80	
	CSA1 to CSB1, CSA2 to CSB2	-0.3	0.3	
	CFG, DIR1, DIR2, EN1, EN2, FBHV, FBLV, IPK, ISET1, ISET2, OPT, OVP, SCL, SDA, SYNCI, UVLO, VDD, VSET to AGND	-0.3	5.5	
	COMP1, COMP2, DT/SD, ERRHV, ERRLV, IMON1, IMON2, OSC, SS/DEM1, SS/DEM2, SYNCO, VREF to AGND	-0.3	VDD+0.3	
	LDODRV TO VCC	-0.3	5	
VCC to PGND	-0.3	14		
PGND to AGND	-0.3	0.3		
Junction temperature, T _J ⁽²⁾		-40	150	°C
Storage temperature, T _{stg}		-55	150	

- (1) Operation outside the [Section 6.1](#) may cause permanent device damage. Absolute Maximum Ratings do not imply functional operation of the device at these or any other conditions beyond those listed under [Section 6.3](#). If used outside the [Section 6.3](#) but within the [Section 6.1](#), the device may not be fully functional, and this may affect device reliability, functionality, performance, and shorten the device lifetime.
- (2) High junction temperatures degrade operating lifetimes. Operating lifetime is de-rated for junction temperatures greater than 125°C.

6.2 ESD Ratings

			VALUE	UNIT	
V _(ESD)	Electrostatic discharge	Human-body model (HBM), per AEC Q100-002 ⁽¹⁾ HBM ESD Classification Level 2	±2000	V	
		Charged-device model (CDM), per AEC Q100-011 CDM ESD Classification Level C4B	All pins		±500
			Corner pins (1,12,13,24,25,36,37,48)		±750

- (1) AEC Q100-002 indicates that HBM stressing shall be in accordance with the ANSI/ESDA/JEDEC JS-001 specification.

6.3 Recommended Operating Conditions

Over the recommended operating junction temperature range of -40°C to 150°C (unless otherwise specified)⁽¹⁾

		MIN	NOM	MAX	UNIT
HV-Port (HV1, HV2)	Buck Mode	3		80	V
HV-Port (HV1, HV2)	Boost Mode	3		80	V
LV-Port	Buck Mode	0		75	V
LV-Port	Boost Mode	1		75	V
VCC	Applicable External Voltage to VCC Pin	9.5		12	V
T _J	Operating Junction Temperature ⁽²⁾	-40		150	°C
F _{OSC}	Oscillator Frequency	50		1000	kHz
F _{EX_CLK}	Synchronization to External Clock Frequency (Minimal 50kHz)	0.8x F _{OSC}		1.2x F _{OSC}	kHz
F _{EX_CLK}	SYNCl Pulse	50		0.8/ F _{OSC}	ns
t _{DT}	Programmable Dead Time Range	15		200	ns

- (1) *Operating Ratings* are conditions under the device is intended to be functional. For specifications and test conditions, see [Section 6.5](#).
 (2) High junction temperatures degrade operating lifetimes. Operating lifetime is de-rated for junction temperatures greater than 125°C .

6.4 Thermal Information

THERMAL METRIC ⁽¹⁾		LM5171	UNIT
		PHP (TQFP)	
		48 PINS	
R _{θJA}	Junction-to-ambient thermal resistance	30.7	°C/W
R _{θJC(top)}	Junction-to-case (top) thermal resistance	18.8	°C/W
R _{θJB}	Junction-to-board thermal resistance	13.5	°C/W
ψ _{JT}	Junction-to-top characterization parameter	0.3	°C/W
ψ _{JB}	Junction-to-board characterization parameter	13.4	°C/W
R _{θJC(bot)}	Junction-to-case (bottom) thermal resistance	2.5	°C/W

- (1) For more information about traditional and new thermal metrics, see the [Semiconductor and IC Package Thermal Metrics application report](#).

6.5 Electrical Characteristics

Typical values correspond to T_J = 25°C . Minimum and maximum limits apply over T_J = -40°C to 150°C . Unless otherwise stated, F_{OSC} = 100 kHz; V_{VCC} = 10 V; V_{HV1} = V_{HV2} = V_{HV-Port} = 48V and V_{LV-Port} = 12 V.

SYMBOL	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
HV Port (HV1, HV2)						
I _{SHUTDOWN1}	HV1 pin current in shutdown mode	V _{UVLO} = 0 V			10	μA
I _{SHUTDOWN2}	HV2 pin current in shutdown mode	V _{UVLO} = 0 V			10	μA
I _{OPERATING}	HV1 and HV2 pin current in operating	V _{UVLO} > 2.6 V, V _{VCC} > 9 V		1		mA
VCC Bias Supply (VCC)						
V _{VCC_reg}	VCC LDO regulation setting point	V _{HV1} > 10V	8.55	9	9.45	V
V _{CCUVLO}	VCC under voltage detection	VCC falling	7.7	8	8.2	V
V _{CCHYS}	VCC UVLO hysteresis	VCC rising	8.2	8.5	8.7	V
I _{VCC_SD}	VCC sink current in shutdown mode	V _{UVLO} = 0 V, V _{VCC} = 10 V			20	μA
I _{VCC_SB}	VCC sink current in standby: no switching	V _{UVLO} > 2.6 V, V _{VCC} > 9 V, EN1=EN2=0 V			10	mA
VDD Analog Bias Supply (VDD)						
V _{VDD}	VDD voltage	V _{UVLO} > 2.6 V, V _{VCC} > 9 V	4.75	5	5.25	V

6.5 Electrical Characteristics (continued)

Typical values correspond to $T_J = 25^\circ\text{C}$. Minimum and maximum limits apply over $T_J = -40^\circ\text{C}$ to 150°C . Unless otherwise stated, $F_{\text{OSC}} = 100\text{ kHz}$; $V_{\text{VCC}} = 10\text{ V}$; $V_{\text{HV1}} = V_{\text{HV2}} = V_{\text{HV-Port}} = 48\text{ V}$ and $V_{\text{LV-Port}} = 12\text{ V}$.

SYMBOL	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
V_{DDUV}	VDD undervoltage detection	VDD falling	4.25	4.5	4.75	V
V_{DDHYS}	VDD UVLO hysteresis	VDD rising above V_{DDUV}	0.1	0.2	0.3	V
I_{VDD}	VDD source current limit	$V_{\text{VDD}} = 4.6\text{ V}$	10			mA
VOLTAGE REFERENCE (VREF)						
V_{REF}	Voltage reference	$V_{\text{UVLO}} > 2.6\text{ V}$, $V_{\text{VCC}} > 9\text{ V}$, $V_{\text{VDD}} > V_{\text{DDUV}}$	3.465	3.500	3.535	V
I_{VREF}	VREF source current limit	$V_{\text{VREF}} = 3.5\text{ V}$	2			mA
Master ON/OFF Control (UVLO)						
$V_{\text{UVLO_TH}}$	UVLO release threshold	UVLO voltage rising	2.4	2.5	2.6	V
I_{HYS}	UVLO hysteresis current	UVLO source current when $V_{\text{UVLO}} > 2.6\text{ V}$	21	25	29	μA
V_{RES}	UVLO shutdown and IC reset voltage threshold	UVLO voltage falling	1	1.25	1.5	V
	UVLO shutdown release	UVLO voltage rising above V_{RES}	0.15	0.25	0.35	V
t_{UVLO}	UVLO 2.5V threshold glitch filter	UVLO voltage both rising and falling		2.5		μs
t_{VRES}	UVLO 1.25V V_{RES} threshold glitch filter			5	10	μs
	UVLO internal pull-down current			100		nA
Enable Inputs EN1 and EN2						
V_{IL}	Enable input low state	The driver outputs disabled			1.0	V
V_{IH}	Enable input high state	The driver outputs enabled	2.0			V
	Internal pulldown impedance	EN1, EN2 logic inputs internal pulldown resistor		1		Meg Ω
	EN glitch filter time (the rising and falling edges)			2.5		μs
DIRECTION COMMANDS (DIR1, DIR2)						
$V_{\text{DIR1}}, V_{\text{DIR2}}$	Command for current flowing from LV-Port to HV-Port (boost mode 12 V to 48 V), for CH-1 and CH-2, respectively	Actively pulled low by external circuit			1	V
$V_{\text{DIR1}}, V_{\text{DIR2}}$	Command for current flowing from HV-Port to LV-Port (buck mode 48 V to 12 V), for CH-1 and CH-2, respectively	Actively pulled high by external circuit	2			V
$V_{\text{DIR1}}, V_{\text{DIR2}}$	Standby (invalid DIR command)	DIR pin (DIR1 or DIR2) neither active High nor active Low		1.5		V
	DIR glitch filter (the rising and falling edges)	Both Rising and Falling Edges		10		μs
ISET INPUTS (ISET1, ISET2)						
	ISET internal dc offset voltage		0.99	1.0	1.01	V
G_{ISET}	Gain of the regulated inductor DC current sense voltage to ISET voltage	$ V_{\text{CSA}} - V_{\text{CSB}} = 50\text{ mV}$	24.75	25	25.25	mV/V
	ISET internal pull-down current sink			75	200	nA
Output Current Monitor (IMON1, IMON2)						
	Gain of IMON1 and IMON2 current source versus channel current sense voltage	$ V_{\text{CSA}} - V_{\text{CSB}} = 50\text{ mV}$, CONFIG = 'Inductor current monitor', $V_{\text{DIR}} > 2\text{ V}$	1.98	2	2.02	$\mu\text{A/mV}$
	Gain of IMON1 and IMON2 current source versus channel current sense voltage	$ V_{\text{CSA}} - V_{\text{CSB}} = 50\text{ mV}$, CONFIG = 'Inductor current monitor', $V_{\text{DIR}} < 1\text{ V}$	1.98	2	2.02	$\mu\text{A/mV}$

6.5 Electrical Characteristics (continued)

Typical values correspond to $T_J = 25^\circ\text{C}$. Minimum and maximum limits apply over $T_J = -40^\circ\text{C}$ to 150°C . Unless otherwise stated, $F_{\text{OSC}} = 100\text{ kHz}$; $V_{\text{VCC}} = 10\text{ V}$; $V_{\text{HV1}} = V_{\text{HV2}} = V_{\text{HV-Port}} = 48\text{ V}$ and $V_{\text{LV-Port}} = 12\text{ V}$.

SYMBOL	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
	Gain of IMON1 and IMON2 current source versus channel current sense voltage	$ V_{\text{CSA-CSB}} = 50\text{ mV}$, CONFIG = 'Output current monitor', $V_{\text{DIR}} < 1\text{ V}$, Duty cycle = 0.75	0.475	0.5	0.525	$\mu\text{A/mV}$
	Gain of IMON1 and IMON2 current source versus channel current sense voltage	$ V_{\text{CSA-CSB}} = 10\text{ mV}$, CONFIG = 'Inductor current monitor', $V_{\text{DIR}} > 2\text{ V}$	1.98	2	2.02	$\mu\text{A/mV}$
	Gain of IMON1 and IMON2 current source versus channel current sense voltage	$ V_{\text{CSA-CSB}} = 10\text{ mV}$, CONFIG = 'Inductor current monitor', $V_{\text{DIR}} < 1\text{ V}$	1.98	2	2.02	$\mu\text{A/mV}$
	Gain of IMON1 and IMON2 current source versus channel current sense voltage	$ V_{\text{CSA-CSB}} = 10\text{ mV}$, CONFIG = 'Output current monitor', $V_{\text{DIR}} < 1\text{ V}$, Duty cycle = 0.75	0.475	0.5	0.525	$\mu\text{A/mV}$
	IMON1 and IMON2 DC offset current	$ V_{\text{CSA-CSB}} = 0\text{ mV}$	47.5	50	52.5	μA
CURRENT SENSE AMPLIFIER (BOTH CHANNELS)						
$G_{\text{CS_BK1}}$	Gain of amplifier output to current sense voltage in buck mode	$ V_{\text{CSA}} - V_{\text{CSB}} = 50\text{ mV}$, $V_{\text{DIR}} > 2\text{ V}$	39.6	40	40.4	V/V
$G_{\text{CS_BST1}}$	Gain of amplifier output to current sense voltage in boost mode	$ V_{\text{CSA}} - V_{\text{CSB}} = 50\text{ mV}$, $V_{\text{DIR}} < 1\text{ V}$	39.6	40	40.4	V/V
$G_{\text{CS_BK2}}$	Gain of amplifier output to current sense voltage in buck mode	$ V_{\text{CSA}} - V_{\text{CSB}} = 10\text{ mV}$, $V_{\text{DIR}} > 2\text{ V}$	39.2	40	40.8	V/V
$G_{\text{CS_BST2}}$	Gain of amplifier output to current sense voltage in boost mode	$ V_{\text{CSA}} - V_{\text{CSB}} = 10\text{ mV}$, $V_{\text{DIR}} < 1\text{ V}$	39.2	40	40.8	V/V
BW_{cs}	Amplifier Bandwidth			10		MHz
TRANSCONDUCTION AMPLIFIER (COMP1, COMP2)						
G_m	Transconductance			100		$\mu\text{A/V}$
I_{COMP}	Output source current limit	$V_{\text{ISET}} = 4\text{ V}$, $ V_{\text{CSA}} - V_{\text{CSB}} = 0\text{ mV}$		250		μA
	Output sink current limit	$V_{\text{ISET}} = 0\text{ V}$, $V_{\text{CSA}} - V_{\text{CSB}} = 50\text{ mV}$ in the buck mode, or $V_{\text{CSA}} - V_{\text{CSB}} = -50\text{ mV}$ in the boost mode		-250		μA
BW_{gm}	Amplifier Bandwidth			10		MHz
VOLTAGE LOOP ERROR AMPLIFIERS (VSET, LVFB, LVERR, HVFB, HVERR)						
A_{OL}	Open loop gain	$V_{\text{VCC}} > 9\text{ V}$, $V_{\text{VDD}} > V_{\text{DDUV}}$		80		dB
F_{BW}	Unity gain bandwidth			2		MHz
V_{OS}	Input offset voltage				1	mV
$V_{\text{ERR_MIN}}$	Minimum amplifier output voltage	Sourcing 2 mA	4			V
$V_{\text{ERR_MAX}}$	Maximum amplifier output voltage	Sinking 2 mA			0.5	V
PWM Comparator						
	COMP to output delay			50		ns
	COMP to PWM comparator offset			1		V
$T_{\text{OFF_MIN}}$	Minimum off time			100	150	ns
PEAK CURRENT LIMIT (IPK)						
$G_{\text{IPK_BK1}}$	Gain from current sense voltage to cycle-by-cycle limit threshold voltage given at IPK pin, in buck mode	$V_{\text{IPK}} = 3\text{ V}$, $V_{\text{DIR}} > 2\text{ V}$	45	50	55	mV/V
$G_{\text{IPK_BK2}}$	Gain from current sense voltage to cycle-by-cycle limit threshold voltage given at IPK pin, in buck mode	$V_{\text{IPK}} = 1\text{ V}$, $V_{\text{DIR}} > 2\text{ V}$	45	50	55	mV/V
$G_{\text{IPK_BST1}}$	Gain from current sense voltage to cycle-by-cycle limit threshold voltage given at IPK pin, in boost mode	$V_{\text{IPK}} = 3\text{ V}$, $V_{\text{DIR}} < 1\text{ V}$	45	50	55	mV/V

6.5 Electrical Characteristics (continued)

Typical values correspond to $T_J = 25^\circ\text{C}$. Minimum and maximum limits apply over $T_J = -40^\circ\text{C}$ to 150°C . Unless otherwise stated, $F_{\text{OSC}} = 100\text{ kHz}$; $V_{\text{VCC}} = 10\text{ V}$; $V_{\text{HV1}} = V_{\text{HV2}} = V_{\text{HV-Port}} = 48\text{ V}$ and $V_{\text{LV-Port}} = 12\text{ V}$.

SYMBOL	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$G_{\text{IPK_BST2}}$	Gain from current sense voltage to cycle-by-cycle limit threshold voltage given at IPK pin, in boost mode	$V_{\text{IPK}} = 1\text{ V}$, $V_{\text{DIR}} < 1\text{ V}$	45	50	55	mV/V
OVER VOLTAGE PROTECTION (OVP)						
	OVP threshold		0.99	1	1.01	V
OVP_{HYS}	OVP Hysteresis			100		mV
t_{OVP}	OVP Glitch Filter			5		us
OSCILLATOR (OSC)						
F_{OSC}	Oscillator frequency 1	$R_{\text{OSC}} = 41.5\text{ k}\Omega$, no external clock signal at SYNC1 pin	90	100	110	kHz
	Oscillator frequency 2	$R_{\text{OSC}} = 4.15\text{ k}\Omega$, no external clock signal at SYNC1 pin	900	1000	1100	kHz
V_{OSC}	OSC pin DC voltage	OSC DC Level		1		V
SYNCHRONIZATION CLOCK INPUT (SYNCI)						
V_{SYNIH}	SYNCI input threshold for high state		2			V
V_{SYNIL}	SYNCI input threshold for low state				1	V
	Delay to establish synchronization	$0.8 \times F_{\text{OSC}} < F_{\text{SYNCI}} < 1.2 \times F_{\text{OSC}}$		200		us
	Internal pull-down impedance	$V_{\text{SYNCI}} = 2.5\text{ V}$		1000		k Ω
SYNCHRONIZATION CLOCK OUTPUT (SYNCO)						
V_{SYNOH}	SYNCO high state		2.5			V
V_{SYNOL}	SYNCO low state				0.4	V
	Sourcing current when SYNCO in high state	$V_{\text{SYNCO}} = 2.5\text{ V}$		1		mA
	Sinking current when SYNCO in low state	$V_{\text{SYNCO}} = 0.5\text{ V}$		1		mA
	SYNCO pulse width		80	100	120	ns
	SYNCO pulse delay for multiphase daisy chain connection	$V_{\text{OPT}} > 2\text{ V}$, $R_{\text{SYNCO}} > 61.9\text{ k}\Omega$		90		Degree
		$V_{\text{OPT}} < 1\text{ V}$, $R_{\text{SYNCO}} > 61.9\text{ k}\Omega$		120		Degree
BOOTSTRAP (HB1, HB2)						
$V_{\text{HB-UV}}$	Bootstrap undervoltage threshold	$(V_{\text{HB}} - V_{\text{SW}})$ voltage rising	6	6.5	7	V
$V_{\text{HB-UV-HYS}}$	Bootstrap undervoltage hysteresis			0.5		V
$I_{\text{HB_LK}}$	Bootstrap quiescent current	$V_{\text{HB}} - V_{\text{SW}} = 10\text{ V}$, $V_{\text{HO}} - V_{\text{SW}} = 0\text{ V}$			100	μA
HIGH SIDE GATE DRIVERS (HO1, HO2)						
V_{OLH}	HO low-state output voltage	$I_{\text{HO}} = 100\text{ mA}$		0.1		V
V_{OHH}	HO high-state output voltage	$I_{\text{HO}} = -100\text{ mA}$, $V_{\text{OHH}} = V_{\text{HB}} - V_{\text{HO}}$		0.15		V
	HO rise time (10% to 90% pulse magnitude)	$C_{\text{LD}} = 1000\text{ pF}$		5		ns
	HO fall time (90% to 10% pulse magnitude)	$C_{\text{LD}} = 1000\text{ pF}$		4		ns
I_{OHH}	HO peak source current	$V_{\text{HB}} - V_{\text{SW}} = 10\text{ V}$		4		A
I_{OLH}	HO peak sink current	$V_{\text{HB}} - V_{\text{SW}} = 10\text{ V}$		5		A
LOW SIDE GATE DRIVERS (LO1, LO2)						
V_{OLL}	LO low-state output voltage	$I_{\text{LO}} = 100\text{ mA}$		0.1		V
V_{OHL}	LO high-state output voltage	$I_{\text{LO}} = -100\text{ mA}$, $V_{\text{OHL}} = V_{\text{VCC}} - V_{\text{LO}}$		0.15		V
	LO rise time (10% to 90% pulse magnitude)	$C_{\text{LD}} = 1000\text{ pF}$		5		ns

6.5 Electrical Characteristics (continued)

Typical values correspond to $T_J = 25^\circ\text{C}$. Minimum and maximum limits apply over $T_J = -40^\circ\text{C}$ to 150°C . Unless otherwise stated, $F_{\text{OSC}} = 100\text{ kHz}$; $V_{\text{VCC}} = 10\text{ V}$; $V_{\text{HV1}} = V_{\text{HV2}} = V_{\text{HV-Port}} = 48\text{ V}$ and $V_{\text{LV-Port}} = 12\text{ V}$.

SYMBOL	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
	LO fall time (90% to 10% pulse magnitude)	$C_{\text{LD}} = 1000\text{ pF}$		4		ns
I_{OHL}	LO peak source current	$V_{\text{VCC}} = 10\text{ V}$		4		A
I_{OLL}	LO peak sink current	$V_{\text{VCC}} = 10\text{ V}$		5		A
INTERLEAVE PHASE DELAY FROM CH-2 To CH-1 (OPT)						
V_{OPTL}	OPT Input Low State	OPT="0"			1.0	V
V_{OPTh}	OPT Input High State	OPT="1"	2.0			V
	HO _{2rising} -HO _{1rising} in the buck mode, or LO _{2rising} -LO _{1rising} in the boost mode	OPT = "0" for 3 Phases in Daisy Chain Interleaving Operation		240		Degree
	HO _{2rising} -HO _{1rising} in the buck mode, or LO _{2rising} -LO _{1rising} in the boost mode	OPT= "1" for 1, 2, or 4 phases in Daisy Chain Interleaving Operation		180		Degree
	Internal Pull down impedance			1		Meg Ω
DEAD TIME and LATCHED SHUTDOWN (DT/SD)						
t_{DT}	LO falling edge to HO rising edge delay	$R_{\text{DT}} = 19.1\text{ k}\Omega$		50		ns
	HO falling edge to LO rising edge delay	$R_{\text{DT}} = 19.1\text{ k}\Omega$		50		ns
V_{DT}	DC voltage level for dead time programming			1.2		V
	DC voltage level for adaptive dead time programming		3.1			V
V_{ADPT}	HO-SW or LO-GND voltage threshold to enable cross output for adaptive dead time scheme	$V_{\text{VCC}} > 9\text{ V}$, $(V_{\text{HB}} - V_{\text{SW}}) > 8\text{ V}$, HO or LO voltage falling		1.5		V
t_{ADPT}	LO falling edge to HO rising edge delay	$V_{\text{DT}} = V_{\text{VDD}}$		40		ns
	HO falling edge to LO rising edge delay	$V_{\text{DT}} = V_{\text{VDD}}$		40		ns
t_{SD}	Latched shutdown glitch filter		1.875	2.5	3.125	μs
R_{SD}	Shutdown latch pulldown resistance	Resistor in series with an external pull-down NFET			2	k Ω
SOFT START and FORCED PWM and DIODE EMULATION PRGRAMMING (SS/DEM1, SS/DEM2)						
I_{SS}	SS charging current source during startup	$V_{\text{SS}} \leq 3.3\text{ V}$, $V_{\text{EN}} > 2\text{ V}$, $V_{\text{UVLO}} > 2.5\text{ V}$, DIR < 1 or DIR > 2		70		μA
I_{SS}	SS charging current source after startup	$V_{\text{SS}} \geq 3.9\text{ V}$, $V_{\text{EN}} > 2\text{ V}$, $V_{\text{UVLO}} > 2.5\text{ V}$, DIR < 1 or DIR > 2		50		μA
	SS to gm input offset			1		V
R_{SS}	SS discharge device Rds(ON)	$V_{\text{SS}} = 2\text{ V}$		20		Ω
$V_{\text{SS_LOW}}$	SS discharge completion threshold	Once it is discharged by internal logic		0.3		V
CONFIGURATIONS (CFG)						
R_{CFG1}	I2C Address: bXXXX000. IMON = Inductor Current			0		k Ω
R_{CFG2}	I2C Address: bXXXX001. IMON = Inductor Current		0.316		0.324	k Ω
R_{CFG3}	I2C Address: bXXXX010. IMON = Inductor Current		0.649		0.665	k Ω
R_{CFG4}	I2C Address: bXXXX011. IMON = Inductor Current		1.1		1.13	k Ω

6.5 Electrical Characteristics (continued)

Typical values correspond to $T_J = 25^\circ\text{C}$. Minimum and maximum limits apply over $T_J = -40^\circ\text{C}$ to 150°C . Unless otherwise stated, $F_{\text{OSC}} = 100\text{ kHz}$; $V_{\text{VCC}} = 10\text{ V}$; $V_{\text{HV1}} = V_{\text{HV2}} = V_{\text{HV-Port}} = 48\text{ V}$ and $V_{\text{LV-Port}} = 12\text{ V}$.

SYMBOL	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
R_{CFG5}	I2C Address: bXXXX100. IMON = Inductor Current		1.65		1.69	k Ω
R_{CFG6}	I2C Address: bXXXX101. IMON = Inductor Current		2.43		2.49	k Ω
R_{CFG7}	I2C Address: bXXXX110. IMON = Inductor Current		3.32	3.32, 3.4	3.4	k Ω
R_{CFG8}	I2C Address: bXXXX111. IMON = Inductor Current		4.53		4.64	k Ω
R_{CFG9}	I2C Address: bXXXX111. IMON = Output Current		6.65		6.81	k Ω
R_{CFG10}	I2C Address: bXXXX110. IMON = Output Current		10.2		10.5	k Ω
R_{CFG11}	I2C Address: bXXXX101. IMON = Output Current		13.7		14.0	k Ω
R_{CFG12}	I2C Address: bXXXX100. IMON = Output Current		18.7		19.1	k Ω
R_{CFG13}	I2C Address: bXXXX011. IMON = Output Current		26.1		26.7	k Ω
R_{CFG14}	I2C Address: bXXXX010. IMON = Output Current		37.4		38.3	k Ω
R_{CFG15}	I2C Address: bXXXX001. IMON = Output Current		60.4		61.9	k Ω
R_{CFG16}	I2C Address: bXXXX000. IMON = Output Current		95.3		97.6	k Ω
I2C INTERFACE (SLC, SDA)						
V_{SDAL}	SDA input low state				1.0	V
V_{SDAH}	SDA input high state		2.0			V
V_{SCLL}	SCL input low state				1.0	V
V_{SCLH}	SCL input high state		2.0			V
Thermal Shutdown						
$T_{\text{J_SD}}$	Thermal shutdown		155	175		$^\circ\text{C}$
	Thermal shutdown hysteresis			15		$^\circ\text{C}$

6.6 Timing Requirements

Over operating junction temperature range and recommended supply voltage range (unless otherwise noted)

			MIN	NOM	MAX	UNIT
OVERALL DEVICE FEATURES						
	Minimum time low EN toggle	time measured from EN toggle from H to L and from L to H	TBD			μs
I2C INTERFACE						
f_{SCL}	SCL clock frequency	Standard mode	0		100	kHz
		Fast mode	0		400	
		Fast mode plus ⁽¹⁾	0		1000	
t_{LOW}	LOW period of the SCL clock	Standard mode	4.7			μs
		Fast mode	1.3			
		Fast mode plus ⁽¹⁾	0.5			

6.6 Timing Requirements (continued)

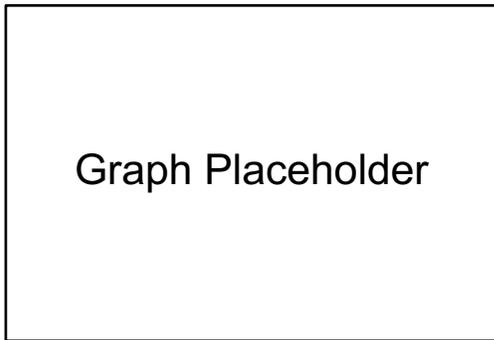
Over operating junction temperature range and recommended supply voltage range (unless otherwise noted)

			MIN	NOM	MAX	UNI T
t _{HIGH}	HIGH period of the SCL clock	Standard mode	4.0			μs
		Fast mode	0.6			
		Fast mode plus ⁽¹⁾	0.26			
t _{BUF}	Bus free time between a STOP and a START condition	Standard mode	4.7			μs
		Fast mode	1.3			
		Fast mode plus ⁽¹⁾	0.5			
t _{SU:STA}	Set-up time for a repeated START condition	Standard mode	4.7			μs
		Fast mode	0.6			
		Fast mode plus ⁽¹⁾	0.26			
t _{HD:STA}	Hold time (repeated) START condition	Standard mode	4.0			μs
		Fast mode	0.6			
		Fast mode plus ⁽¹⁾	0.26			
t _{HD:DAT}	Data hold time	Standard mode	0			μs
		Fast mode	0			
		Fast mode plus ⁽¹⁾	0			
t _r	Rise time of both SDA and SCL signals	Standard mode			1000	ns
		Fast mode	20		300	
		Fast mode plus ⁽¹⁾			20	
t _f	Fall time of both SDA and SCL signals	Standard mode			300	ns
		Fast mode	$20 \times V_{DD} / 5.5$		300	
		Fast mode plus ⁽¹⁾	$20 \times V_{DD} / 5.5$		120	
t _{SU:STO}	Set-up time for STOP condition	Standard mode	4.0			μs
		Fast mode	0.6			
		Fast mode plus ⁽¹⁾	0.26			
t _{VD:DAT}	Data valid time	Standard mode			3.45	μs
		Fast mode			0.9	
		Fast mode plus ⁽¹⁾			0.45	
t _{VD:ACK}	Data valid acknowledge time	Standard mode			3.45	μs
		Fast mode			0.9	
		Fast mode plus ⁽¹⁾			0.45	
C _b	Capacitive load for each bus line	Standard mode			400	pF
		Fast mode			400	

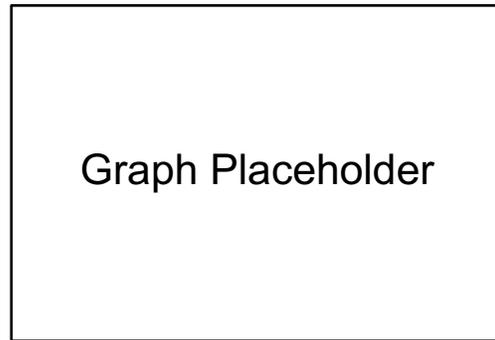
(1) Fast mode plus is supported but not fully compliant with I²C standard

6.7 Typical Characteristics

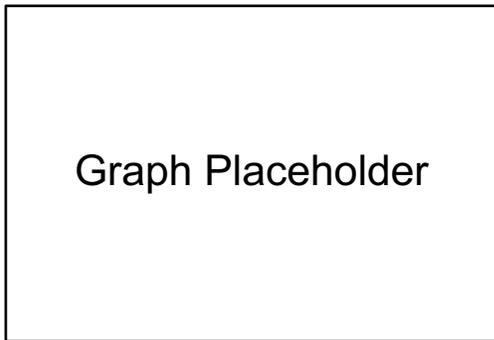
$V_{IN} = 48\text{ V}$, $V_{VCC} = 10\text{ V}$, $V_{UVLO} = 3.3\text{ V}$, $T_J = 25^\circ\text{C}$, unless otherwise stated.



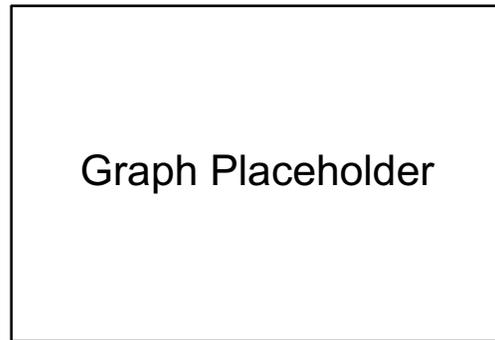
$V_{UVLO} = 0$
Figure 6-1. Shutdown Current vs Temperature
 $I_{Q_Shutdown}$



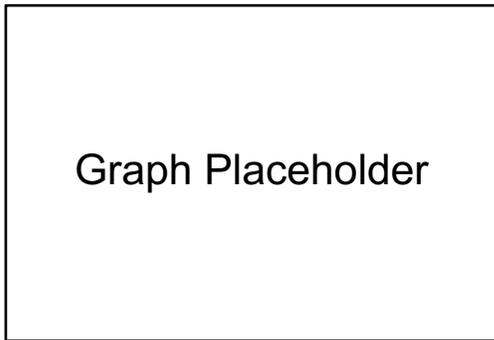
$V_{UVLO} = 3\text{V}$ $V_{EN1} = 0\text{V}, V_{EN2} = 0\text{V}$
Figure 6-2. Operating VCC Current vs Temperature
 $I_{Q_standby}$



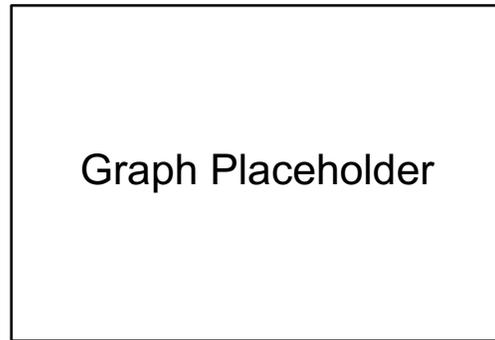
$V_{UVLO} = 3\text{V}$ $V_{EN1} = 0\text{V}, V_{EN2} = 0\text{V}$
Figure 6-3. VREF Accuracy vs Temperature



$R_{OSC} = 40.2\text{ k}\Omega$
Figure 6-4. Oscillator Frequency vs Temperature



$DIR = 0$, Buck Mode
Figure 6-5. Average Load Current Regulation Accuracy vs Temperature
 $I_{AVG_ACCURACY}$



$DIR = 1$, Boost Mode
Figure 6-6. Average Load Current Regulation Accuracy vs Temperature
 $I_{AVG_ACCURACY}$

Graph Placeholder

DIR =0, Buck Mode

Figure 6-7. IMON Accuracy $I_{MON_ACCURACY}$

Graph Placeholder

DIR =1, Boost Mode

Figure 6-8. IMON Accuracy $I_{MON_ACCURACY}$

7 Detailed Description

7.1 Overview

The LM5171-Q1 device is a high performance, dual-channel bidirectional PWM controller intended to manage power transfer between a Higher Voltage Port (HV-Port) and a Lower Voltage Port (LV-Port) like the 48-V and 12-V ports of automotive dual battery systems. LM5171-Q1 integrates essential analog functions that enable the design of high-power converters with a minimal number of external components. Depending on the operating mode, device can regulate both the output port voltages, or currents, in either direction designated by the DIR input signal.

The dual-channel differential current sense amplifiers and dedicated channel current monitors achieve typical accuracy of 1%. The robust 5-A half-bridge gate drivers are capable of controlling parallel MOSFET switches delivering 500 W or more per channel. The device offers dynamically selectable Diode Emulation Mode (DEM) and Forced PWM (FPWM). With DEM, the buck or boost synchronous rectifier enables discontinuous mode operation for improved efficiency under light load conditions, and it also prevents negative current. With FPWM, the synchronous rectifier allows negative current and hence helps achieving fast dynamic response under large circuit transients. Versatile protection features include the cycle-by-cycle peak current limit, overvoltage protection of both 48-V and 12-V battery rails, detection and protection of MOSFET switch failures, and overtemperature protection.

The LM5171-Q1 uses an innovated average current mode control technology which simplifies the inner current loop compensation by maintaining a constant loop gain regardless of the power flow direction and the operating voltages and load level. Device also integrates two error amplifiers and a 1% accurate voltage reference to facilitate the bi-directional output voltage regulation. The free-running oscillator is adjustable up to 1000 kHz and can be synchronized to an external clock within $\pm 20\%$ of the free running oscillator frequency. The stackable multiphase parallel operation is achieved by connecting two LM5171-Q1 controllers in parallel for 3- or 4-phase operation, or by synchronizing multiple LM5171-Q1 controllers to external multiphase clocks for a higher number of phases. In addition, the two channels of the LM5171-Q1 can implement two independent bi-directional converters. The UVLO pin provides commander ON/OFF control that disables the LM5171-Q1 in a low quiescent current shutdown state when the pin is held low.

The LM5171-Q1 also features the I2C port, through which the status of operation and alarms of the IC can be monitored.

Device Configurations (CFG) and I2C Address

A single resistor placed across the CFG and AGND pins sets the IMON1 and IMOM2 of the LM5171-Q1 to monitor each inductor current or load current of a channel, and it also programs the I2C address as listed in [Table 7-1](#).

Table 7-1. CFG Programming for IMONs and I2C Address

CFG Resistor Selection (k Ω) (1% Resistor)		I2C Address	IMON1 and IMON2 Function
Min	Max		
0	0.1	Hx0	Inductor Current
0.316	0.324	Hx1	Inductor Current
0.649	0.665	Hx2	Inductor Current
1.10	1.13	Hx3	Inductor Current
1.65	1.69	Hx4	Inductor Current
2.43	2.49	Hx5	Inductor Current
3.32	3.40	Hx6	Inductor Current
4.53	4.64	Hx7	Inductor Current
6.65	6.81	Hx7	Load Current
10.2	10.5	Hx6	Load Current
13.7	14.0	Hx5	Load Current
18.7	19.1	Hx4	Load Current

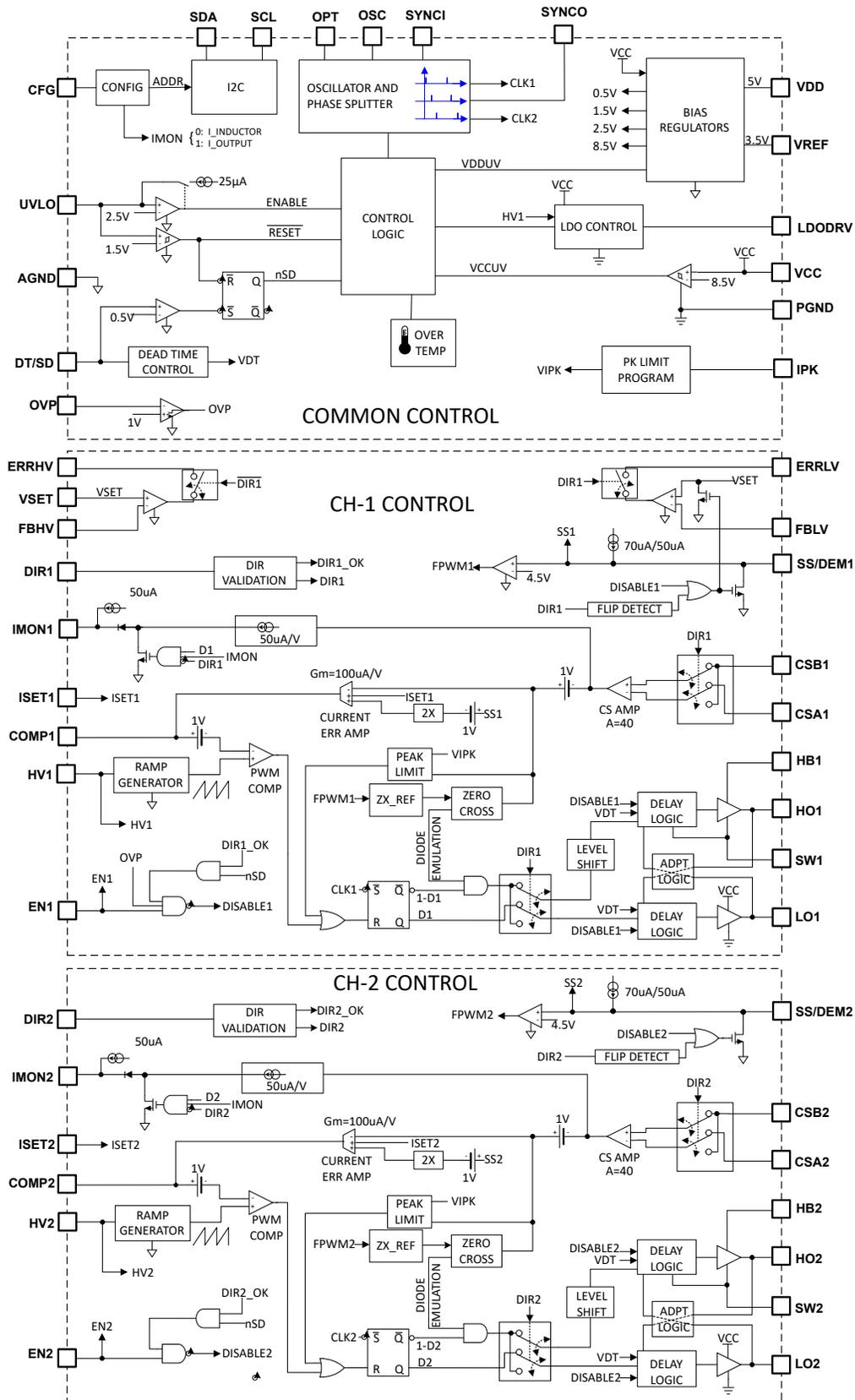
Table 7-1. CFG Programming for IMONs and I2C Address (continued)

CFG Resistor Selection (kΩ) (1% Resistor)		I2C Address	IMON1 and IMON2 Function
Min	Max		
26.1	26.7	Hx3	Load Current
37.4	38.3	Hx2	Load Current
60.4	61.9	Hx1	Load Current
95.3	97.6	Hx0	Load Current

Definition of IC Operation Modes:

- **Shutdown Mode:** When the UVLO pin is < 1.25 V, the LM5171-Q1 is in the shutdown mode with all gate drivers in the low state, and all internal logic reset. When UVLO < 1.25 V, the IC draws < 10 μA through each of the HV1, HV2 and VCC pins.
- **Initialization Mode:** When the UVLO pin is > 1.5 V but < 2.5 V, and DT/SD > 0.5V, the LM5171-Q1 establishes proper internal logic states, and the LDODRV is turned on to control the external MOSFET to produce the VCC, and LM5171-Q1 prepares for circuit operation. Once VCC voltage is >8.5V, VDD and VREF are also established at approximately 5.0V and 3.5V, respectively.
- **Standby Mode:** When the UVLO pin is > 2.5 V, and VCC > 8.5 V, VDD > 4.5 V, and DT/SD > 0.5 V, the LM5171-Q1 is ready to operate. The oscillator is activated and the SYNCO is firing phase-shifted clock signals, but the four gate drive outputs remain off until the EN1 or EN2 initiate the power delivery mode.
- **Power Delivery Mode:** When the UVLO pin > 2.5 V, VCC > 8.5 V, VDD > 4.5V, DT/SD > 0.5 V, EN1 or EN2 > 2 V, DIR1 and/or DIR2 is valid (> 2 V or < 1 V), the SS capacitor is release. Once the SS voltage rises above 1V, the LM5171-Q1 gate drivers start to switch and start the power delivery.
- **Latch-ed Shutdown mode** serves as an emergency shutdown function, and it is achieved by pulling DT/SD pin below 1V for at least 2.5μs by an external circuit during operation. In latched shutdown mode, all gate drivers remains in the low state, and both SS/DEM1 and SS/DEM2 pins are held low. The latch can be reset by pulling the UVLO to below 1.25V for at least 10μs.

7.2 Functional Block Diagram



ADVANCE INFORMATION

7.3 Feature Description

7.3.1 Bias Supplies and Voltage Reference (VCC, VDD, and VREF)

The LM5171-Q1 integrates a LDO driver to drive an external N-channel MOSFET to generate 9V bias supply at the VCC pin. The VCC pin can also accept an external supply of 9.5 V to 12 V and the device turns off the LDO driver to save the power dissipation in the external LDO MOSFET. Figure 7-1 shows typical connections of the bias supply.

When external supply is used, it is recommended to add a block diode to prevent from discharging the VCC during transient in the external supply. If an external supply voltage is greater than 12 V, a 10-V LDO or switching regulator must be used to produce 10 V for VCC. The VCC voltage is directly fed to the low-side MOSFET drivers. A 1- μ F to 2.2- μ F ceramic capacitor must be placed between the VCC and PGND pins to bypass the driver switching currents. For the LDO MOSFET, it is recommended to have the C_{iss} around 300pF (TBD) or below.

The internal VCC undervoltage (UV) detection circuit monitors the VCC voltage. When the VCC voltage falls below 8 V on the falling edge, the LM5171-Q1 is held in the shutdown state. For normal operation, the VCC and voltage must be greater than 8.5 V on the rising edge.

Once the VCC voltage is above the VCC_UV, the VDD and VREF regulator turns on to establish 5.0 V and 3.5 V, respectively. The VDD regulator can supply up to 10mA to the external circuit. The VREF is 1% accurate reference voltage for the external circuit use, and it has a loading capability of 2mA. A 0.1 to 1.0 μ F ceramic capacitor must be placed between VDD and AGND pins, and 0.01 μ F between VREF and AGND pins, respectively.

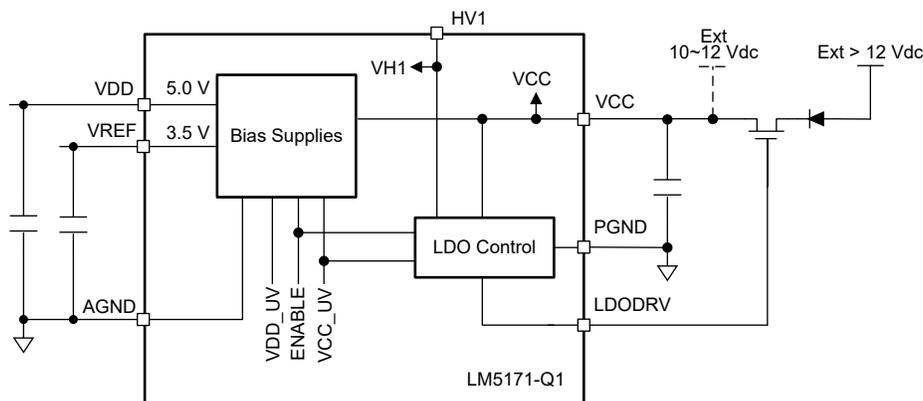


Figure 7-1. Bias Supplies Connections

7.3.2 Undervoltage Lockout (UVLO) and Controller Enable or Disable

The UVLO pin serves as the Controller enable or disable pin. To use the UVLO pin to program undervoltage lockout control for the HV-port, LV-port, or VCC rail, see Section 7.4.2 for details.

There are two UVLO voltage thresholds. When the pin voltage is externally pulled below 1.25 V, the LM5171-Q1 is in shutdown mode, in which all gate drivers are in the OFF state, all internal logic resets, and the IC draws less than 10 μ A through each of the HV and VCC pins.

When the UVLO pin voltage is pulled higher than 1.5 V but lower than 2.5 V, the LM5171-Q1 is in the initialization mode in which LDODRV pin turns on to control the external MOSFET to establish the VCC voltage at 9.0 V, and the VDD at 5.0V and VREF at 3.5V. The DT/SD pin is pulled up to 1.2 V, but the rest of the LM5171-Q1 remains off as long as EN1, EN2 are less than 1V, and/or DIR1 and DIR2 are invalid signals.

When the UVLO pin is pulled higher than 2.5 V, which is the UVLO release threshold and the Controller enable threshold, the LM5171-Q1 oscillator is activated, and the SYNCO pin gives out the phase shifted clock at the oscillator frequency, and the LM5171-Q1 is ready to operate. The SS/DEM1 and SS/DEM2 as well as LO1, LO2, HO1, and HO2 drivers remain off until the EN1, EN2, and DIR inputs command them to operate.

7.3.3 High Voltage Inputs (HV1, HV2)

Figure 7-2 shows the external and internal configuration for the HV1 and HV2 pins. Both pins are rated at 85 Vdc. For independent channel operation, the HV1 and HV2 must be directly connected to the HV-port voltage rails for each channel, respectively, which are not necessarily the same HV-port. When operating in parallel dual phase configuration to support high power, the two HV pins can be tied together and connect to the same HV-port. As shown in Figure 7-2, a small RC filter like 10 Ω and 0.1 μ F can be applied at these two pins to bypass high frequency noises.

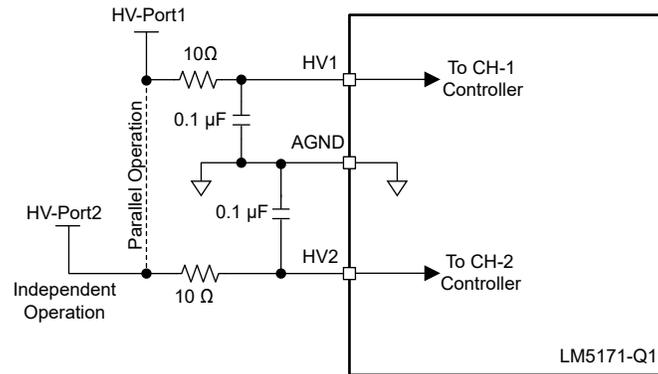


Figure 7-2. HV1 and HV2 Pins Configuration

7.3.4 Current Sense Amplifier

Each channel of the LM5171-Q1 has an independent bidirectional, high accuracy, and high-speed differential current sense amplifier. The differential current sense polarity is determined by the DIR command. The amplifier gain is 40, such that a smaller current sense resistor can be used to reduce power dissipation. The amplified current sense signal is used to perform the following functions:

- Applied to the inverting input of the trans-conductance amplifier for the current loop regulation.
- Used to reconstruct the channel current monitor signal at the IMON1 and IMON2 pins.
- Monitored by the cycle-by-cycle peak current limit comparator for the instantaneous overcurrent protection.
- Sensed by the current zero cross detector to operate the synchronous rectifiers in the diode emulation mode.

The current sense resistor R_{cs} must be selected for 50-mV current sense voltage when the channel DC current reaches the rated level. The CSA1, CSB1, CSA2, and CSB2 pins must be Kelvin connected for accurate sensing.

It is very important that the current sense resistors are non-inductive. Otherwise the sensed current signals are distorted even if the parasitic inductance is only a few nH. Such inductance may not affect the current regulation during continuous conduction mode, but it does affect current zero cross detection, and hence the performance of diode emulation mode under light load. As a consequence, the synchronous rectifier gate pulse is truncated much earlier than the inductor current zero crossing, causing the body diode of the synchronous rectifier to conduct unnecessarily for a longer time. See the *Diode Emulation* for details.

If the selected current sense resistor has parasitic inductance, see the [Section 8.1](#) for methods to compensate for this condition and achieve optimal performance.

7.3.5 Control Commands

7.3.5.1 Channel Enable Commands (EN1, EN2)

These pins are two state function pins. EN1 and EN2 are independent command signals. EN1 controls CH-1, and EN2 controls CH-2.

1. When the EN1 pin voltage is pulled above 2 V (logic state of 1), the HO1 and LO1 outputs of the same channel are enabled through soft start programmed by SS/DEM1.
2. When the EN1 pin voltage is pulled below 1 V (logic state of 0), CH-1 controller is disabled and both HO1 and LO1 outputs are turned off, and SS/DEM1 is discharged.
3. Similar behaviors for EN2, HO2 and LO2, and SS/DEM2 of CH-2.

4. When the EN1 and EN2 pins are left open, an internal 1000-kΩ pulldown resistor sets them to the low state.
5. The built-in 2.5-μs glitch filters prevent errant operation due to the noise on the EN1 and EN2 signals.

7.3.5.2 Direction Command (DIR1 and DIR2)

These pins are tri-state function pins. DIR1 controls CH-1, and DIR2 controls CH-2.

1. When the DIR1 pin is actively pulled above 2 V (logic state of 1), CH-1 operates in buck mode, and current flows from the HV-Port to the LV-Port.
2. When the DIR1 pin is actively pulled below 1 V (logic state of 0), CH-1 operates in boost mode, and current flows from the LV-Port to the HV-Port.
3. When the DIR1 pin is in the third state that is different from the above two, it is considered an invalid command and CH-1 remains in standby mode regardless of the EN1 states. This tri-state function prevents faulty operation when losing the DIR signal connection to the MCU.
4. When DIR1 changes the logic state between 1 and 0 dynamically during operation, the transition causes the SS/DEM1 pin to discharge first to below 0.3 V, then the SS/DEM1 pin pulldown is released and CH-1 goes through a new soft-start process to produce the current in the new direction. This eliminates the surge current during the direction change.
5. Similar behaviors for DIR2, CH-2, EN2, and SS/DEM2.
6. The built-in 10-μs glitch filter prevents errant operation by noise on the DIR1 and DIR2 signals.

7.3.5.3 Channel Current Setting Commands (ISET1 and ISET2)

Each channel of the LM5171-Q1 has the independent current setting pin, ISET1 and ISET2, for independent channel operation. For multiphase in parallel operation, connect all ISET pins together to achieve balanced power sharing among multiphases.

Each ISET pin accepts an analog voltage to program the channel dc current, as shown in [Figure 7-3](#). The ISET pin signal feeds directly to one of the two non-inverting inputs of the gm amplifier. The other non-inverting pin is controlled by the soft-start. Because the current sense signal passes an 1V dc offset voltage before it feeds to the inverting input of the gm amplifier, the channel DC current that flows through the current sense resistor is determined by [Equation 1](#) in the closed loop operation.

$$V_{CS_dc} = 0.025 \times (V_{ISET} - 1V) \quad (1)$$

Or by [Equation 2](#),

$$I_{channel_dc} = \frac{V_{CS_dc}}{R_{cs}} \quad (2)$$

Or by [Equation 3](#),

$$I_{channel_dc} = \frac{0.025 \times (V_{ISET} - 1V)}{R_{cs}} \quad (3)$$

Where

- Rcs is the channel current sensing resistor value.

If a PWM signal is provided to control the channel current but no DAC is available, recommend to use a two-stage RC filter to convert it to the analog voltage at the ISET, as shown in [Figure 7-4](#). The corner frequency of the filter must be set to at least 1 decade below the PWM frequency in order to attenuate the ripple voltage to less than 1% at the ISET pin, namely, the RC selection satisfies [Equation 4](#), and the PWM to analog voltage conversion is given by [Equation 5](#).

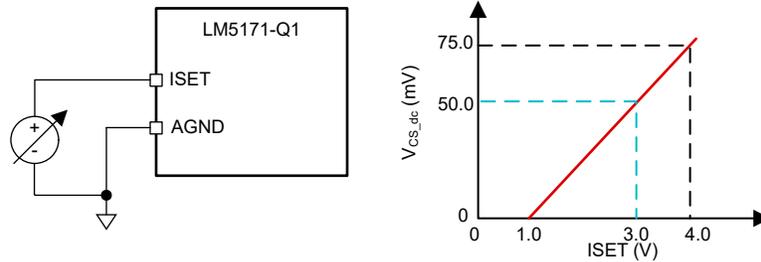


Figure 7-3. Analog Voltage Channel Current Programming

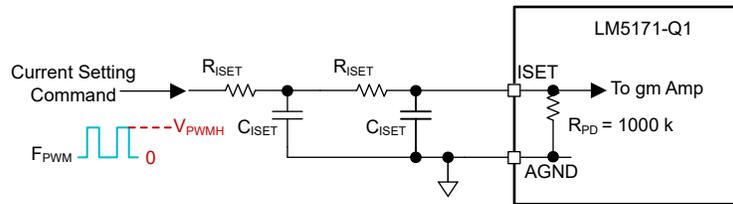


Figure 7-4. PWM Channel Current Programming

$$6.28 \times R_{ISETA} \times C_{ISETA} \leq 10 \times F_{PWM} \quad (4)$$

$$V_{ISET} = \frac{R_{PD}}{R_{PD} + 2 \times R_{ISET}} \times V_{PWMH} \times D_{PWM} \quad (5)$$

Where

- F_{PWM} is the PWM command frequency.
- R_{PD} is the internal pull-down resistor, which is 1000 k Ω typical.
- V_{PWMH} is the PWM signal magnitude.
- D_{PWM} is the PWM signal duty cycle.

Note that the internal pull-down resistor R_{PD} has some tolerances. If $R_{ISET} \ll R_{PD}$, the effects of the tolerance on V_{ISET} accuracy can be greatly reduced.

7.3.6 Channel Current Monitor (IMON1, IMON2)

The LM5171-Q1 monitors the real time inductor current in each channel by converting the current sense voltage to small current sources at the IMON1 and IMON2 pins. By programming at the CFG pin (see [Table 7-1](#)), these monitors can be set to monitor the inductor DC current or the converter output current regardless the buck or boost mode.

7.3.6.1 Individual Channel Current Monitor

When the monitors are set to monitor the inductor dc current, which is the input current in the boost mode, or the load current in the buck mode, the monitor current source is determined by [Equation 6](#) and [Equation 7](#):

$$IMON1 = \frac{V_{CS1}}{500\Omega} + 50\mu A \quad (6)$$

$$IMON2 = \frac{V_{CS2}}{500\Omega} + 50\mu A \quad (7)$$

Where

- V_{CS1} and V_{CS2} are the real time current sense voltage of CH-1 and CH-2, respectively.
- the 50 μA is a DC offset current superimposed on to the IMON signals (refer to [Figure 7-5](#)).

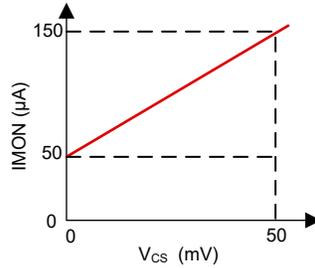


Figure 7-5. IMON Current Source vs Current Sense Voltage

The 50 µA DC offset current is introduced to raise the no-load signal above the possible ground noise floor. Because the monitor signal is in the form of current, an accurate reading can be obtained across a termination resistor even if the resistor is located far from the LM5171-Q1 but close to the MCU, thus rejecting potential ground differences between the LM5171-Q1 and the MCU. [Figure 7-7](#) shows a typical channel current monitor through a 20-KΩ termination resistor and a 10-nF to 100-nF ceramic capacitor in parallel. The RC network converts the current monitor signal into a DC voltage proportional to the channel DC current. For example, when the current sense voltage DC component is 50 mVdc, namely $V_{CS_dc} = 50$ mV, the termination RC network produces a DC voltage of 3 V. Note that the maximum active operating voltage of the IMON pin is 3 V.

When the monitors are set to monitor the output DC current, which is the channel load current flowing out of the LV-port in the buck mode, or flowing out of the HV-port in the boost mode, the monitor current source is determined by [Equation 8](#) through [Equation 11](#):

$$IMON1_{BK} = \frac{R_{CS1} \times I_{O1_BK}}{R_{IMON1}} + 50\mu A \quad (8)$$

$$IMON2_{BK} = \frac{R_{CS2} \times I_{O2_BK}}{R_{IMON2}} + 50\mu A \quad (9)$$

$$IMON1_{BST} = \frac{R_{CS1} \times I_{O1_BST}}{R_{IMON1}} + 50\mu A \quad (10)$$

$$IMON2_{BST} = \frac{R_{CS2} \times I_{O2_BST}}{R_{IMON2}} + 50\mu A \quad (11)$$

Where

- I_{O1_BK} and I_{O2_BK} are the buck mode load current of CH-1 and CH-2, respectively.
- I_{O1_BST} and I_{O2_BST} are the boost mode load current of CH-1 and CH-2, respectively.

Obviously, the buck mode channel load current is the same as shown in [Figure 7-5](#). However, the boost load current can be shown as in [Figure 7-6](#).

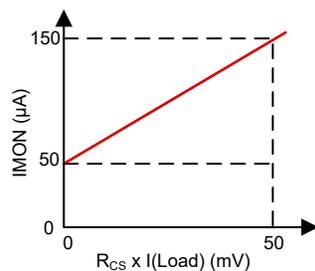


Figure 7-6. IMON Current Source vs Boost Load Current

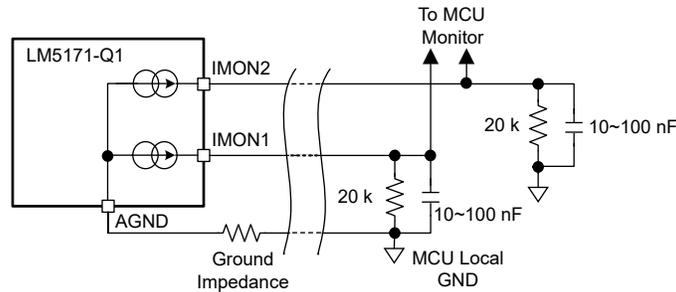


Figure 7-7. Channel Current Monitor

7.3.6.2 Multiphase Total Current Monitoring

For multiphase parallel operation, all LM5171-Q1 IMON pins can be combined to serve as a total current monitor. This also helps save the monitor single lines. Figure 7-8 shows an example of total current monitor of a three-phase system in which the unused fourth phase monitor (U2-IMON2) is grounded.

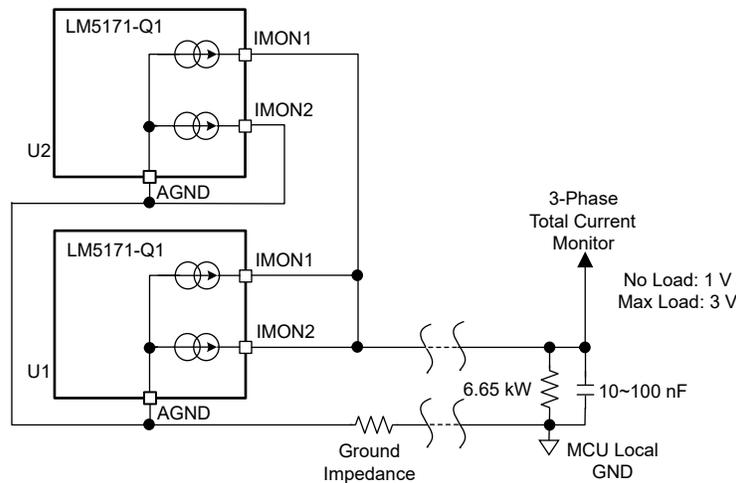


Figure 7-8. An Example of the 3-Phase Total Inductor Current Monitor

7.3.7 Cycle-by-Cycle Peak Current Limit (IPK)

An external resistor divider as shown in Figure 7-9 establishes a voltage at the IPK pin to program the cycle-by-cycle current limit threshold. The threshold applies to both CH-1 and CH-2 controller circuits. During operation, each controller circuit has a real time detection circuit to monitor the channel current sense signal. Once the current sense voltage reaches the programmed threshold, the controller terminates the main switch duty cycle, thereby preventing the peak current from exceeding the threshold, and this function is fulfilled in each switching cycle.

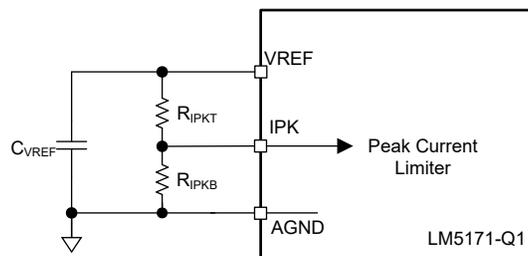


Figure 7-9. Cycle-by-Cycle Peak Current Limit Programming

To set the inductor peak current limit threshold, the programming voltage at the IPK pin must satisfy Equation 12:

$$V_{IPK} = \frac{I_{PK} \times R_{CS}}{50\text{mV/V}} \quad (12)$$

Where V_{IPK} is determined by [Equation 13](#)

$$V_{IPK} = \frac{R_{IPKB}}{R_{IPKT} + R_{IPKB}} \times 3.5\text{V} \quad (13)$$

I_{PK} must be greater than the inductor peak current at full load, and lower than the rated saturation current I_{sat} of the inductor.

It is recommended to select R_{IPKT} and R_{IPKB} such that they do not draw more than 0.1mA from VREF pin, in order to keep the overall VREF current consumption low.

Note that when the IPK pin voltage is greater than 4 V, owing to an open R_{IPKB} or a short R_{IPKT} or some other reasons, an internal monitor circuit shuts down the switching of both controllers of the LM5171, preventing the LM5171-Q1 from operating with erroneous peak current limit threshold.

7.3.8 Inner Current Loop Error Amplifier

Each channel of the LM5171-Q1 has an independent gm error amplifier for the inner current loop control. The output of the gm amplifier is connected to the COMP pin, allowing the loop compensation network to be applied between the COMP pins and AGND.

Because the LM5171-Q1 employs the averaged current mode control scheme, the inner current loop is basically a first order system. As shown in [Figure 7-10](#), a Type-II compensation network consisting of R_{COMP} , C_{COMP} , and C_{HF} is adequate to stabilize the LM5171-Q1 inner current loop. The compensation applies to both the buck and boost operating modes. Refer to [Section 8.1](#) for details of the compensation network selection criteria.

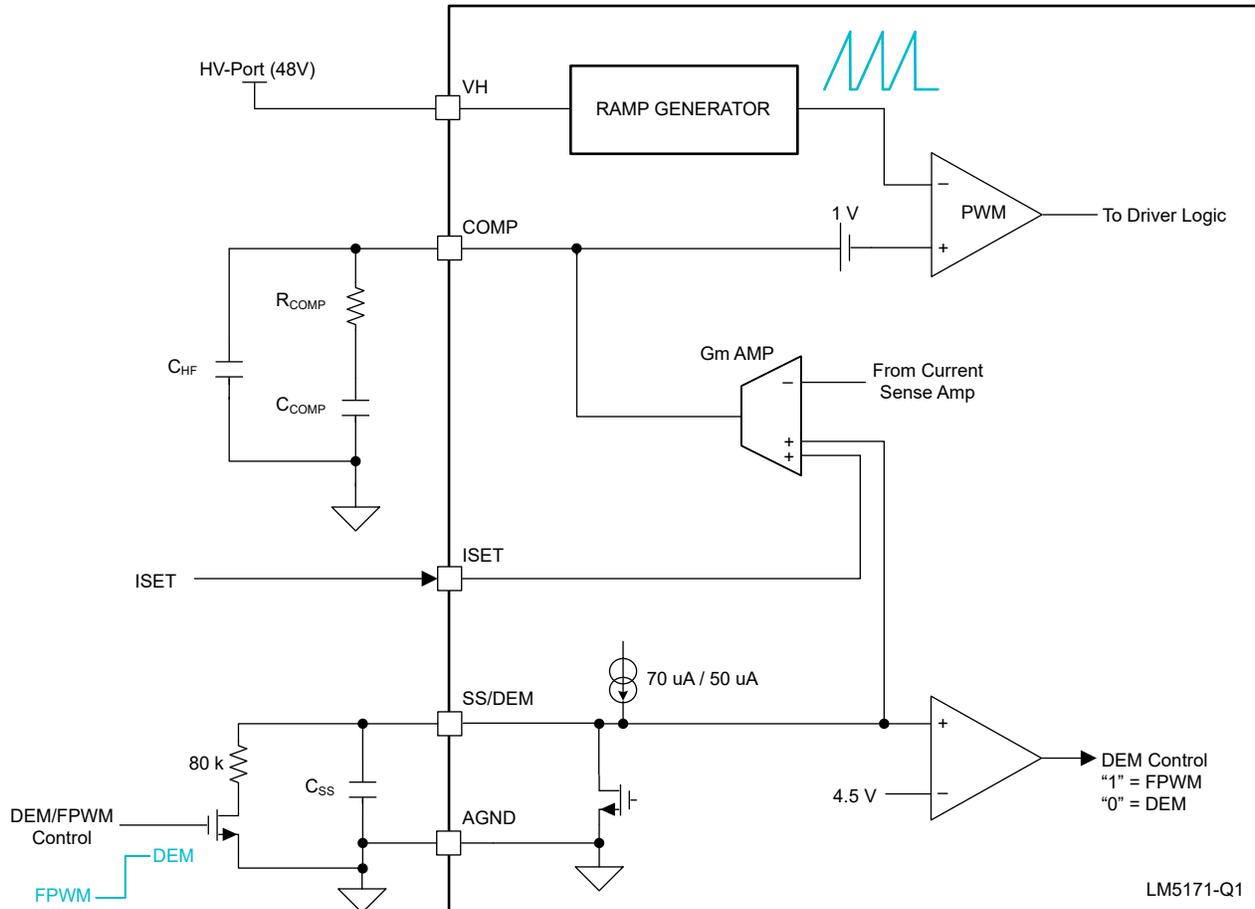


Figure 7-10. Inner Loop GM Amplifier, Soft-Start, and PWM Comparator, and DEM/FPWM Control

7.3.9 Outer Voltage Loop Error Amplifier

The LM5171-Q1 also integrates two Op-Amps serving as the outer voltage loop error amplifiers, one for the buck mode operation, the other for the boost mode operation. For the channel independent operation, these two Op-Amps can be used for CH-1, and the users need to use two external Op-Amps for CH-2. Once the inner current loop is closed, the outer voltage loop is also a first order system and a Type-II compensation network can be used to stabilize the LM5171-Q1 output voltage loop. Refer to the [Section 8.1](#) section for details of the compensation network selection criteria.

7.3.10 Soft Start, Diode Emulation, and Forced PWM Control (SS/DEM1 and SS/DEM2)

The SS/DEM1 and SS/DEM2 are multifunction pins. They serve as the soft-start timer, and they can also dynamically program each channel to operate in the Diode Emulation Mode (DEM) or Forced PWM Mode (FPWM). In addition, the SS/DEM pin also fulfills the function of a restart timer in an Over Voltage Protection (OVP) event or following a dynamic DIR command change.

7.3.10.1 Soft-Start Control by the SS/DEM Pins

Place a ceramic capacitor C_{SS1} between the SS/DEM1 pin and AGND to program the CH-1 soft-start time. When the EN1 voltage is < 1 V, an internal pulldown FET holds the SS/DEM1 pin at AGND. When the EN1 pin voltage is > 2 V, the SS pulldown FET is released, and C_{SS} is charged up slowly by the internal $70\text{-}\mu\text{A}/50\text{-}\mu\text{A}$ current source, as shown in [Figure 7-10](#). The slow ramping SS voltage overrides the ISET1 signal at the non-inverting input voltage of the gm amplifier until it reaches the ISET1 pin voltage. Once the SS/DEM1 voltage exceeds the 1-V offset voltage, the CH-1 PWM duty cycle starts to increase gradually from zero.

When EN1 is pulled below 1 V, C_{SS1} is discharged by the internal pulldown FET. Once this pulldown FET is turned on, it remains on until the SS/DEM1 voltage falls below 0.3 V, which is the threshold voltage indicating the completion of SS/DEM1 discharge.

Similar behaviors apply to SS/DEM2 for CH-2.

When the LM5171-Q1 operates in multiphase parallel operation, the two SS/DEM pins can be tied together.

7.3.10.2 DEM Programming

Each SS/DEM pin is monitored in real time by an internal comparator. If the pin voltage is less than 4V, which can be the result of placing a 60 k Ω resistor across the SS/DEM and AGND pins, the corresponding channel of the LM5171-Q1 operates in DEM. Each channel has a real time current zero crossing detector to monitor instantaneous V_{CS} . When V_{CS} is detected to cross zero, the LM5171-Q1 turns off the gate drive of the synchronous rectifier (Sync FET) to prevent negative current. In this way, the negative current is prevented and the light load efficiency is improved. Figure 7-11 shows key waveforms of a typical operation transiting into the diode emulation mode.

To obtain optimal diode emulation performance, it requires the VCS signal to be accurate in real time. Any signal distortion caused by parasitic inductances in the current sense resistor or sensing traces may lead to erroneous zero crossing detection and cause non-optimal diode emulation operation, and the Sync FET may be turned off while the current is still high in the positive direction. See the Application Information section for coping with current sense parasitic inductances for optimal diode emulation operation.

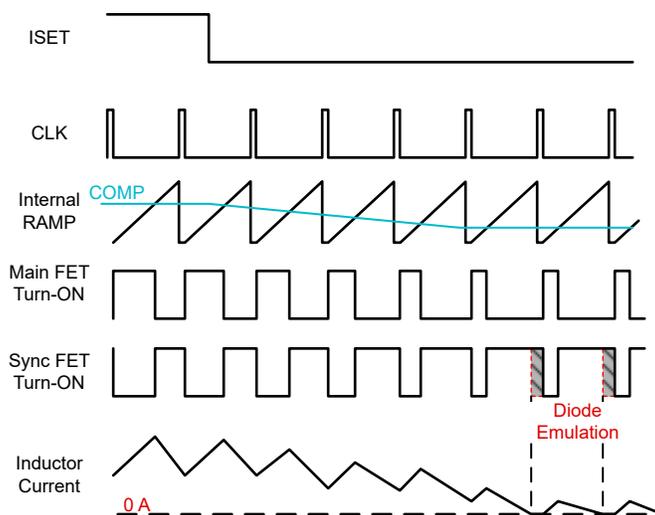


Figure 7-11. Diode Emulation Operation

7.3.10.3 FPWM Programming and Dynamic FPWM and DEM Change

If the SS/DEM pin does not have an external pulldown resistor, or if the external pulldown resistor is large enough, the pin voltage eventually raises above 4V by the SS current source that charges the C_{SS} , and this sets the corresponding channel of the LM5171-Q1 to operate in FPWM.

To dynamically change the operating mode between the FPWM and DEM modes, the programming resistor can be switched in and off by controlling the series FET, as shown in Figure 7-10. When the FET is turned on, it sets the channel in DEM. When the FET is turned off, it sets the channel in FPWM. There are 128 switching cycles transition time to gradually change from one mode to the other.

7.3.10.4 SS Pin as the Restart Timer

The SS pin also fulfills the function of a restart timer in an OVP event or following a DIR command change:

(1) **Restart Timer in OVP:** When OVP catches an overvoltage event (refer to Section 7.3.16), C_{SS1} of CH-1 is discharged immediately by the internal pulldown FET, and this FET remains ON as long as the overvoltage condition persists. When the overvoltage condition is removed and after the SS/DEM1 voltage is discharged to

below 0.3 V, the pulldown is released, setting off a new soft-start cycle. The circuit may run in retry or hiccup mode if the overvoltage condition reappears. The retry frequency is determined by the C_{SS1} as well as the nature of the overvoltage condition.

Note that OVP only affects SS/DEM1 but not SS/DEM2. For multiphase parallel operation, connect SS/DEM1 and SS/DEM2 to enable the same hiccup mode in CH-2 as shown in Figure 7-12. For independent channel operation, an external OVP protection circuit is needed for CH-2, and that circuit must be configured to discharge SS/DEM2 to achieve OVP and also the hiccup mode operation. Figure 7-13 shows an example of such an external OVP implementation for CH-2. See Figure 7-22 and Figure 7-23 for other examples.

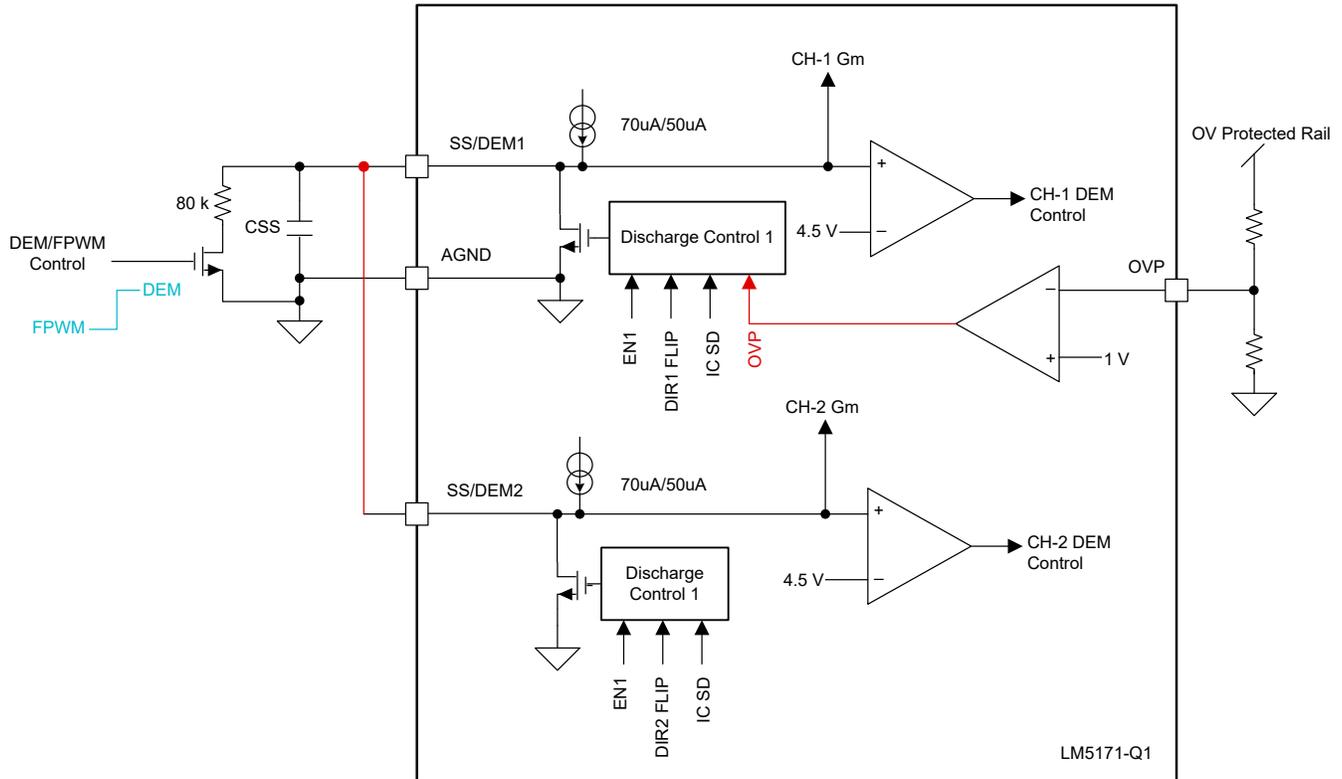


Figure 7-12. OVP Implementation for SS-DEM Pins Connection for Parallel Operation

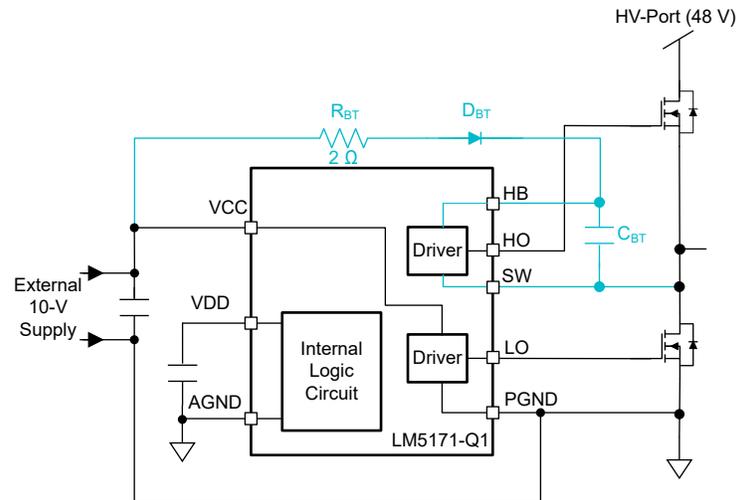


Figure 7-14. Bootstrap Circuit for High-Side Bias Supply (Only One Channel is Shown)

During start-up in buck mode, C_{BT} may not be charged initially; the LM5171-Q1 then holds off the high-side driver outputs (HO1 and HO2) and sends LO pulses of 200-ns width in consecutive cycles to pre-charge C_{BT} . When the boot voltage is greater than the 6.5-V boot UV threshold, the high-side drivers output PWM signals at the HO1 and HO2 pins for normal switching action. If the boot voltage becomes lower than the boot UV threshold voltage on the falling edge, the corresponding HO output pulls low until the boot voltage recovers to assume normal HO switching pulses. During normal buck mode operation, when the C_{BT} voltage falls below the 6.5V boot UV threshold, the same precharge function starts by interrupting the normal switching until the boot voltage restores above the UV threshold. This helps prevent the power MOSFETs from running into linear mode by inadequate gate voltage. Note that the gate threshold voltage of the MOSFETs may raise to as high as 6V due to degradation over aging.

During start-up and normal operation in boost mode, C_{BT} is naturally charged by the normal turnon of the low side MOSFET, therefore there is no such 200-ns pre-charge pulse at the LO pins.

To prevent shoot-through between the high-side and low-side power MOSFETs on the same half bridge leg, two types of dead time schemes can be chosen with the DT pin: the programmable dead time or built-in adaptive dead time.

To program the dead time, place a resistor R_{DT} across the DT/SD and AGND pins as shown in [Figure 7-15](#).

The dead time t_{DT} as depicted in [Figure 7-16](#) is determined by [Equation 14](#):

$$t_{DT} = R_{DT} \times 2.625 \frac{\text{ns}}{\text{k}\Omega} \quad (14)$$

Note that this equation is valid for programming t_{DT} between 15 ns and 200 ns. When the power MOSFET is connected to the gate drive, its gate input capacitance C_{ISS} becomes a load of the gate drive output, and the HO and LO slew rate are reduced, leading to a reduced effective t_{DT} between the high- and low-side MOSFETs. The user must evaluate the effective t_{DT} to make sure it is adequate to prevent shoot-through between the high- and low-side MOSFETs.

When the DT programmability is not used, simply connect the DT/SD pin to VDD as shown in [Figure 7-17](#), to activate the built-in adaptive dead time. The adaptive dead time is implemented by real time monitoring of the output of a driver (either HO or LO) by the other driver (LO or HO) of the same half bridge switch leg, as shown in [Figure 7-17](#) and [Figure 7-18](#). Only when the output voltage of a driver falls below 1.5 V does the other driver starts turnon. The effectiveness of adaptive dead time is greatly reduced if a series gate resistor is used, or if the PCB traces of the gate drive have excessive impedance due to poor layout design.

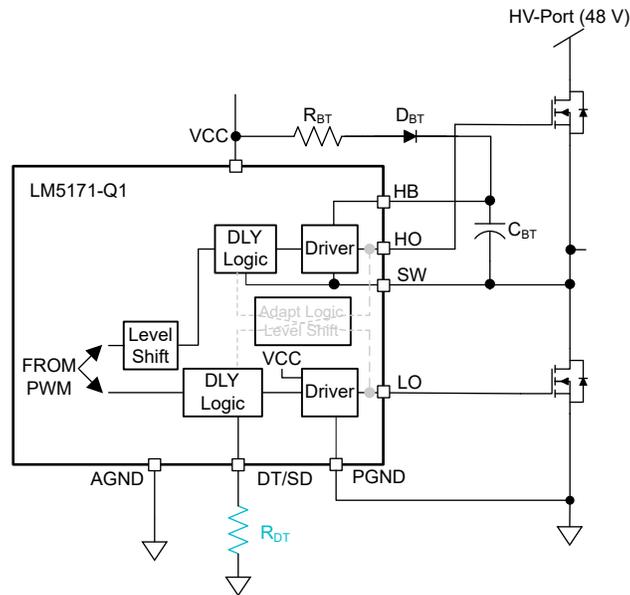


Figure 7-15. Dead Time Programming With DT Pin (Only One Channel is Shown)

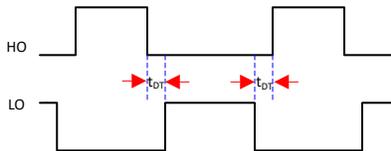


Figure 7-16. Gate Drive Dead Time (Only One Channel is Shown)

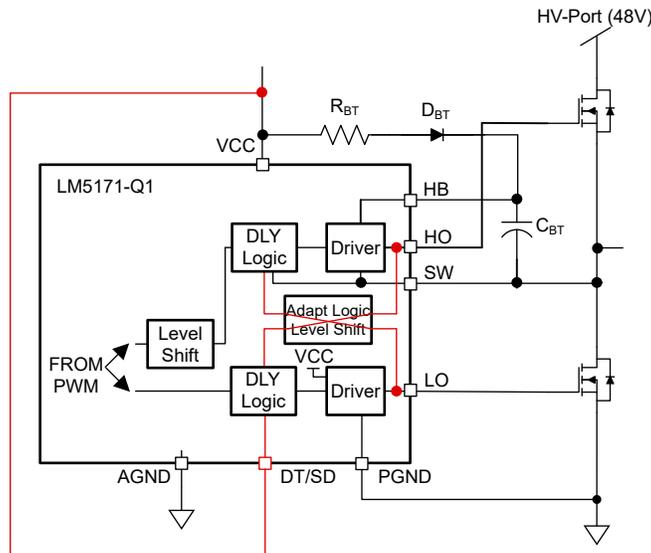


Figure 7-17. Dead Time Programming With DT Pin (Only One Channel is Shown)

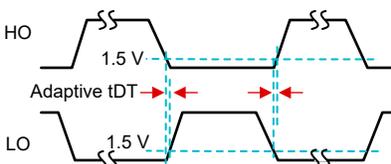


Figure 7-18. Adaptive Dead Time (Only One Channel is Shown)

7.3.12 Emergent Latched Shutdown (DT/SD)

The DT/SD pin also serves as an emergent latched shutdown pin. During the operation the DT/SD pin is monitored by an internal circuit. The pin is normally regulated at 1.2V with a sourcing current limit of 300uA. Once the pin is externally pulled down below 0.5V for more than 2.5 μ s, the LM5171-Q1 shuts down and the state is latched until the UVLO is pulled below 1.25V to unlatch. Figure 7-19 shows an example of implementing the emergency latched shutdown function.

When the LM5171-Q1 sets for adaptive dead time scheme, DT/SD pin needs to be pulled up to VDD. In order to implement the emergent latched shutdown control in this case, a 20 k Ω limiting resistor must be placed across the VDD and DT/SD pin, as shown in Figure 7-20.

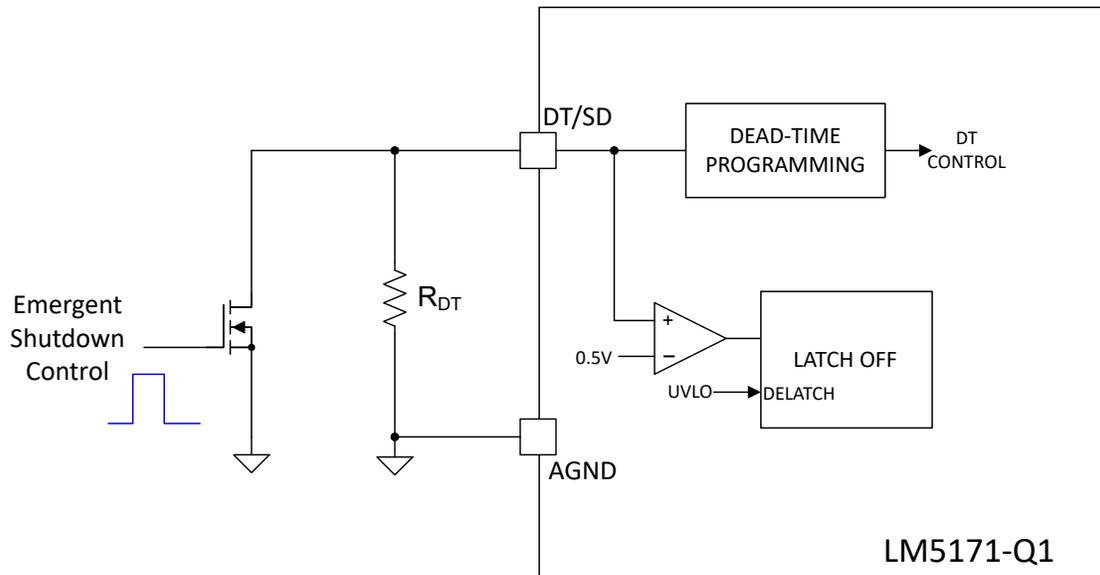


Figure 7-19. Emergent Latched Shutdown

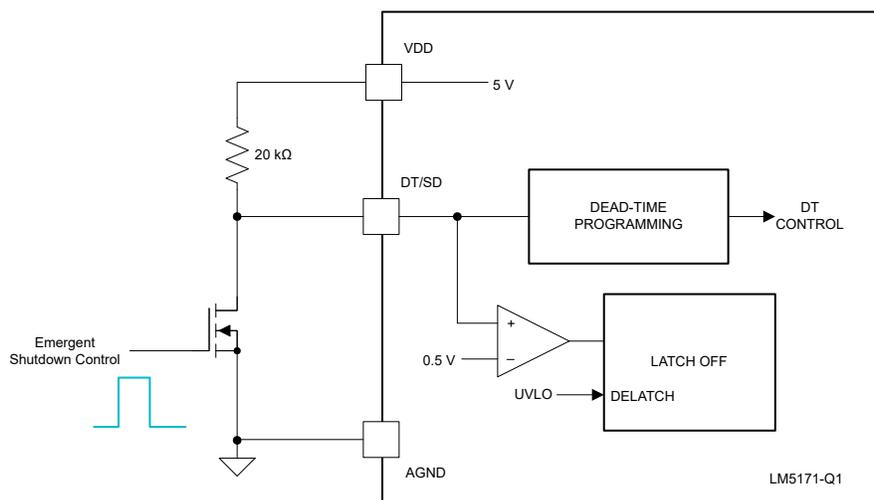


Figure 7-20. Emergent Latched Shutdown with Adaptive Dead-time Scheme

7.3.13 PWM Comparator

Each channel of the LM5171-Q1 has a pulse width modulator (PWM) employing a high-speed comparator. It compares the internal ramp signal and the COMP pin signal to produce the PWM duty cycle. Note that the COMP signal passes through a 1-V DC offset before it is applied to the PWM comparator, as shown in Figure 7-10. Owing to this DC offset, the duty cycle can reduce to zero when the COMP pin or SS pin is pulled

lower than 1 V. The maximum duty cycle is limited by the 100-ns typical minimum off-time, with the worst case max limit of 150 ns. Note that the programmed dead time may reduce the maximum duty cycle because it is additional to the minimum off-time. Therefore, the maximum duty cycle, for both buck and boost mode operation, is determined by [Equation 15](#).

$$D_{MAX} = 1 - (150\text{ns} + t_{DT}) \times F_{SW} \quad (15)$$

Where

- t_{DT} is the dead time given by [Equation 14](#) or the adaptive dead time, whichever applicable.

This maximum duty cycle limits the minimum voltage step-down ratio in buck mode operation, and the maximum step-up ratio in boost mode operation.

7.3.14 Oscillator (OSC)

The LM5171-Q1 oscillator frequency is set by the external resistor R_{OSC} connected between the OSC pin and AGND, as shown in [Figure 7-21](#). The OSC pin must never be left open whether or not an external clock is present. To set a desired oscillator frequency F_{OSC} , R_{OSC} is approximately determined by [Equation 16](#):

$$R_{OSC} = \frac{41.5\text{k}\Omega \times 100\text{ kHz}}{F_{OSC}} \quad (16)$$

R_{OSC} must be placed as close as possible to the OSC and AGND pins. Take the tolerance of the external resistor and the frequency tolerance indicated in *Electrical Characteristics* into account when determining the worst-case operating frequency.

The LM5170-Q1 also includes a Phase-Locked Loop (PLL) circuit to manage multiphase interleaving phase angle as well as the synchronization to the external clock applied at the SYNCIN pin. When no external clock is present, the converter operates at the oscillator frequency given by [Equation 16](#). If an external clock signal of a frequency within $\pm 20\%$ of F_{SW} is applied (see [Section 7.3.15](#)), the converter switches at the frequency of the external clock F_{EX_CLK} , namely [Equation 17](#):

$$F_{SW} = \begin{cases} F_{OSC} & \text{(in Standalone)} \\ F_{EX_CLK} & \text{(in Synchronization)} \end{cases} \quad (17)$$

Two internal clock signals CLK1 and CLK2 are produced to control the interleaving operation of CH-1 and CH-2, respectively. The third clock signal is output at the SYNCO pin. All these three clock signals run at the same frequency of F_{SW} . The phase angles among these three clock signals are controlled by the state of the OPT pin. See [Section 7.3.17](#) for details.

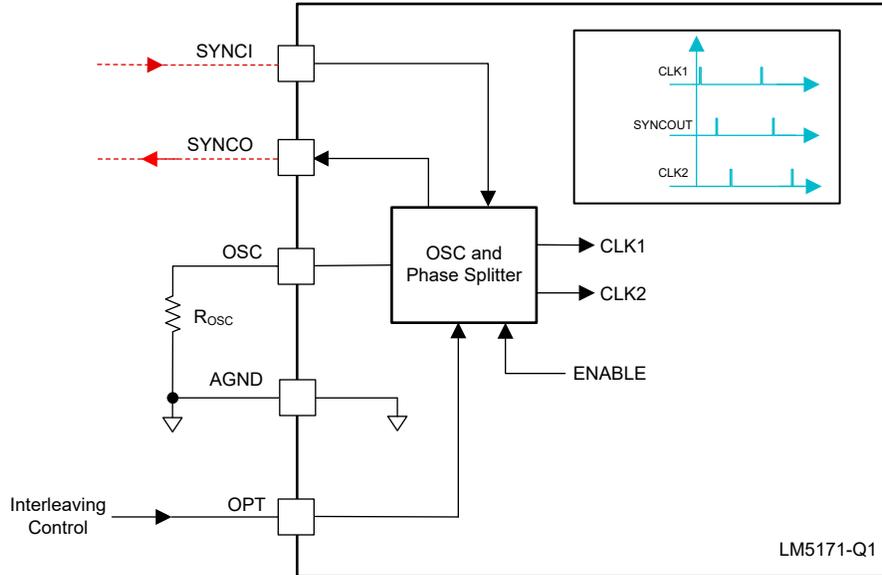


Figure 7-21. Oscillator and Interleaving Clock Programming

7.3.15 Synchronization to an External Clock (SYNCIN, SYNCOUT)

The LM5171-Q1 can synchronize to an external clock if F_{EX_CLK} is within $\pm 20\%$ of F_{OSC} . The SYNCIN clock pulse width must be in the range of 100 ns to $0.8/F_{OSC}$, with a high voltage level > 2 V and low voltage level < 1 V.

F_{EX_CLK} can be adjusted dynamically. However the LM5171-Q1 PLL takes approximately 150 μ s to settle down to the newly asserted frequency. During the PLL transient, the instantaneous F_{SW} may temporarily drop by 25%. To avoid overstress during the transient, TI recommends the user to reduce the load current to less than 50% by lowering the ISET voltage, or to simply turn off the dual-channels by setting $EN1 = EN2 = 0$ when making an the external clock change.

7.3.16 Overvoltage Protection (OVP)

As shown in Figure 7-22, the LM5171-Q1 includes the over voltage protection function, which can be used to monitor either the HV-port, or the LV-port, or a user defined voltage rail, through a resistor divider at the OVP pin.

A resistor divider at the OVP pin sets the OVP threshold. When the OVP pin voltage exceeds the 1.0 V threshold on the rising edge, both HO1 and LO1 are turned off. At the same time C_{SS1} is discharged, and the C_{SS1} remains discharged as long as the OVP event lasts. When the OVP voltage falls 105 mV below the 1.0V threshold on the falling edge, the OVP alarm is removed, the SS/DEM1 pulldown is released, and CH-1 resumes operation through a soft-start. See the Soft Start description for details.

Note that OVP alarm only affects CH-1, but not CH-2, and it only protects one voltage rail. Additional OVP functions can be implemented with simple external circuits

- For multiphase parallel operation, connect SS/DEM1 and SS/DEM2 to enable OVP for both channels as shown in Figure 7-22.
- For additional voltage rail OVP, employ an external circuit as shown in Figure 7-23, in which an open drain comparator can discharge C_{SS1} and C_{SS2} once the protected railed voltage exceeds the OVP threshold.
- For independent channel operation, an external OVP protection circuit is needed for CH-2 as shown in Figure 7-24, in which CH-1 OVP is implemented with the internal circuit, and the CH-2 OVP is fulfilled by the external open-drain comparator at SS/DEM2. Note the C_{SS2} also serves as the OVP hiccup mode timer for CH-2.

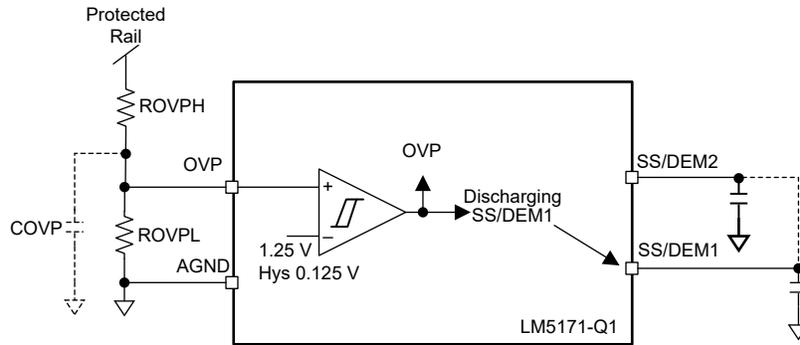


Figure 7-22. OVP for CH-1 or Multiphase Parallel Operation

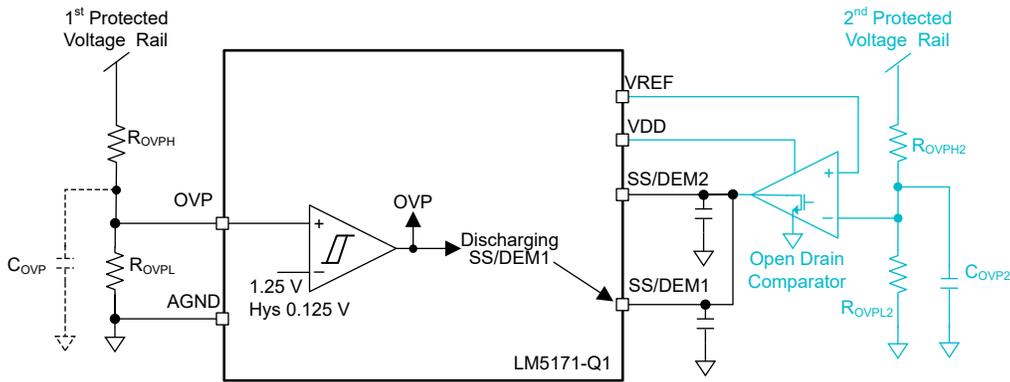


Figure 7-23. OVP for 2nd Protected Voltage Rail in Multiphase Parallel Operation

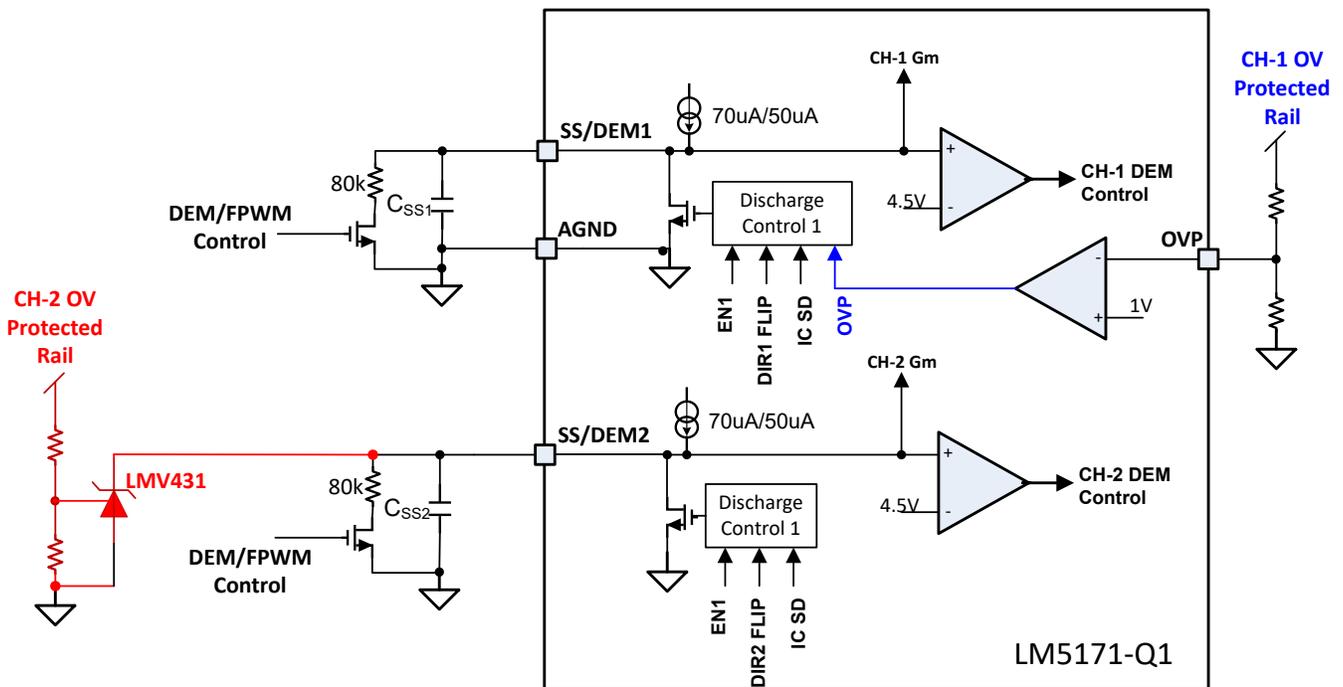


Figure 7-24. Independent Channel Operation OVP Implementation

7.3.17 Multiphase Configurations (SYNCO, OPT)

There are various options to make multiphase configurations.

7.3.17.1 Multiphase in Star Configuration

Each LM5171-Q1 synchronizes to an external clock, and the clock signals must have appropriate phase delays among them for proper multiphase interleaving operation. The interleave angle between the two phases of each LM5171-Q1 can be programmed to 180° or 240° by the OPT pin. The SYNCIN and SYNCOUT are phase shifted by 90° with each other. Higher stage phases (More than 8) can be implemented using HOST MCU generating SYNCIN pulses for set of each 8 phase block. [Table 7-2](#) summarizes the settings of the external clocks and the OPT pin state for multiphase configurations.

Table 7-2. Multiphase Configurations With Individual External Clock

NUMBER OF PHASES	PHASE SHIFT BETWEEN EXTERNAL CLOCKS FOR MULTIPHASE INTERLEAVING	OPT LOGIC STATE ⁽¹⁾	CH-2 PHASE LAGGING VS CH-1	NUMBER OF LM5170-Q1 CONTROLLERS NEEDED	NUMBER OF EXTERNAL CLOCKS NEEDED
2	180°	1	180°	1	1 or 0
3	120°	0	240°	2	2
4	90°	1	180°	2	2
6	60° or 120°	1	180°	3	3
8	45°	1	180°	4	2

(1) OPT State = 0 when the pin connects to AGND, and 1 when the pin voltage is VDD.

7.3.17.2 Daisy-Chain Configurations for 2, 3, or 4 Phases parallel operations

This can be used to achieve 1, 2, 3, or 4 phases without using an external clock. [Table 7-3](#) summarizes the OPT settings for the daisy-chain multiphase configurations. [Figure 7-25](#) shows an example of daisy-chain connection for three and four phases interchangeable operation.

Table 7-3. Multiphase Configurations With Built-In Daisy-Chain Controller - Responder Configuration

NUMBER OF PHASES	OPT LOGIC STATE ⁽¹⁾	CH-2 PHASE LAGGING VS CH-1	SYNCOUT PHASE LAGGING VS CH-1	NUMBER OF LM5170-Q1 CONTROLLERS NEEDED	NUMBER OF EXTERNAL CLOCKS NEEDED
2	1	180°	90°	1	0 or 1
3	0	240°	120°	2	0 or 1
4	1	180°	90°	2	0 or 1

(1) OPT State = 0 when the pin connects to AGND, and 1 when the pin voltage is VDD.

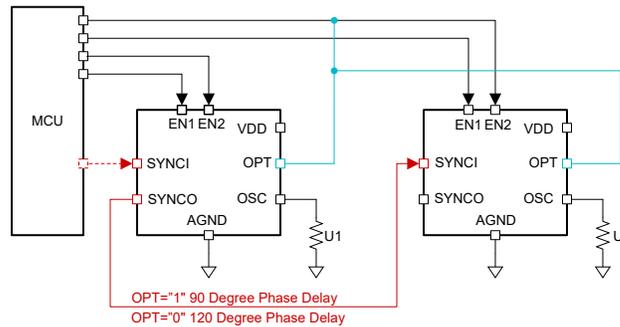


Figure 7-25. Three or Four Phases Interchangeable Configuration

7.3.17.3 Daisy-Chain configuration for 6 or 8 phases parallel operation

To configure 6 phases, it requires daisy chain as shown in [Figure 7-26](#) and for 8 phases, it requires daisy chain as shown in [Eight Phases 45° Interleaving Configuration using External Clock Shift](#).

Note that two phase-shifted external clock signals are required for proper interleaving operation

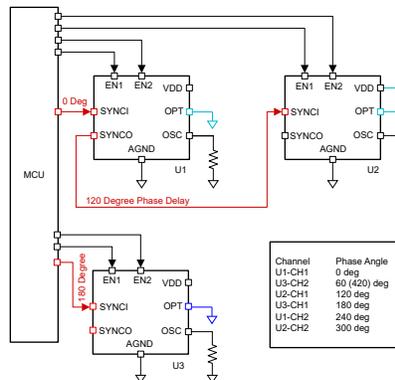


Figure 7-26. Six Phases 60° Interleaving Configuration using External Clock Shift

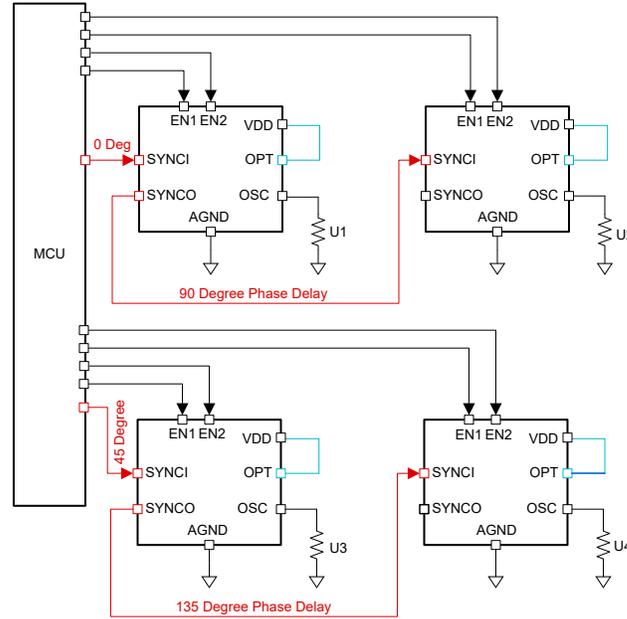


Figure 7-27. Eight Phases 45° Interleaving Configuration using External Clock Shift

When external clock signals are not available, the 6-phase can be configured in 120° interleaving as shown in [Six Phases 120° Interleaving Configuration using Internal Clock Shift](#)

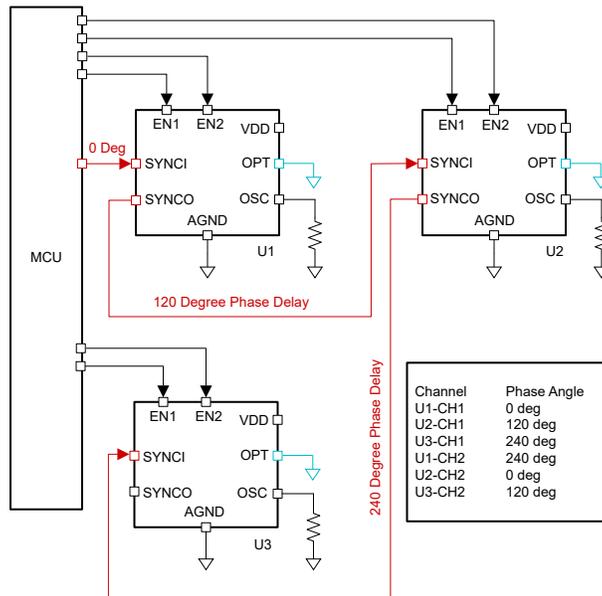


Figure 7-28. Six Phases 120° Interleaving Configuration using Internal Clock Shift

7.3.18 Thermal Shutdown

An internal thermal shutdown is provided to protect the device in case that the junction temperature exceeds 175°C typical. During thermal shutdown, the device is forced into a low power state with the MOSFET drivers disabled, and SS/DEM1 and SS/DEM2 pin internally pulled down and held low. After the junction temperature is reduced (typical hysteresis is 15°C), the device steps out of the thermal shutdown mode, and it restarts through soft-start by releasing the SS/DEM1 and SS/DEM2 pulldown.

7.4 Programming

7.4.1 Dynamic Dead Time Adjustment

In addition to a fixed dead time programming by R_{DT} , the dead time can be dynamically adjusted either by applying an analog voltage or a PWM signal as shown in [Figure 7-29](#). Varying the analog voltage or the duty ratio of the PWM signal adjusts the DT programming. For analog adjustment, a single stage RC filter is recommended to filter out any possible noise. For PWM adjustment, a two-stage RC filter is recommended to minimize the ripple voltage resulted on the DT pin.

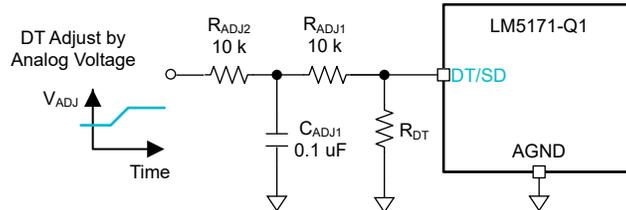


Figure 7-29. Dynamic Dead Time Adjustment A

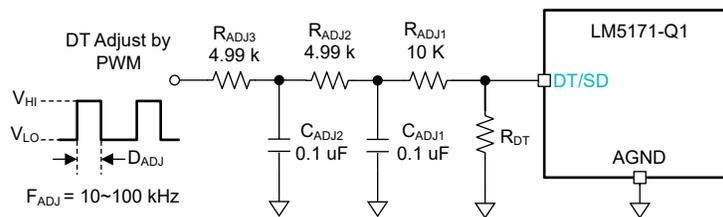


Figure 7-30. Dynamic Dead Time Adjustment b

When an analog voltage is applied, the resulted dead time is determined by [Equation 18](#):

$$t_{DT}(V_{ADJ}) = \left(\frac{1}{R_{DT}} + \frac{1}{R_{ADJ1} + R_{ADJ2}} - \frac{0.8 \times V_{ADJ}}{R_{ADJ1} + R_{ADJ2}} \right)^{-1} \times 2.625 \frac{\text{ns}}{\text{k}\Omega} \quad (18)$$

where

- V_{ADJ} is the analog voltage used to adjust the dead time

When a PWM signal is applied, the resulted dead time is determined by [Equation 19](#):

$$t_{DT}(D_{ADJ}) = \left(\frac{1}{R_{DT}} + \frac{1}{R_{ADJ1} + R_{ADJ2} + R_{ADJ3}} - \frac{0.8 \times [(V_{HI} - V_{LO}) \times D_{ADJ} + V_{LO}]}{R_{ADJ1} + R_{ADJ2} + R_{ADJ3}} \right)^{-1} \times 2.625 \frac{\text{ns}}{\text{k}\Omega} \quad (19)$$

where

- V_{HI} and V_{LO} are the high and low voltage levels of the PWM signal, respectively,
- D_{ADJ} is the duty factor of the PWM signal.

Note that in dynamic dead time programming, to equivalent impedance at the DT /SD pin seen by the IC must be greater than 5 k Ω to prevent unintended shutdown latch. See [Section 7.3.12](#) for details.

7.4.2 UVLO Programming

The UVLO pin is the enable pin of the LM5171-Q1 controller. It can be directly controlled by an external control unit like an MCU.

Nevertheless, the UVLO pin can also fulfill the undervoltage lockout function of a particular power rail. The rail can be either the HV-Port, or the LV-Port, or VCC. Use a resistor divider to set the UVLO threshold, as shown in [Figure 7-31](#). The divider must satisfy [Equation 20](#):

$$\frac{R_{UVLO2}}{R_{UVLO1} + R_{UVLO2}} \times V_{UVLO} = 2.5 \text{ V} \quad (20)$$

The UVLO hysteresis is accomplished with an internal 25- μ A current source. When $UVLO > 2.5 \text{ V}$, the current source is activated to instantly raise the voltage at the UVLO pin. When the UVLO pin voltage falls below the 2.5-V threshold the current source is turned off, causing the voltage at the UVLO pin to fall. The UVLO hysteresis is determined by Equation 21:

$$V_{HYS} = R_{UVLO1} \times 25 \mu\text{A} \quad (21)$$

An optional ceramic capacitor C_{UVLO} can be placed in parallel with R_{UVLO2} to improve the noise immunity. C_{UVLO} is usually between 1 nF to 10 nF. A large C_{UVLO} may cause excessive delay to respond to a real UVLO event.

If Equation 21 does not provide adequate hysteresis voltage, the user can add R_{UVLO3} as shown in Figure 7-32. The hysteresis voltage is thus given by Equation 22:

$$V_{HYS} = \left[R_{UVLO1} + R_{UVLO3} \times \left(1 + \frac{R_{UVLO1}}{R_{UVLO2}} \right) \right] \times 25 \mu\text{A} \quad (22)$$

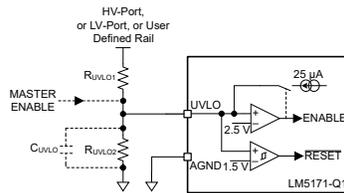


Figure 7-31. UVLO Programming

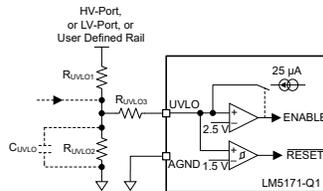


Figure 7-32. UVLO With Additional Hysteresis Programming

7.5 I²C Serial Interface

In LM5171, I²C communication is available when the UVLO pin is $> 1.5\text{V}$ and the configuration is complete. VDD pin voltage falling below 4.5V VDDUV disables the communication, but as long as it stays above 2.5V (the lower threshold), it does not require reconfiguring to enter the I²C communication when VDD goes out of VDDUV.

I²C Bus Operation

The I²C bus is a communications link between a Controller and a series of Peripheral devices. The link is established using a two-wired bus consisting of a serial clock signal (SCL) and a serial data signal (SDA). The serial clock is sourced from the Controller in all cases where the serial data line is bi-directional for data communication between the Controller and the Peripheral terminals. Each device has an open-drain output to transmit data on the serial data line (SDA). An external pull-up resistor must be placed on the serial data line to pull the drain output high during data transmission. The device hosts a Peripheral I²C interface that supports standard-mode, fast-mode and fast-mode plus operation with data rates up to 100 kbit/s, 400 kbit/s and 1000 kbit/s respectively and auto-increment addressing compatible to I²C standard 3.0.

Data transmission is initiated with a start bit from the controller as shown in the figure below. The start condition is recognized when the SDA line transitions from high to low during the high portion of the SCL signal. Upon

reception of a start bit, the device receives serial data on the SDA input and check for valid address and control information. If the peripheral address bits are set for the device, then the device issues an acknowledge pulse and prepares to receive the register address and data. Data transmission is completed by either the reception of a stop condition or the reception of the data word sent to the device. A stop condition is recognized as a low to high transition of the SDA input during the high portion of the SCL signal. All other transitions of the SDA line must occur during the low portion of the SCL signal. An acknowledge is issued after the reception of valid address, sub-address and data words. The I²C interfaces auto-sequence through register addresses, so that multiple data words can be sent for a given I²C transmission.

ADVANCE INFORMATION

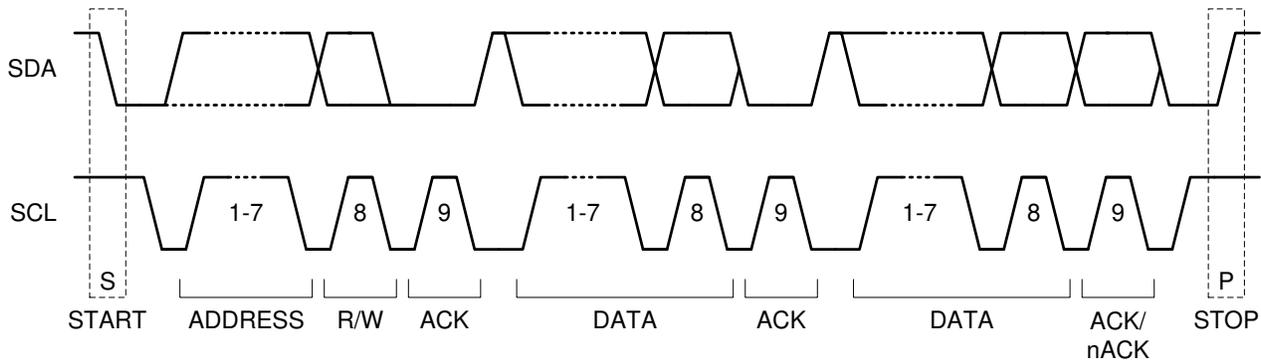


Figure 7-33. I²C START / STOP / ACKNOWLEDGE Protocol

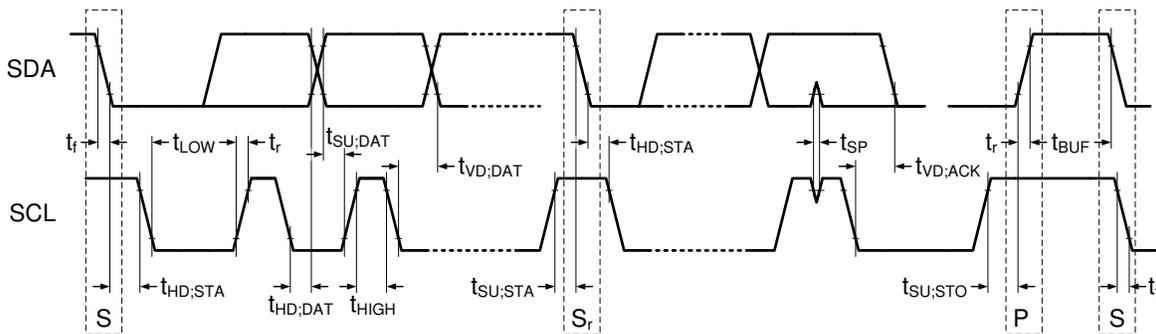


Figure 7-34. I²C Data Transmission Timing

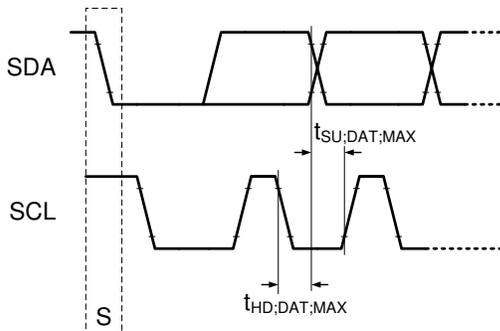


Figure 7-35. I²C Data Transmission Timing for maximum rise/fall times.

Clock Stretching

Clock stretching is not supported. If the device is addressed while busy and not able to process the received data, it does not acknowledge the transaction.

Data Transfer Formats

The device supports four different read/write operations:

- Single read from a defined register address.
- Single write to a defined register address.
- Sequential read starting from a defined register address
- Sequential write starting from a defined register address

Single READ From a Defined Register Address

Figure 7-36 shows the format of a single read from a defined register address. First, the Controller issues a start condition followed by a seven-bit I²C address. Next, the Controller writes a zero to signify that it conducts a write operation. Upon receiving an acknowledge from the Peripheral the Controller sends the eight-bit register address across the bus. Following a second acknowledge the device sets the internal I²C register number to the defined value. Then the Controller issues a repeat start condition and the seven-bit I²C address followed by a one to signify that it conducts a read operation. Upon receiving a third acknowledge, the Controller releases the bus to the device. The device then returns the eight-bit data value from the register on the bus. The Controller does not acknowledge (nACK) and issues a stop condition. This action concludes the register read.

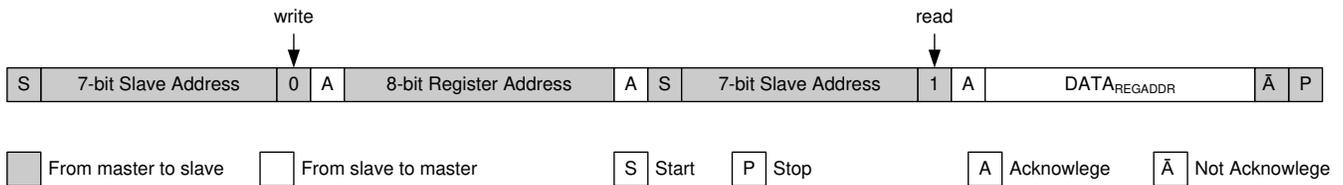


Figure 7-36. Single READ From a Defined Register Address

Sequential READ Starting From a Defined Register Address

A sequential read operation is an extension of the single read protocol and shown in Figure 7-37. The Controller acknowledges the reception of a data byte, the device auto increments the register address and returns the data from the next register. The data transfer is stopped by the Controller not acknowledging the last data byte and sending a stop condition.

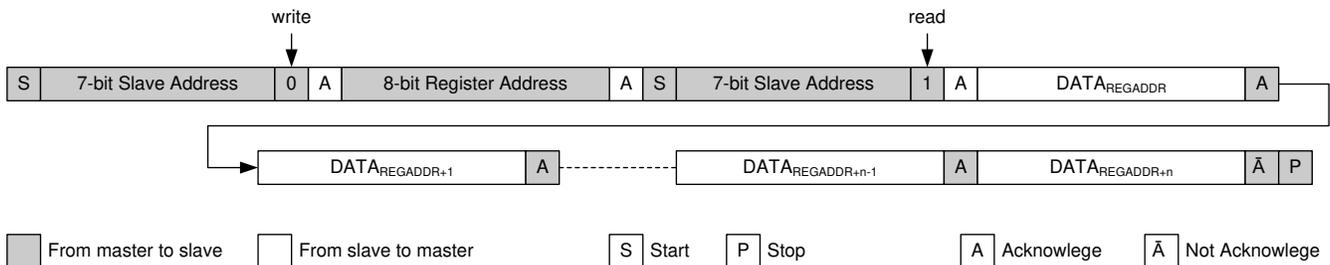


Figure 7-37. Sequential READ Starting From A Defined Register Address

Single WRITE to a Defined Register Address

Figure 7-38 shows the format of a single write to a defined register address. First, the Controller issues a start condition followed by a seven-bit I²C address. Next, the Controller writes a zero to signify that it wishes to conduct a write operation. Upon receiving an acknowledge from the Peripheral, the Controller sends the eight-bit register address across the bus. Following a second acknowledge the device sets the I²C register address

to the defined value and the Controller writes the eight-bit data value. Upon receiving a third acknowledge the device auto increments the I²C register address by one and the Controller issues a stop condition. This action concludes the register write.

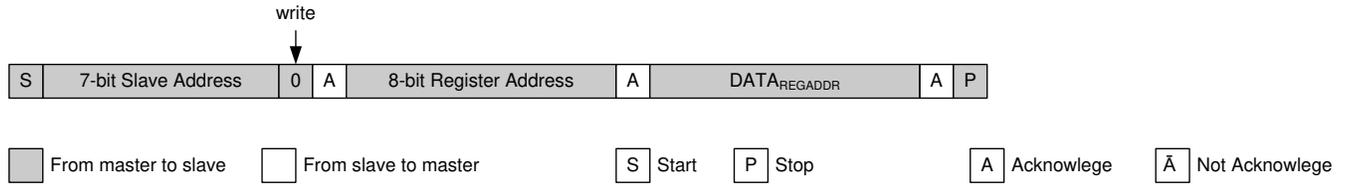


Figure 7-38. Single WRITE to Defined Register Address

Sequential WRITE Starting From A Defined Register Address

A sequential write operation is an extension of the single write protocol and shown in [Figure 7-39](#). If the Controller does not send a stop condition after the device has issued an ACK, the device auto increments the register address by one and the Controller can write to the next register.

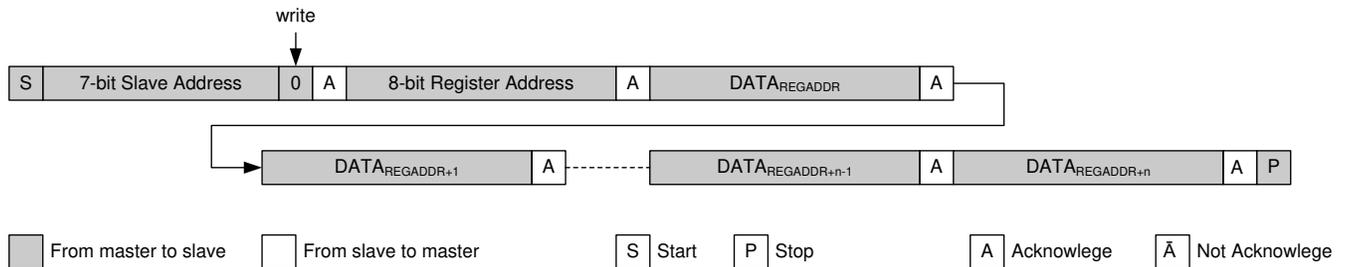


Figure 7-39. Sequential WRITE Starting At A Defined Register Address

7.5.1 REGFIELD Registers

[REGFIELD Registers](#) lists the memory-mapped registers for the REGFIELD registers. All register offset addresses not listed in [REGFIELD Registers](#) should be considered as reserved locations and the register contents should not be modified.

Table 7-4. REGFIELD Registers

Address	Acronym	Register Name	Section
3h	CLEAR_FAULTS	CLEAR_FAULTS	CLEAR_FAULTS Register (Address = 3h) [Reset = 00h]
78h	FAULT_STATUS	FAULT_STATUS	FAULT_STATUS Register (Address = 78h) [Reset = 00h]
D0h	DEVICE_STATUS_1	DEVICE_STATUS_1	DEVICE_STATUS_1 Register (Address = D0h) [Reset = 00h]
D1h	DEVICE_STATUS_2	DEVICE_STATUS_2	DEVICE_STATUS_2 Register (Address = D1h) [Reset = 00h]

Complex bit access types are encoded to fit into small table cells. [REGFIELD Access Type Codes](#) shows the codes that are used for access types in this section.

Table 7-5. REGFIELD Access Type Codes

Access Type	Code	Description
Read Type		
R	R	Read
Write Type		
W	W	Write
Reset or Default Value		
-n	CLEAR FAULT	Value after reset or the default value

7.5.1.1 CLEAR_FAULTS Register (Address = 3h) [Reset = 00h]

CLEAR_FAULTS is shown in [CLEAR_FAULTS Register Field Descriptions](#).

Return to the [REGFIELD Registers](#).

Clear all latched status flags in 0x78 register

Table 7-6. CLEAR_FAULTS Register Field Descriptions

Bit	Field	Type	Reset	Description
7-0	CLEAR_FAULTS	R/W	0h	Accessing the address is enough to clear fault

7.5.1.2 FAULT_STATUS Register (Address = 78h) [Reset = 00h]

FAULT_STATUS is shown in [FAULT_STATUS Register Field Descriptions](#).

Return to the [REGFIELD Registers](#).

Fault status

Table 7-7. FAULT_STATUS Register Field Descriptions

Bit	Field	Type	Reset	Description
7-6	NIL	R	0h	This bit is not implemented in hardware. During write operations data for this bit is ignored. During read operations 0 is returned.
5	BOOTUV1	R	0h	Boot UV (HB-SW undervoltage) Channel 1 0h = no fault 1h = fault
4	BOOTUV2	R	0h	Boot UV (HB-SW undervoltage) Channel 2 0h = no fault 1h = fault
3	ILIM1	R	0h	Peak Current limit Channel 1 0h = no fault 1h = fault
2	ILIM2	R	0h	Peak Current limit Channel 2 0h = no fault 1h = fault
1	OVP	R	0h	Over voltage fault 0h = no fault 1h = fault
0	TSD	R	0h	Thermal shutdown fault 0h = no fault 1h = fault

7.5.1.3 DEVICE_STATUS_1 Register (Address = D0h) [Reset = 00h]

 DEVICE_STATUS_1 is shown in [DEVICE_STATUS_1 Register Field Descriptions](#).

 Return to the [REGFIELD Registers](#).

Informational bits about the part status

Table 7-8. DEVICE_STATUS_1 Register Field Descriptions

Bit	Field	Type	Reset	Description
7	EN1	R	0h	Channel 1 enable status 0h = Channel 1 disabled 1h = Channel 1 enabled
6	EN2	R	0h	Channel 2 enable status 0h = Channel 2 disabled 1h = Channel 2 enabled
5	DEM1	R	0h	Channel 1 DEM status 0h = Channel 1 FPWM 1h = Channel 1 DEM
4	DEM2	R	0h	Channel 2 DEM status 0h = Channel 2 FPWM 1h = Channel 2 DEM
3	DIR1	R	0h	DIR 1 status 0h = DIR1 low 1h = DIR1 high
2	DIR2	R	0h	DIR 2 status 0h = DIR2 low 1h = DIR2 high
1	DIR_INVALID1	R	0h	Invalid DIR1 command 0h = Valid DIR1 command 1h = Invalid DIR1 command
0	DIR_INVALID2	R	0h	Invalid DIR2 command 0h = Valid DIR2 command 1h = Invalid DIR2 command

7.5.1.4 DEVICE_STATUS_2 Register (Address = D1h) [Reset = 00h]

DEVICE_STATUS_2 is shown in [DEVICE_STATUS_2 Register Field Descriptions](#).

Return to the [REGFIELD Registers](#).

Informational bits about the part status

Table 7-9. DEVICE_STATUS_2 Register Field Descriptions

Bit	Field	Type	Reset	Description
7-6	SPARE	R	0h	Spare register - Preset LOW
5	OPT	R	0h	OPT pin status 0h = OPT low 1h = OPT high
4	SS1_DONE	R	0h	SS channel 1 completion status 0h = SS1 not done 1h = SS1 done
3	SS2_DONE	R	0h	SS channel 2 completion status 0h = SS2 not done 1h = SS2 done
2	SD	R	0h	SD/DT pin status 0h = Part not in SD 1h = Part in SD
1	ADAPT_DT	R	0h	Adaptive deadtime status 0h = No adaptive deadtime 1h = Adaptive deadtime
0	VCC_UV	R	0h	VCC UV status 0h = VCC not in UV 1h = VCC in UV

8 Application and Implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

8.1 Application Information

LM5171-Q1 is suitable for the bidirectional DC-DC converters for the automotive 48-V and 12-V dual battery systems, and battery backup systems. It can also create stackable, high power, unidirectional buck or boost converters with balanced current sharing among multiphases.

LM5171-Q1 uses average current mode control which is a two-loop system. LM5171-Q1 integrates two operational amplifiers to achieve HV voltage regulation and LV voltage regulation. Please note only one operational amplifier is enabled according to DIR1. External operational amplifiers may be necessary for CH-2 in case of independent operation. The interface signals between the inner current loop and outer voltage loop are basically the DIR and ISET signals, of which the DIR signal controls the current direction, and the ISET signal carries the error information of the outer voltage loop.

8.1.1 Small Signal Model

The following describes the small signal model of inner current loop and outer voltage loop of LM5171-Q1. Some simplifications are made for better insight. And the compensation for the loops are also introduced.

LM5171-Q1 Design Calculator is also provided for the loop compensation.

8.1.1.1 Current Loop Small Signal Model

Figure 8-1 shows the current loop block diagram of each phase in buck mode. V_{HV} is the input while V_{LV} is the output.

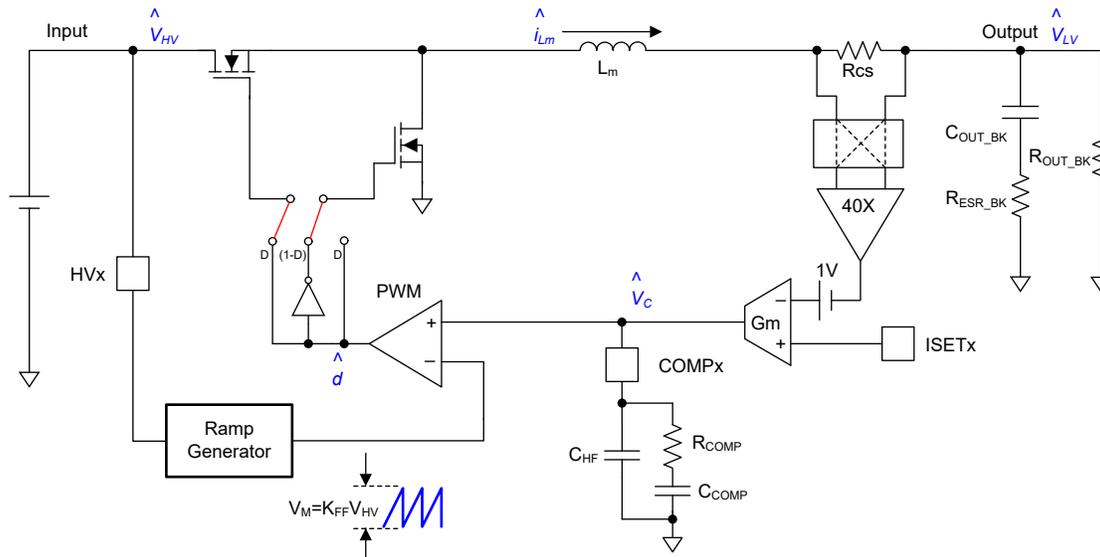


Figure 8-1. Buck Loop Block Diagram

The inner current loop should be designed first. The average current-mode control loop of buck mode can be modeled as: [Figure 8-2](#)

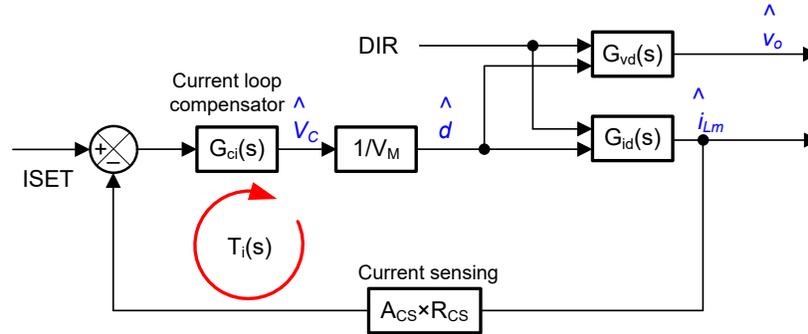


Figure 8-2. Current Loop Block Diagram

The buck power plant transfer function from the duty cycle (d) to the channel inductor current (i_{Lm}) is determined by the following:

$$G_{id_BK}(s) = \frac{\hat{i}_{Lm}}{\hat{d}} = \frac{V_{HV}}{R_{OUT_BK}} \times \frac{1 + \frac{s}{\omega_{Z_il_BK}}}{1 + \frac{s}{\omega_{0_BK} \times Q_{BK}} + \frac{s^2}{\omega_{0_BK}^2}} \quad (23)$$

where

$$R_{OUT_BK} = \frac{V_{LV}}{I_{Lmax}} \quad (24)$$

$$\omega_{Z_il_BK} = \frac{1}{R_{OUT_BK} \times C_{OUT_BK}} \quad (25)$$

$$\omega_{0_BK} = \frac{1}{\sqrt{L_m \times C_{OUT_BK}}} \quad (26)$$

$$Q_{BK} = \frac{1}{\omega_{0_BK}} \times \frac{1}{\frac{L_m}{R_{OUT_BK}} + (R_{ESR_BK} + R_{CS} + R_S) \times C_{OUT_BK}} \quad (27)$$

- L_m is the power inductor,
- R_{CS} is the current sense resistor,
- R_S is the equivalent total resistance along the current path excluding R_{CS} ,
- C_{OUT_BK} is the output capacitance for each phase in buck mode. For a system with n_p phases, C_{OUT_BK} is $1/n_p$ times the total capacitance.
- R_{ESR_BK} is the output capacitor equivalent series resistance (ESR) for each phase in buck mode. For n_p phase system, R_{ESR_BK} is n_p times total system output capacitor ESR.

Figure 8-3 shows the current loop block diagram in boost mode. V_{LV} is the input while V_{HV} is the output.

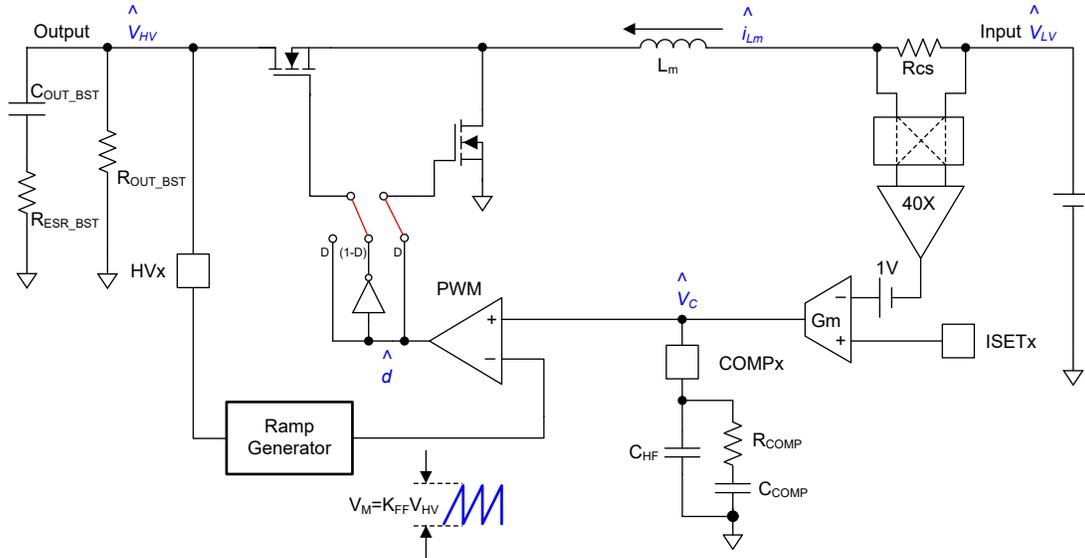


Figure 8-3. Boost Loop Block Diagram

The average current-mode control loop of boost mode is the same as buck as shown in [Figure 8-2](#). But the transfer function of the boost power stage $G_{id}(s)$ and $G_{vd}(s)$ is different from that of buck power stage.

The boost power plant transfer function from the duty cycle (d) to the channel inductor current (i_{Lm}) is determined by the following:

$$G_{id_BST}(s) = \frac{\hat{i}_{Lm}}{\hat{d}} = \frac{2 \times V_{LV}}{(1-D)^3 \times R_{OUT_BST}} \times \frac{1 + \frac{s}{\omega_{Z_il_BST}}}{1 + \frac{s}{\omega_{0_BST} \times Q_{BST}} + \frac{s^2}{\omega_{0_BST}^2}} \quad (28)$$

where

$$D = 1 - \frac{V_{LV}}{V_{HV}} \quad (29)$$

$$R_{OUT_BST} = \frac{V_{HV}^2}{V_{LV} \times I_{Lmax}} \quad (30)$$

$$\omega_{Z_il_BST} = \frac{2}{R_{OUT_BST} \times C_{OUT_BST}} \quad (31)$$

$$\omega_{0_BST} = \frac{1-D}{\sqrt{L_m \times C_{OUT_BST}}} \quad (32)$$

$$Q_{BST} = \frac{1-D}{\omega_{0_BST}} \times \frac{1}{\frac{L_m}{(1-D) \times R_{OUT_BST}} + \frac{(R_{CS} + R_S) \times C_{OUT_BST}}{1-D} + R_{ESR_BST} \times C_{OUT_BST}} \quad (33)$$

- C_{OUT_BST} is the output capacitance for each phase in boost mode. For a system with n_p phases, C_{OUT_BST} is $1/n_p$ times the total capacitance.
- R_{ESR_BST} is the output capacitor equivalent series resistance (ESR) for each phase in boost mode. For a system with n_p phases, R_{ESR_BST} is n_p times total system output capacitor ESR.

When we select the current loop cross over frequency at $1/6$ of switching frequency, $G_{id_BK}(s)$ can be simplified. For the numerator, $s \times R_{OUT_BK} \times C_{OUT_BK}$ dominates. And for the denominator, $s^2/\omega_{0_BK}^2$ dominates. [Equation 23](#) can be simplified as:

$$G_{id_BK}(s) = \frac{V_{HV}}{R_{OUT_BK}} \times \frac{1 + \frac{s}{\omega_{Z_il_BK}}}{\frac{s^2}{\omega_{0_BK}^2}} = \frac{V_{HV}}{s \times L_m} \quad (34)$$

Similarly, Equation 28 can be simplified as:

$$G_{id_BST}(s) = \frac{2 \times V_{LV}}{(1-D)^3 \times R_{OUT_BST}} \times \frac{\frac{s}{\omega_{Z_il_BST}}}{\frac{s^2}{\omega_{0_BST}^2}} = \frac{V_{HV}}{s \times L_m} \quad (35)$$

It can be observed that the same duty cycle (d) to channel inductor current (i_{Lm}) transfer function is shared by both buck and boost mode:

$$G_{id}(s) = \frac{V_{HV}}{s \times L_m} \quad (36)$$

So compensator for buck current loop and boost current loop can also be shared.

8.1.1.2 Current Loop Compensation

Equation 36 indicates that the power plant is basically a first-order system. A Type-II compensator as shown in Figure 8-1 is adequate to stabilize the loop for both buck and boost mode operations.

Assuming the output impedance of the gm amplifier is R_{GM} , the gain from the inductor to the output of gm amplifier is determined by :

$$G_{ci}(s) = G_m \times [R_{GM} || Z_{comp}(s)] \quad (37)$$

where

- A_{CS} is the current sense amplifier gain, that is 40;
- G_m is the trans-conductance of the gm error amplifier, which is 100 μ A/V;
- $Z_{COMP}(s)$ is the equivalent impedance of the compensation network seen at the COMP pin (see Figure 8-1)

$$Z_{COMP}(s) = \frac{1}{C_{HF} + C_{COMP}} \times \frac{1 + s \times R_{COMP} \times C_{COMP}}{s \times \left(1 + s \times R_{COMP} \times \frac{C_{HF} \times C_{COMP}}{C_{HF} + C_{COMP}}\right)} \quad (38)$$

Considering $C_{HF} \ll C_{COMP}$, Equation 38 can be simplified to :

$$Z_{COMP}(s) = \frac{1}{C_{COMP}} \times \frac{1 + s \times R_{COMP} \times C_{COMP}}{s \times (1 + s \times R_{COMP} \times C_{HF})} \quad (39)$$

Because R_{GM} is > 5 Meg Ω , and the frequency range for loop compensation is usually above a few kHz, the effects of R_{GM} on the loop gain in the interested frequency range becomes negligible. Therefore, substituting Equation 39 into Equation 37, and neglecting R_{GM} , one can get the following:

$$G_{ci}(s) = \frac{G_m}{C_{COMP}} \times \frac{1 + s \times R_{COMP} \times C_{COMP}}{s \times (1 + s \times R_{COMP} \times C_{HF})} \quad (40)$$

From Figure 8-2, the open-loop gain of the inner current loop can be found as:

$$T_i(s) = G_{ci}(s) \times \frac{1}{V_M} \times G_{id}(s) \times A_{CS} \times R_{CS} \quad (41)$$

where

$$V_M = V_{HV} \times K_{FF} \quad (42)$$

- K_{FF} is the ramp generator coefficient. For LM5171-Q1, $K_{FF}=0.03125$.

Substituting Equation 40, Equation 42 and Equation 36 into Equation 41, $T_i(s)$ can be written as:

$$T_i(s) = \frac{1}{s \times K_{FF} \times L_m} \times \frac{A_{CS} \times R_{CS} \times G_m}{C_{COMP}} \times \frac{1 + s \times R_{COMP} \times C_{COMP}}{s \times (1 + s \times R_{COMP} \times C_{HF})} \quad (43)$$

The poles and zeros of the total loop transfer function are determined by:

$$f_{p1} = 0 \quad (44)$$

$$f_{p2} = \frac{1}{2\pi \times R_{COMP} \times C_{HF}} \quad (45)$$

$$f_z = \frac{1}{2\pi \times R_{COMP} \times C_{COMP}} \quad (46)$$

To tailor the total inner current loop gain to crossover at f_{CI} , select the components of the compensation network according to the following guidelines, then fine tune the network for optimal loop performance.

1. The zero f_z is placed at around 1/5 of target crossover frequency f_{CI} ,
2. The pole f_{p2} is placed at approximately 1/2 of switching frequency f_{SW} ,
3. The total open-loop gain is set to unity at f_{CI} , namely,

$$\left| G_{ci}(2i \times \pi \times f_{CI}) \times \frac{1}{V_M} \times G_{id}(2i \times \pi \times f_{CI}) \times A_{CS} \times R_{CS} \right| = 1 \quad (47)$$

Therefore, the compensation components can be derived from the above equations, as shown in Equation 48.

$$\begin{cases} R_{COMP} = \frac{K_{FF}}{A_{CS} \times R_{CS} \times G_m} \times |2i \times \pi \times f_{CI} \times L_m| \\ C_{COMP} = \frac{1}{|2i \times \pi \times \frac{f_{CI}}{5} \times R_{COMP}|} \\ C_{HF} = \frac{1}{|2i \times \pi \times \frac{f_{SW}}{2} \times R_{COMP}|} \end{cases} \quad (48)$$

8.1.1.3 Voltage Loop Small Signal Model

When the current loop compensator is designed, the outer voltage loop can then be analyzed. Figure 8-4 shows the outer voltage control loop and inner current loop.

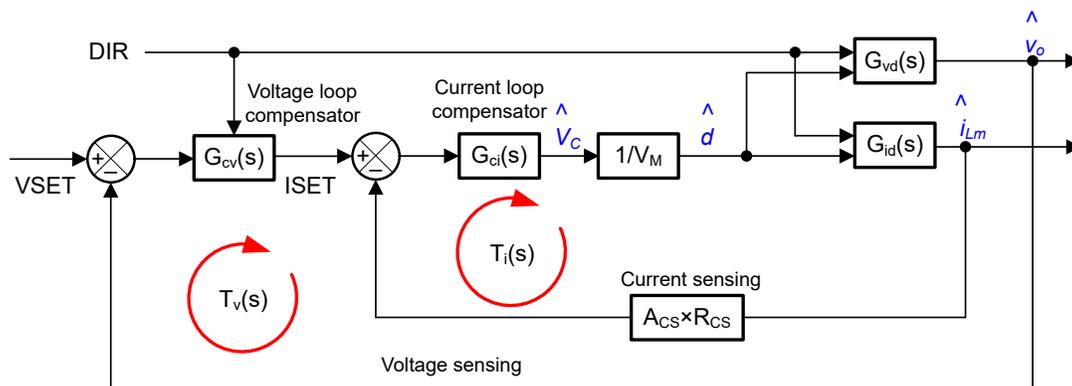


Figure 8-4. Voltage Loop and Current Loop Block Diagram

We can get the close loop transfer function from ISET to the output voltage (v_O) as:

$$G_{vs}(s) = \frac{\hat{v}_{LV}}{\hat{v}_{ISET}} = \frac{G_{ci}(s) \times \frac{1}{V_M} \times G_{vd}(s)}{1 + T_i(s)} \quad (49)$$

When selecting the crossover frequency of the buck voltage loop lower than the current loop crossover frequency, $G_{vs}(s)$ can be simplified. For the denominator, $T_i(s)$ dominates, [Equation 49](#) can be written as:

$$G_{vs}(s) = \frac{\hat{v}_{LV}}{\hat{v}_{ISET}} = \frac{G_{ci}(s) \times \frac{1}{V_M} \times G_{vd}(s)}{T_i(s)} = \frac{G_{vd}(s)}{G_{id}(s) \times A_{CS} \times R_{CS}} \quad (50)$$

The buck power plant transfer function from the duty cycle (d) to the output voltage (v_{LV}) is determined by the following:

$$G_{vd_BK}(s) = \frac{\hat{v}_{LV}}{d} = V_{HV} \times \frac{1 + \frac{s}{\omega_{Z_vl_BK}}}{1 + \frac{s}{\omega_{0_BK} \times Q_{BK}} + \frac{s^2}{\omega_{0_BK}^2}} \quad (51)$$

where

$$\omega_{Z_vl_BK} = \frac{1}{R_{ESR_BK} \times C_{OUT_BK}} \quad (52)$$

Substituting [Equation 51](#) into [Equation 50](#), a simplified transfer function from the ISET voltage to the Output voltage (V_{LV}) is determined by the following:

$$G_{vs_BK}(s) = \frac{\hat{v}_{LV}}{\hat{v}_{ISET}} = K_{dc_BK} \times \frac{1 + \frac{s}{\omega_{Z_vl_BK}}}{1 + \frac{s}{\omega_{Z_il_BK}}} \quad (53)$$

where

$$K_{dc_BK} = \frac{R_{OUT_BK}}{A_{CS} \times R_{CS}} \quad (54)$$

Similarly, the boost power plant transfer function from the duty cycle (d) to the output voltage (v_{HV}) is determined by the following:

$$G_{vd_BST}(s) = \frac{\hat{v}_{HV}}{d} = \frac{V_{LV}}{(1-D)^2} \times \frac{\left(1 + \frac{s}{\omega_{Z_vl_BST}}\right) \left(1 + \frac{s}{\omega_{RHPZ}}\right)}{1 + \frac{s}{\omega_{0_BST} \times Q_{BST}} + \frac{s^2}{\omega_{0_BST}^2}} \quad (55)$$

where

$$\omega_{Z_vl_BST} = \frac{1}{R_{ESR_BST} \times C_{OUT_BST}} \quad (56)$$

$$\omega_{RHPZ} = \frac{R_{OUT_BST} \times (1-D)}{L_m} \quad (57)$$

Substituting [Equation 55](#) into [Equation 50](#), a simplified transfer function from the ISET voltage to the output voltage (V_{HV}) is determined by the following:

$$G_{vs_BST}(s) = \frac{\hat{v}_{HV}}{\hat{i}_{set}} = K_{dc_BST} \times \frac{\left(1 + \frac{s}{\omega_{Z_vl_BST}}\right)\left(1 - \frac{s}{\omega_{RHPZ}}\right)}{1 + \frac{s}{\omega_{Z_il_BST}}} \quad (58)$$

where

$$K_{dc_BST} = \frac{R_{OUT_BST} \times (1-D)}{2 \times A_{CS} \times R_{CS}} \quad (59)$$

8.1.1.4 Voltage Loop Compensation

The typical bi-directional application with HV voltage regulation and LV voltage regulation is shown in Figure 8-5. Connect the error voltage of the outer voltage loop error amplifiers (ERRHV and ERRLV) to ISETx as the reference for the inner current loop.

It is advised that the outer voltage loop crossover frequency f_{CV} should be one decade below that of the inner current loop crossover frequency f_{CI} . And boost outer voltage loop crossover frequency should also be below 1/5 of the Right-Half-Plane Zero (RHPZ).

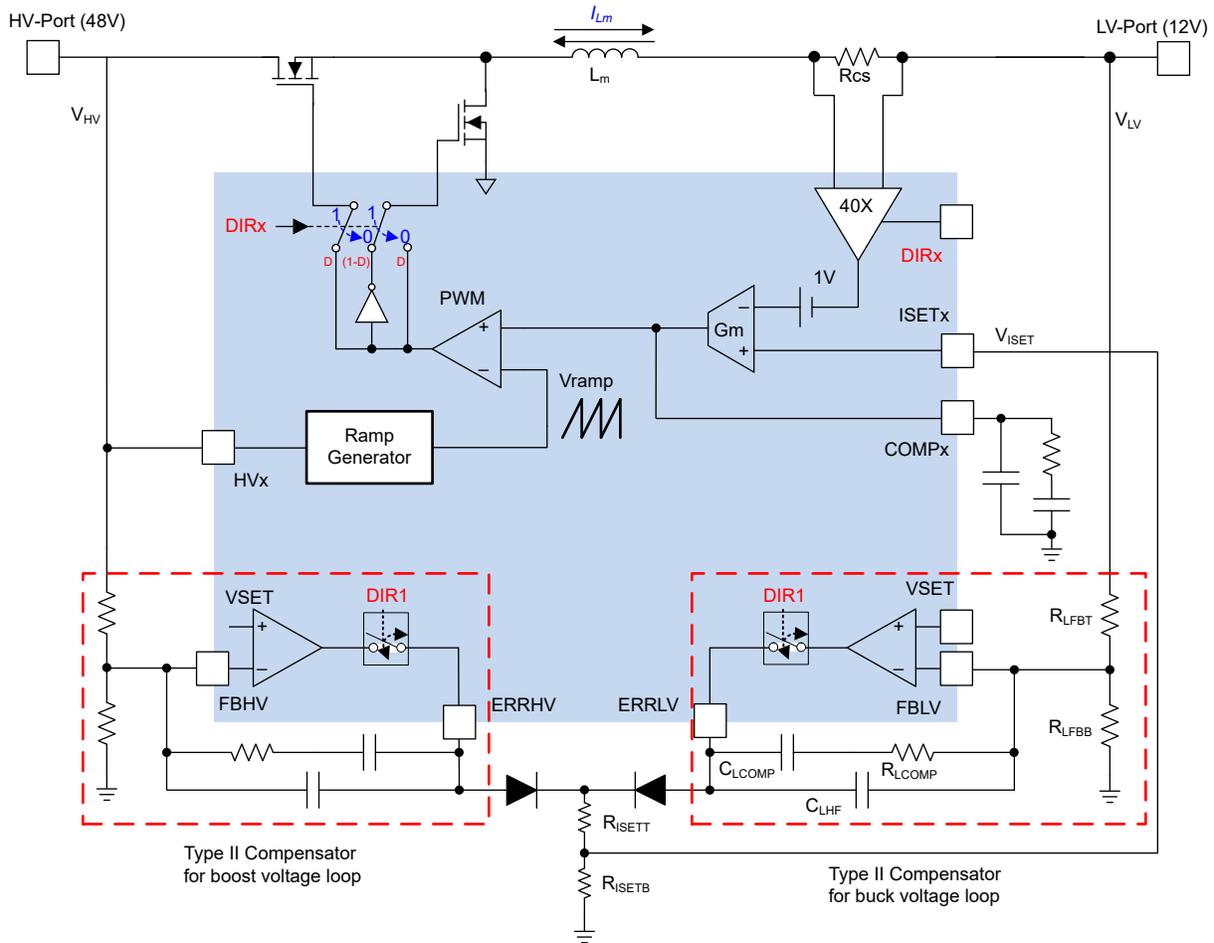


Figure 8-5. Outer Voltage Loop Control

Type-II compensator as shown in Figure 8-5 is recommended to stabilize the voltage loop for both buck and boost mode operations.

Buck mode compensation will be analyzed as an example. The transfer function of the compensator of buck mode can be found as:

$$G_{cv}(s) = \frac{\hat{V}_{ISET}}{\hat{V}_{LV}} \approx \frac{A_{VM} \times \omega_{ZEA}}{s} \times \frac{1 + \frac{s}{\omega_{ZEA}}}{1 + \frac{s}{\omega_{HF}}} \times K_{ISET} \quad (60)$$

where

$$A_{VM} \approx \frac{R_{LCOMP}}{R_{LFBT}} \quad (61)$$

$$\omega_{ZEA} = \frac{1}{R_{LCOMP} \times C_{LCOMP}} \quad (62)$$

$$\omega_{HF} \approx \frac{1}{R_{LCOMP} \times C_{LHF}} \quad (63)$$

$$K_{ISET} = \frac{R_{ISETB}}{R_{ISETT} + R_{ISETB}} \quad (64)$$

The total open-loop gain of the outer voltage loop of buck mode $T_{V_BK}(s)$ is the product of $G_{vs_BK}(s)$ and $G_{cv}(s)$:

$$T_{V_BK}(s) = G_{vs_BK}(s) \times G_{cv}(s) \quad (65)$$

Or:

$$T_{V_BK}(s) = K_{dc_BK} \times \frac{1 + \frac{s}{\omega_{Z_vl}}}{1 + \frac{s}{\omega_{Z_il}}} \times \frac{A_{VM} \times \omega_{ZEA}}{s} \times \frac{1 + \frac{s}{\omega_{ZEA}}}{1 + \frac{s}{\omega_{HF}}} \times K_{ISET} \quad (66)$$

To tailor the total outer voltage loop gain to crossover at f_{CV} , select the components of the compensation network according to the following guidelines, then fine tune the network for optimal loop performance.

1. Choose a value for R_{LFBT} based on the bias current and power dissipation,
2. The zero f_z is placed around 1/5 of target crossover frequency f_{CV} ,
3. The pole f_{p2} is placed at approximately 10 times of f_{CV} ,
4. The total open-loop gain is set to unity at f_{Cl} , namely,

$$|G_{vs_BK}(2i \times \pi \times f_{CV}) \times G_{cv}(2i \times \pi \times f_{CV})| = 1 \quad (67)$$

Therefore, the compensation components can be derived from the above equations as:

$$\left\{ \begin{array}{l} R_{LCOMP} = \frac{R_{LFBT}}{K_{dc_BK} \times \left| \frac{1 + \frac{\omega_{Z_vl}}{2i \times \pi \times f_{CV}}}{1 + \frac{\omega_{Z_il}}{2i \times \pi \times f_{CV}}} \right| \times K_{ISET}} \\ C_{LCOMP} = \frac{1}{\left| 2i \times \pi \times \frac{f_{CV}}{5} \times R_{COMP} \right|} \\ C_{LHF} = \frac{1}{\left| 2i \times \pi \times 10 \times f_{CV} \times R_{COMP} \right|} \end{array} \right. \quad (68)$$

The compensator of boost voltage loop can be designed similarly. Please note that boost voltage loop crossover frequency should also be below 1/5 of the Right-Half-Plane Zero (RHPZ).

8.2 Typical Application

8.2.1 60-A, Dual-Phase, 48-V to 12-V Bidirectional Converter

A typical application example is a 60-A, dual-phase bidirectional converter as shown in Figure 8-6. The HV-Port voltage range is 32 V to 70 V and the LV-Port 0 V to 23 V. Each phase is able to deliver 30-A dc current through the inductor.

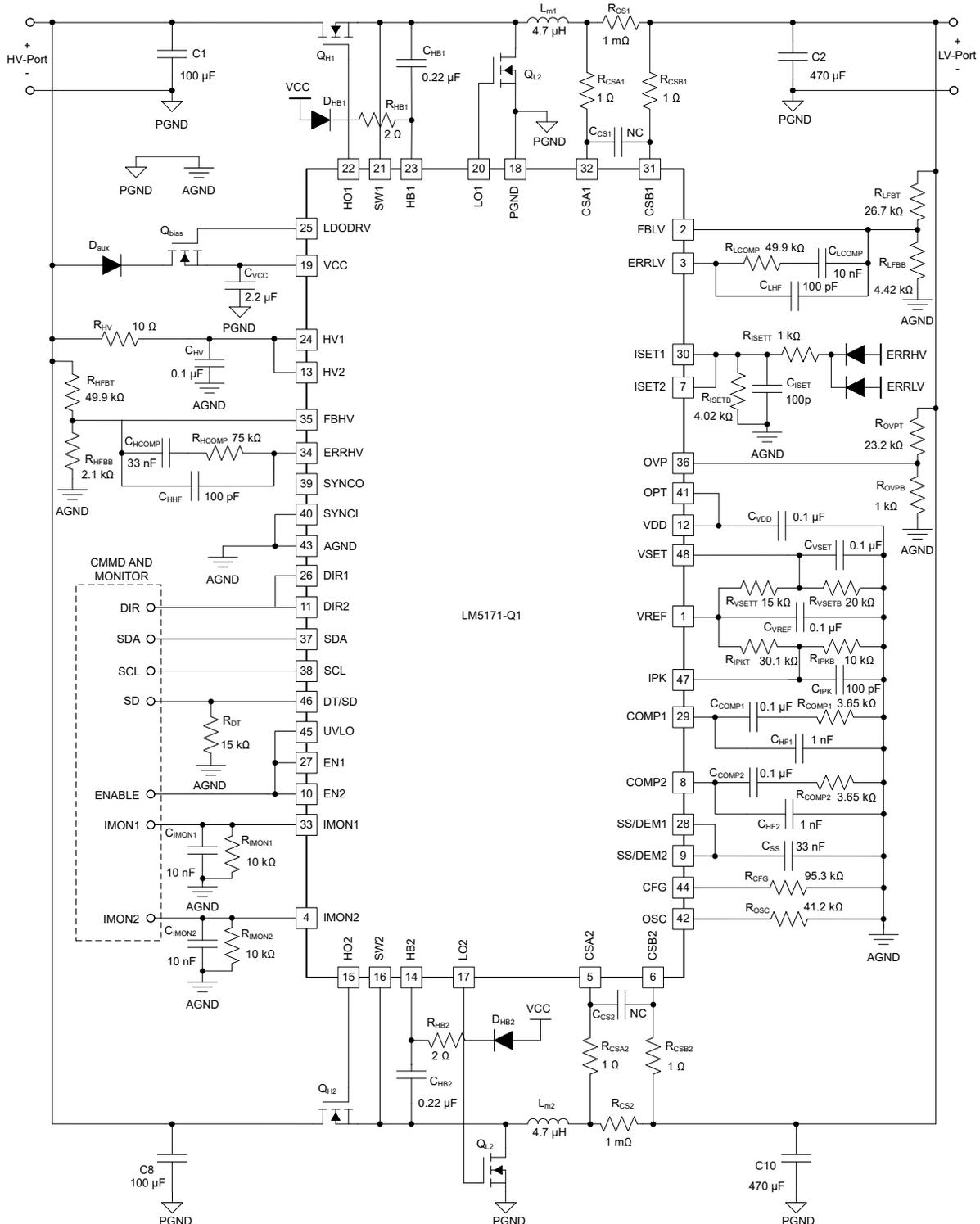


Figure 8-6. Schematic of the Example Dual-Phase Bidirectional Converter

8.2.1.1 Design Requirements

Table 8-1 lists the design parameters for this example.

Table 8-1. Design Parameters

PARAMETER	EXAMPLE VALUE	NOTE
V_{LV_min}	6 V	LV-Port minimum operating voltage
V_{LV_reg}	14 V	LV-Port nominal voltage
V_{LV_max}	23 V	LV-Port maximum operating voltage
V_{HV_min}	32 V	HV-Port minimum operating voltage
V_{HV_reg}	50 V	HV-Port nominal operating voltage
V_{HV_max}	70 V	HV-Port maximum operating voltage
F_{SW}	100 kHz	Switching frequency
I_{Lmax}	30 A	Maximum average inductor current for each channel
I_{total}	60 A	Total bidirectional DC at the LV-Port

8.2.1.2 Detailed Design Procedure

8.2.1.2.1 Determining the Duty Cycle

Obviously, the duty cycles are determined by Equation 69 through Equation 72:

$$D_{BK_min} = \frac{V_{LV_reg}}{V_{HV_max}} = \frac{14 \text{ V}}{70 \text{ V}} = 0.2 \quad (69)$$

$$D_{BK_max} = \frac{V_{LV_reg}}{V_{HV_min}} = \frac{14 \text{ V}}{32 \text{ V}} = 0.438 \quad (70)$$

$$D_{BST_min} = \frac{V_{HV_reg} - V_{LV_max}}{V_{HV_reg}} = \frac{50 \text{ V} - 23 \text{ V}}{50 \text{ V}} = 0.54 \quad (71)$$

$$D_{BST_max} = \frac{V_{HV_reg} - V_{LV_min}}{V_{HV_reg}} = \frac{50 \text{ V} - 6 \text{ V}}{50 \text{ V}} = 0.88 \quad (72)$$

8.2.1.2.2 Oscillator Programming

To operate the converter at the desired switching frequency F_{SW} , select the R_{OSC} by satisfying Equation 16, namely,

$$R_{osc} = \frac{41.5k\Omega \times 100kHz}{F_{osc}} = 41.5k\Omega \quad (73)$$

Choose standard resistor $R_{OSC} = 41.2 \text{ k}\Omega$.

8.2.1.2.3 Power Inductor, RMS and Peak Currents

The inductor current has a triangle waveform, as shown in Effects of Parasitic Inductance on the Current Sense Signal and Zero Crossing Detection. TI recommends selecting an inductor such that its peak-to-peak ripple current is less than 80% of the channel inductor full load DC current. Therefore, the inductor must satisfy Equation 74:

$$L_m \geq \frac{V_{LV_reg} \times (1 - D_{BK_min})}{80\% \times I_{Lmax} \times F_{sw}} = \frac{14 \text{ V} \times (1 - 0.2)}{0.8 \times 30 \text{ A} \times 100 \text{ kHz}} = 4.67 \text{ }\mu\text{H} \quad (74)$$

Select $L_m = 4.7 \text{ }\mu\text{H}$.

Then, the actual inductor peak to peak inductor current is determined by [Equation 75](#):

$$I_{pk-pk} = \frac{V_{LV_reg} \times (1 - D_{BK_min})}{L_m \times F_{sw}} = \frac{14 \text{ V} \times (1 - 0.2)}{4.7 \text{ } \mu\text{H} \times 100 \text{ kHz}} = 23.83 \text{ A} \quad (75)$$

The peak inductor current is determined by [Equation 76](#):

$$I_{peak} = I_{max} + \frac{I_{pk-pk}}{2} = 30 \text{ A} + \frac{23.83}{2} = 41.9 \text{ A} \quad (76)$$

Select an inductor that has a saturation current I_{sat} at least 20% greater than I_{peak} to ensure full power with adequate margin. In this example, TI recommends selecting an inductor of $I_{sat} > 49 \text{ A}$.

The power inductor full load Root Mean Square (RMS) current I_{LM_RMS} determines its conduction losses. The RMS current is given by [Equation 77](#):

$$I_{LM_RMS} = \sqrt{I_{max}^2 + \frac{1}{12} \times I_{pk-pk}^2} = 30.8 \text{ A} \quad (77)$$

8.2.1.2.4 Current Sense (R_{CS})

To achieve the highest regulation accuracy over wider load range, the user must target to create 50-mV of V_{CS} at full current. Therefore, R_{CS} must be selected as [Equation 78](#):

$$R_{CS} \leq \frac{50 \text{ mV}}{I_{max}} = \frac{50 \text{ mV}}{30 \text{ A}} = 1.667 \text{ m}\Omega \quad (78)$$

Ideally, a 1.5-m Ω current sense resistor must be chosen for this example. However, owing to availability, a standard non-inductive 1-m Ω current sense resistor is selected, namely,

$$R_{CS} = 1.0 \text{ m}\Omega \quad (79)$$

Wide terminal chip resistors are recommended for minimized parasitic inductance. For low ohmic value resistors, 4-terminal current sense resistors are suggested for best accuracy.

It is a good practice to reserve room for some ceramic capacitors for possible noise filtering as shown in [Figure 8-7](#). C_{CS1} and C_{CS2} filter out differential-mode noise, 100-pF ceramic capacitors at each current sense pin filter out common-mode noise.

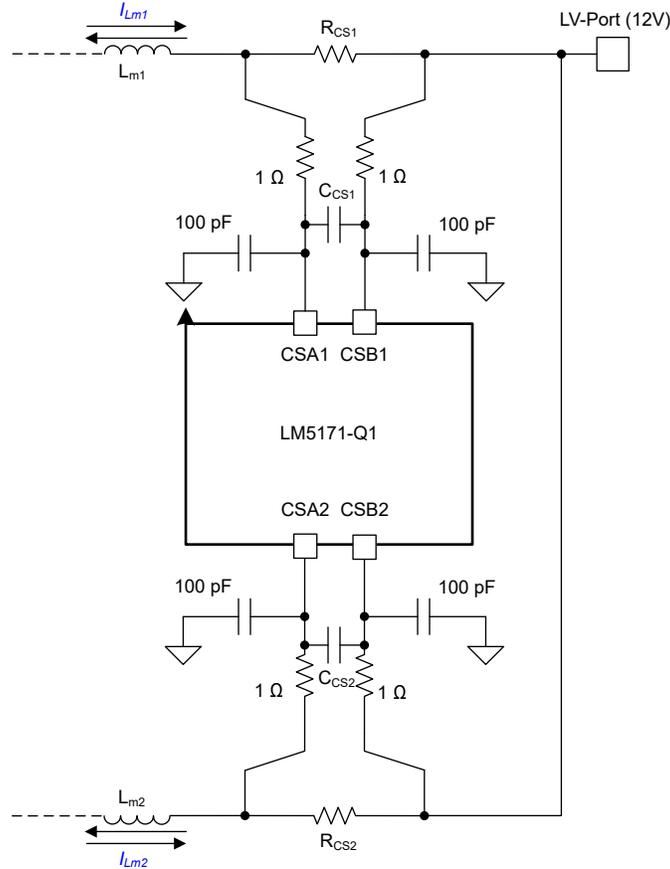


Figure 8-7. Current Sense With RC filter

ADVANCE INFORMATION

8.2.1.2.5 Current Setting Limits (ISETx)

TI recommends setting a hard limit of the maximum current programming signal such that the converter cannot be over driven by an errant current programming signal. Assume the converter is allowed up to 10% overloading current. Refer to [Channel Current Setting Commands \(ISET1 and ISET2\)](#), the analog current setting signal ISETx must be limited by the following voltage level:

$$V_{ISET_max} = \frac{110\% \times I_{max} \times R_{CS}}{G_{ISET}} + 1V = \frac{110\% \times 30A \times 1m\Omega}{0.025} + 1V = 2.32V \quad (80)$$

As shown in [Figure 8-5](#), R_{ISETT} and R_{ISETB} are used to limit the maximum voltage on ISETx.

8.2.1.2.6 Peak Current Limit

One purpose of the peak current limit is to protect the power inductor from saturation. Program V_{IPK} such that the peak current limit threshold is 5% greater than I_{peak} . According to [Equation 12](#), one gets:

$$V_{IPK} = \frac{105\% \times I_{peak} \times R_{CS}}{G_{IPK}} = \frac{105\% \times 41.9A \times 1m\Omega}{0.05} = 0.880V \quad (81)$$

Select $R_{IPKB} = 10 \text{ k}\Omega$ and $R_{IPKT} = 30.1 \text{ k}\Omega$ which results in $V_{IPK} = 0.873V$, corresponding to a nominal peak inductor current limit of 43.6 A per channel.

8.2.1.2.7 Power MOSFETS

The power MOSFETs must be chosen with a V_{DS} rating capable of withstanding the maximum HV-port voltage plus transient spikes (ringing). 100 V rated MOSFETs is selected in this application.

When the voltage rating is determined, select the MOSFETs by making tradeoffs between the MOSFET $R_{ds(ON)}$ and total gate charge Q_g to balance the conduction and switching losses. For high power applications, parallel

MOSFETs to share total power and reduce the dissipation on any individual MOSFET, hence relieving the thermal stress. The conduction losses in each MOSFET is determined by Equation 82.

$$P_{Q_cond} = \frac{1.8 \times R_{ds(ON)}}{N} \times I_{Q_RMS}^2 \quad (82)$$

where

- N is the number of MOSFETs in parallel
- 1.8 is the approximate temperature coefficient of the $R_{ds(ON)}$ at 125 °C
- and the total RMS switch current I_{Q_RMS} is approximately determined by Equation 83

$$I_{Q_RMS} \approx \sqrt{D_{max}} \times I_{max} = \sqrt{D_{max}} \times I_{max} \quad (83)$$

where

- D_{max} is the maximum duty cycle, either in the buck mode or boost mode.

The switching transient rise and fall times are approximately determined by:

$$\Delta t_{rise} \approx \frac{N \times Q_g}{4 A} \quad (84)$$

$$\Delta t_{fall} \approx \frac{N \times Q_g}{5 A} \quad (85)$$

And the switching losses of each of the paralleled MOSFETs are approximately determined by:

$$P_{Q_sw} = \frac{1}{2} \times C_{oss} \times V_{HV}^2 \times F_{sw} + \frac{1}{2} \times \frac{I_{peak}}{N} \times V_{HV} \times (\Delta t_{rise} + \Delta t_{fall}) \times F_{sw} \quad (86)$$

where

- C_{oss} is the output capacitance of the MOSFET.

The power MOSFET usually requires a gate-to-source resistor of 10 kΩ to 100 kΩ to mitigate the effects of a failed gate drive. When using parallel MOSFETs, a good practice is to use 1- to 2-Ω gate resistor for each MOSFET, as shown in Figure 8-8.

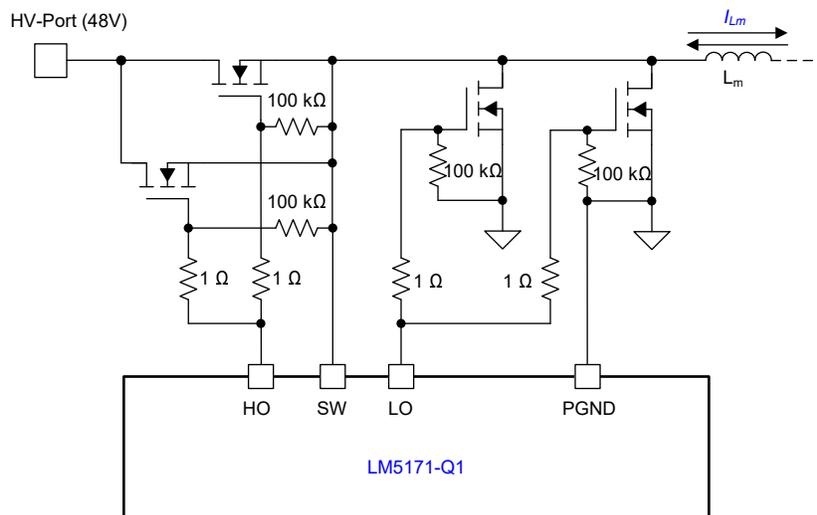


Figure 8-8. Paralleled MOSFET Configuration

If the dead time is not optimal, the body diode of the power synchronous rectifier MOSFET causes losses in reverse recovery. Assuming the reverse recovery charge of the power MOSFET is Q_{rr} , the reverse recovery losses are thus determined by [Equation 87](#):

$$P_{Q_{rr}} = Q_{rr} \times V_{HV_max} \times F_{sw} \quad (87)$$

To reduce the reverse recovery losses, an optional Schottky diode can be placed in parallel with the power MOSFETs. The diode must have the same voltage rating as the MOSFET, and it must be placed directly across the MOSFETs drain and source. The peak repetitive forward current rating must be greater than I_{peak} , and the continuous forward current rating must be greater than the following [Equation 88](#):

$$I_{SD_avg} = I_{peak} \times t_{DT} \times F_{sw} \quad (88)$$

8.2.1.2.8 Bias Supply

The total load current of the bias supply is mainly determined by the total MOSFET gate charge Q_g . Assume the system employs multiple LM5171-Q1s to implement M number of phases, and each phase uses N number of MOSFETs in parallel as one switch. There are $2 \times N$ MOSFETs per phase to drive. Then the total current to drive these MOSFETs through VCC bias supply is determined by [Equation 89](#).

$$I_{VCC} = 2 \times M \times N \times Q_g \times F_{sw} + M \times 5 \text{ mA} \quad (89)$$

where

- 5 mA is the worst case maximum current used by the control logic circuit of each phase.

In an example of a four-phase system employing two parallel MOSFETs for one switch, where $M = 4$, $N = 2$, $Q_g = 100 \text{ nC}$, and $F_{sw} = 100 \text{ KHz}$, the bias supply must be able to support at least the following total load current:

$$I_{VCC} \geq 2 \times 4 \times 2 \times 100 \text{ nC} \times 100 \text{ kHz} + 4 \times 5 \text{ mA} = 180 \text{ mA} \quad (90)$$

In an example of an eight-phase system employing the same parallel MOSFETs for one switch, the bias supply must be able to support the following total load current:

$$I_{VCC_8ph} = 2 \times 8 \times 2 \times 100 \text{ nC} \times 100 \text{ kHz} + 8 \times 5 \text{ mA} = 360 \text{ mA} \quad (91)$$

As described in [Bias Supplies and Voltage Reference \(VCC, VDD, and VREF\)](#) The LM5171-Q1 integrates a LDO driver to drive an external N-channel enhancement MOSFET to generate 9V bias supply at the VCC pin. PMT560ENEAX is selected in this application.

However, the loss of the external MOSFET may be quite high especially in high load current and high input voltage conditions. External 10- to 12-V VCC bias supply may be preferred. If not available in the system, the user can generate it from the LV-port using a buck-boost or SEPIC converter, or from the HV-port using a buck converter. Refer to the Texas Instruments [LM25118-Q1](#) and [LM5118-Q1](#) to implement a buck-boost converter, or [LM5001-Q1](#) to implement a SEPIC converter, or the [LM5160-Q1](#) and [LM5161-Q1](#) to implement a buck converter.

A bypass capacitor must be placed close to the VCC and PGND pins. In this application, 2.2 μF , 16 V ceramic capacitor is selected.

8.2.1.2.9 Boot Strap

Select a ceramic capacitor $C_{HB1} = C_{HB2} = 0.1$ to approximately 0.22 μF , placed close to the HB and SW pins. The fast switching diode of the forward current rated at 1-A and reverse voltage not lower than V_{HV_max} must be selected as the boot strap diode, through which the boot capacitor C_{HB1} or C_{HB2} is charged by VCC. To reduce the noise caused by the fast charging current, a 2- Ω to 5- Ω current limiting resistor must be placed in series with each boot diode.

8.2.1.2.10 OVP

As described in [Overvoltage Protection \(OVP\)](#), LM5171-Q1 has a built in comparator with 1V internal reference and 100mV hysteresis to fulfill overvoltage protection.

In this application, We select LV-prot OVP voltage $V_{OVP} = 24V$. Here we select $R_{OVPB} = 1\text{ k}\Omega$ thus the current through R_{OVPB} is 1mA. R_{OVPT} can be found according to:

$$R_{OVPT} = \frac{V_{OVP} - V_{OVPTH}}{V_{OVPTH}} \times R_{OVPB} = \frac{24V - 1V}{1V} \times 1k\Omega = 23k\Omega \quad (92)$$

Choose standard resistor $R_{OVPT} = 23.2\text{ k}\Omega$.

8.2.1.2.11 Dead Time

Pull DT pin to VDD via a 20k Ω resistor to enable built-in adaptive dead time,.

To program the dead time, follow [Equation 14](#) to select the resistor R_{DT} . To dynamically adjust the dead time with an external analog voltage signal, follow [Figure 7-29](#). To dynamically adjust the dead time with an external PWM signal, follow [Figure 7-30](#).

In this application, the nominal dead time is selected to be 50 ns. According to [Equation 14](#), the programming resistor must be:

$$R_{DT} = \frac{t_{DT} \text{ k}\Omega}{2.625 \text{ ns}} = 19.05k\Omega \quad (93)$$

Select standard value $R_{DT} = 20\text{ k}\Omega$.

8.2.1.2.12 Channel Current Monitor (IMONx)

For best current monitor accuracy, choose IMONx resistor that the maximum operating voltage on the IMONx pin is less than 3 V.

Considering two phase current monitoring with maximum 50A for each channel, and make sure IMONx voltage no more than 3V, R_{IMONx} can be find as:

$$R_{IMONx} = 10\text{ k}\Omega \quad (94)$$

Choose C_{IMONx} considering delay and voltage ripple. Here we select:

$$C_{IMONx} = 10\text{ nF} \quad (95)$$

Then the delay of the monitor is determined by the following time constant:

$$\tau_{IMONx} = R_{IMONx} \times C_{IMONx} = 10k\Omega \times 10ns = 100\mu s \quad (96)$$

At full load, the DC component of the monitor voltage is:

$$V_{IMONx} = 2 \times \left(\frac{I_{max} \times R_{CS}}{500\Omega} + 50\mu A \right) \times R_{IMONx} = 2 \times \left(\frac{30A \times 1m\Omega}{500\Omega} + 50\mu A \right) \times 10k\Omega = 2.2V \quad (97)$$

Considering the inductor ripple current, according to [Equation 6](#), the IOU peak to peak ripple current is:

$$\Delta I_{IMONx} = \frac{I_{pk-pk} \times R_{CS}}{500\Omega} = \frac{23.8A \times 1m\Omega}{500\Omega} = 47.6\mu A \quad (98)$$

The RC filter corner frequency is thus given by:

$$f_{IMONx} = \frac{1}{2\pi \times R_{IMONx} \times C_{IMONx}} = \frac{1}{6.28 \times 10k\Omega \times 10nF} = 1.59kHz \quad (99)$$

The resulting peak-to-peak monitor ripple voltage is approximately determined by:

$$\Delta V_{IMONx} = \Delta IMONx \times \left[R_{IMONx} \parallel \frac{1}{2i \times \pi \times F_{SW} \times C_{IMONx}} \right] = 47.6\mu A \times \left[10k\Omega \parallel \frac{1}{2i \times \pi \times 100kHz \times 10nF} \right] = 7.5mV \quad (100)$$

The peak-to-peak monitor ripple voltage is approximately 0.34% of the full load DC monitor voltage. Increasing C_{IMONx} attenuates the ripple voltage at the cost of higher monitor delay.

8.2.1.2.13 UVLO Pin Usage

The example circuit uses UVLO pin as the Controller enable pin of LM5171-Q1. However, UVLO pin can also fulfill the function of undervoltage lockout, either the 48-V rail UVLO, or 12-V rail UVLO, or VCC UVLO.

Assume the user implements the 48-V rail UVLO, and the low-side resistor $R_{UVLO2} = 10\text{ k}\Omega$, the 48 V UVLO release threshold $V_{UVLO} = 24\text{ V}$, and UVLO hysteresis is $V_{HYS} = 2.4\text{ V}$. Referring to [Figure 7-32](#) and [Equation 20](#), one can find that R_{UVLO1} is given by:

$$R_{UVLO1} = \frac{V_{UVLO} - 2.5\text{ V}}{2.5\text{ V}} \times R_{UVLO2} = \frac{24\text{ V} - 2.5\text{ V}}{2.5\text{ V}} \times 10\text{ k}\Omega = 86\text{ k}\Omega \quad (101)$$

The final selection must select the closest standard resistor of $R_{UVLO1} = 86.6\text{ k}\Omega$.

And R_{UVLO3} must satisfy [Equation 22](#), namely,

$$R_{UVLO3} = \frac{\frac{V_{HYS}}{25\text{ }\mu A} - R_{UVLO1}}{1 + \frac{R_{UVLO1}}{R_{UVLO2}}} = \frac{\frac{2.4\text{ V}}{25\text{ }\mu A} - 86.6\text{ k}\Omega}{1 + \frac{86.6\text{ k}\Omega}{10\text{ k}\Omega}} = 0.973\text{ k}\Omega \quad (102)$$

Select the closest standard resistor, $R_{UVLO1} = 976\text{ }\Omega$.

If the user chooses to add the capacitor $C_{UVLO} = 1\text{ nF}$, it leads to a delay time constant of $10\text{ }\mu s$ to filter possible noise at the UVLO pin.

8.2.1.2.14 HVx Pin Configuration

The HVx pin must always be connected to the HV voltage rail. It is good practice to add a small RC filter to improve the HVx noise immunity, as shown in [Figure 8-9](#). Usually the filter resistor is $10\text{ }\Omega$, and the bypass capacitor is $0.1\text{ }\mu F$.

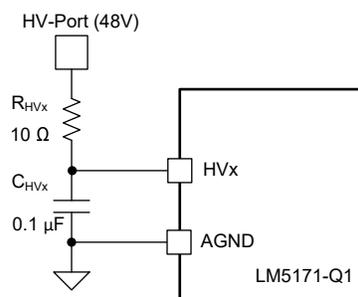


Figure 8-9. HVx Pin Configuration

8.2.1.2.15 Loop Compensation

Select current loop cross over frequency f_{Cl} to 1/6 of the switching frequency. According to [Equation 48](#), the compensation network for the inner current loop is determined by:

$$\begin{cases} R_{COMP} = \frac{K_{FF}}{A_{CS} \times R_{CS} \times G_m} \times |2i \times \pi \times f_{CI} \times L_m| = \frac{0.03125}{40 \times 1m\Omega \times 100\mu A/V} \times |2i \times \pi \times 15kHz \times 4.7\mu H| = 3.5k\Omega \\ C_{COMP} = \frac{1}{|2i \times \pi \times \frac{f_{CI}}{5} \times R_{COMP}|} = \frac{1}{|2i \times \pi \times \frac{15kHz}{5} \times 3.5k\Omega|} = 15nF \\ C_{HF} = \frac{1}{|2i \times \pi \times \frac{f_{SW}}{2} \times R_{COMP}|} = 0.9nF \end{cases} \quad (103)$$

Selecting the closest standard values for the compensation network, namely,

$$R_{COMP1} = R_{COMP2} = 3.65k\Omega$$

$$C_{COMP1} = C_{COMP2} = 15 \text{ nF}$$

$$C_{HF1} = C_{HF2} = 1 \text{ nF}$$

Figure 8-10 shows the Bode Plots of the power plant $\frac{1}{V_M} \times G_{id}(s) \times A_{CS} \times R_{CS}$, the current loop compensation gain $G_{ci}(s)$, and the resulting total open loop gain $T_i(s)$.

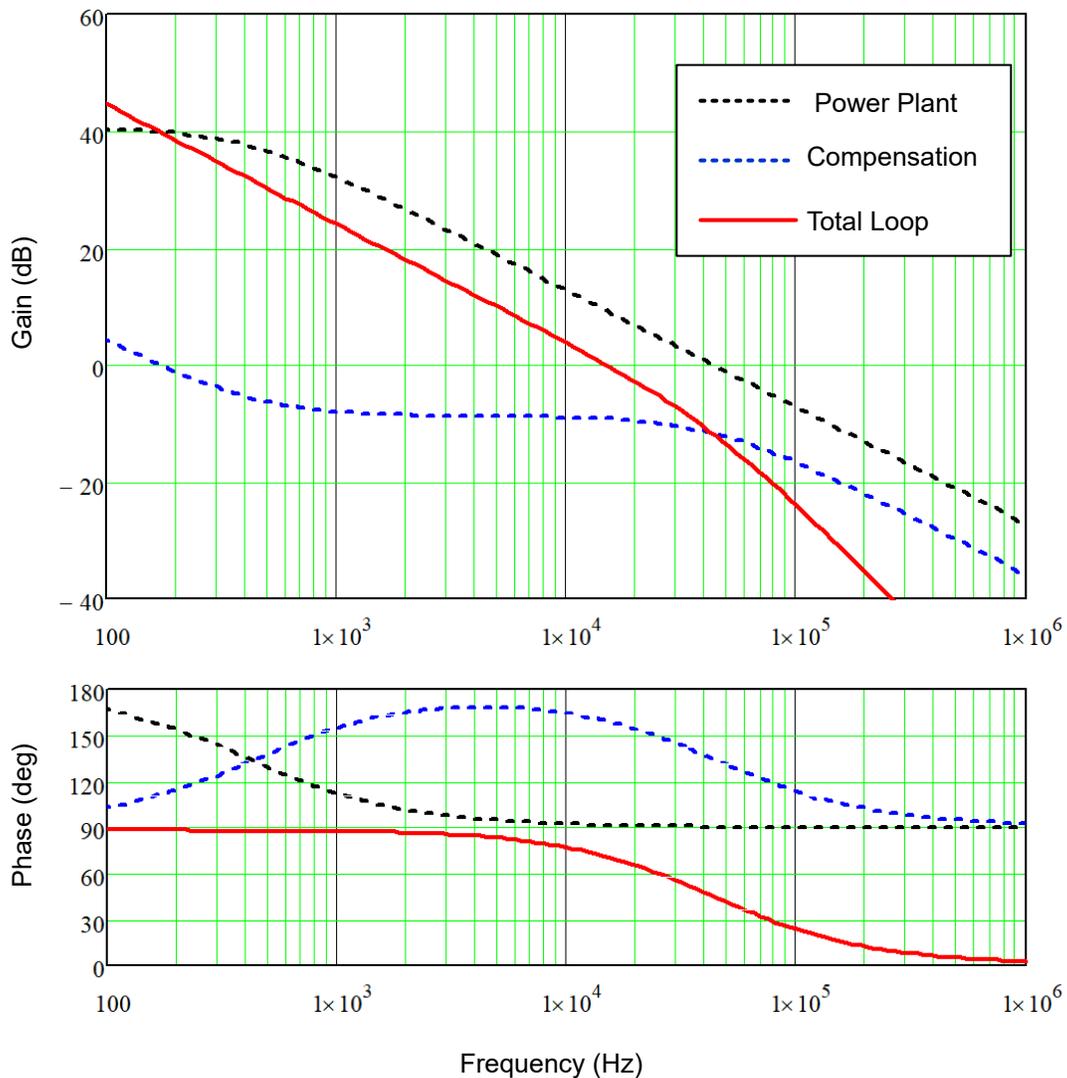


Figure 8-10. Bode Plots of the current loop

For buck mode, select the voltage loop crossover frequency at 1/10 of the current loop crossover frequency. According to [Equation 104](#), the compensation network for the voltage current loop is determined by:

$$\left\{ \begin{aligned}
 R_{LCOMP} &= \frac{R_{LFBT}}{K_{dc_BK} \times \left| \frac{1 + \frac{\omega_{Z_vl}}{2i \times \pi \times f_{CV}}}{1 + \frac{\omega_{Z_il}}{2i \times \pi \times f_{CV}}} \right| \times K_{ISET}} = \frac{26.7k\Omega}{40 \times 1m\Omega \times \left| \frac{1 + \frac{250kHz}{2i \times \pi \times 1.5kHz}}{1 + \frac{6.25kHz}{2i \times \pi \times 1.5kHz}} \right| \times 0.8} = 6.1k\Omega \\
 C_{LCOMP} &= \frac{1}{|2i \times \pi \times \frac{f_{CV}}{5} \times R_{COMP}|} = \frac{1}{|2i \times \pi \times \frac{1.5kHz}{5} \times 6.1k\Omega|} = 86nF \\
 C_{LHF} &= \frac{1}{|2i \times \pi \times 10 \times f_{CV} \times R_{COMP}|} = 1.7nF
 \end{aligned} \right. \quad (104)$$

Selecting the closest standard values for the compensation network, namely,

$$R_{LCOMP} = 6.2k\Omega$$

$$C_{COMP1} = 100 \text{ nF}$$

$$C_{HF1} = 1.5 \text{ nF}$$

[Figure 8-10](#) shows the Bode Plots of the power plant $G_{vs_BK}(s)$, the voltage loop compensation gain $G_{cv}(s)$, and the resulting total open loop gain $T_{vs_BK}(s)$.

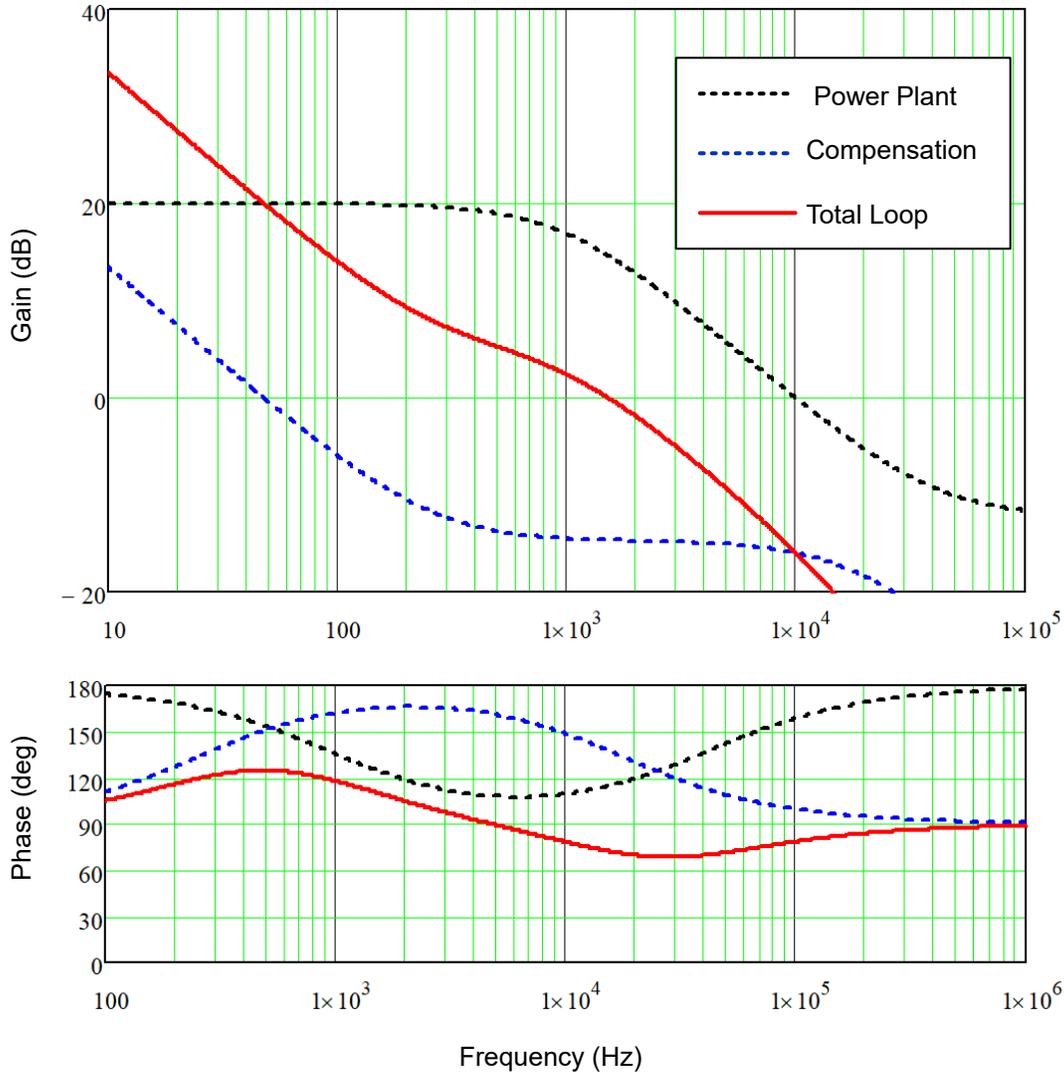


Figure 8-11. Bode Plots of the current loop

8.2.1.2.16 Soft Start

Current soft start can be programmed with a ceramic capacitor C_{SS} . Note that C_{SS} also determines the retry frequency when the converter is at under overvoltage condition. The soft start completes when the SS pin voltage reaches approximately 3 V. Choose full load current start-up time within $\Delta T_{SS} = 1$ ms in FPWM configuration, the capacitor C_{SS} can be chosen by :

$$C_{SS} = \frac{I_{SS} \times \Delta T_{SS}}{3V} = \frac{50\mu A \times 1ms}{3V} = 16.7nF \quad (105)$$

When SS/DEM1 and SS/DEM2 are connected together, double the capacitance to maintain the same startup time. Here we select standard ceramic capacitor $C_{SS} = 33$ nF.

8.2.1.2.17 PWM to ISET Pins

For digital solutions using PWM signals, an external two-stage RC filter is recommended to convert the PWM signal to a DC voltage feeding the ISET pin as shown in Figure 8-12. A two stage RC filter requires much smaller capacitance, and has a shorter delay time compared to a single stage filter. Please note, conversion errors occur if the PWM signal voltage levels are not well regulated.

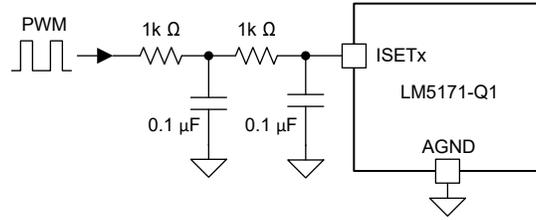


Figure 8-12. Two-Stage RC Filter to Convert the PWM into an Analog Voltage at the ISETx Pin

8.2.1.3 Application Curves

Graph Placeholder

Figure 8-13. Channel Inductor Current and IOUT Tracking ISET Command

Graph Placeholder

Figure 8-14. Diode Emulation Prevents Negative Current

Graph Placeholder

Figure 8-15. Channel Inductor Current and Monitor Responses to Dynamic DIR Change

Graph Placeholder

Figure 8-16. Start-Up Sequence Following UVLO Enable

Graph Placeholder

Figure 8-17. nSD Shutdown Latch

Graph Placeholder

Figure 8-18. ISET Sweep : Bidirectional Mode

Graph Placeholder

Figure 8-19. Efficiency : Buck Mode

Graph Placeholder

Figure 8-20. Efficiency : Boost Mode

Graph Placeholder

Figure 8-21. Thermal : Buck Mode

Graph Placeholder

Figure 8-22. Thermal : Boost Mode

8.3 Power Supply Recommendations

The LM5171-Q1-based converter is designed to operate with two differential voltage rails like the 48-V and 12-V dual battery system, or a storage system having a battery on one end and the Super-Cap on the other end. When operating with bench power supplies, each supply must be capable of sourcing and sinking the maximum operating current. This may require to parallel an Electronic load (E-Load) with the bench power supply (PS) to emulate the batteries, as shown in [Figure 8-23](#).

It can also be used with a voltage source on one end and a load on the other end if the outer voltage control loop is closed.

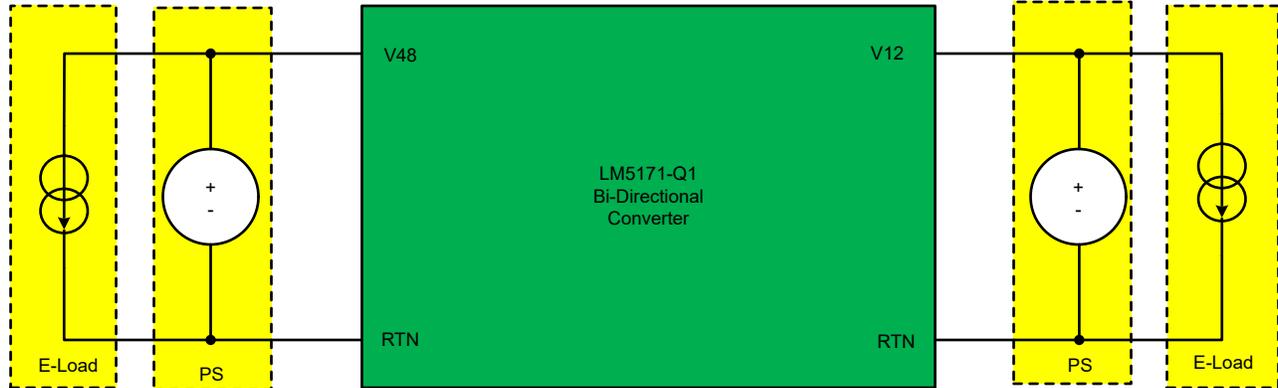


Figure 8-23. Emulated Dual Battery System With Bench Power Supplies and E-Loads

8.4 Layout

8.4.1 Layout Guidelines

Careful PCB layout is critical to achieve low EMI and stable power supply operation as well as optimal efficiency. Make the high frequency current loops as small as possible, and follow these guidelines of good layout practices:

1. For high power board design, use at least a 4-layer PCB of 2-oz or thicker copper planes. Make the first inner layer a ground plane that is adjacent to the top layer on which the power components are installed, and use the second inner layer for the critical control signals including the current sense, gate drive, commands, and so forth. The ground plane between the signal and top layers helps shield switching noises on the top layer away from affecting the control signals.
2. Optimize the component placements and orientations before routing any traces. Place the power components such that the power flow from port to port is direct, straight and short. Avoid making the power flow path zigzag on the board.
3. Identify the high frequency AC current loops. In the bidirectional converter, the AC current loop of each channel is along the path of the HV-port rail capacitors, high-side MOSFET, low-side MOSFET, and back to the return of the HV-port rail capacitor. Place these components such that the current flow path is short, direct and the special area enclosed by the loop is minimized.
4. Place the power circuit symmetrically between CH-1 and CH-2. Split the HV-port rail capacitors and LV-port rail capacitors evenly between CH-1 and CH-2.
5. If more than one LM5171-Q1 is used on the same PCB for multi phases, place the circuits of each LM5171-Q1 in the similar pattern.
6. Use adequate copper for the power circuit, so as to minimize the conduction losses on high-current PCB tracks. Adequate copper can also help dissipate the heat generated by the power components, especially the power inductors, power MOSFETs, and current sense resistors. However, pay attention to the polygon of the switch node, which connects the high-side MOSFET source, low-side MOSFET drain, power inductor, and the controller SW pin. The switch node polygon sees high dv/dt during switching operation. To minimize the EMI emission by the switch node polygon, make its size sufficient but not excessive to conduct the switched current.
7. Use appropriate number of via holes to conduct current to, and heat through, the inner layers.
8. Always separate the power ground from the analog ground, and make a single point connection of the power ground, analog ground, and the EP pad, at the location of the PGND pin.
9. Minimize current-sensing errors by routing each pair of CSA and CSB traces using a kelvin-sensing directly across the current sense resistors. The pair of traces must be routed closely side by side for good noise immunity.
10. Route sensitive analog signals of the CS, FBLV, FBHV, IPK, VSET, IMON, COMP and OVP pins away from the high-speed switching nodes (HB, HO, LO, and SW).
11. Route the paired gate drive traces, namely the pairs of HO1 and SW1, HO2 and SW2, LO1 and return, and LO2 and return, closely side by side. Route CH-1 gate drive traces in symmetry with that of CH-2.

12. Place the IC setting, programming and controlling components as close as possible to the corresponding pins, including the following component: R_{OSC} , R_{CFG} , R_{DT} , C_{COMP1} , R_{COMP2} , C_{COMP1} , C_{COMP2} , C_{HF1} , C_{HF2} , R_{HVC} , R_{LVC} , C_{HVC} , C_{LVC} , C_{HVHF} and C_{LVHF} .
13. Place the bypass capacitors as close as possible to the corresponding pins, including C_{HV} , C_{VCC} , C_{VDD} , C_{VREF} , C_{VSET} , C_{HB1} , C_{HB2} , C_{OVP} , C_{IPK} , C_{ISET} , C_{CS1} , C_{CS2} as well as the 100-pF current sense common-mode bypassing capacitors.
14. Flood each layer with copper to take up the empty areas for optimal thermal performance.
15. Apply heat sink to components as necessary according to the system requirements.

8.4.2 Layout Examples

The following figures are some examples illustrating these layout guidelines. For the detailed PCB layout artwork of the LM5171-Q1 Evaluation Module (LM5171EVM-BIDIR), please refer to the [LM5171-Q1 EVM User's Guide](#) (TBD).

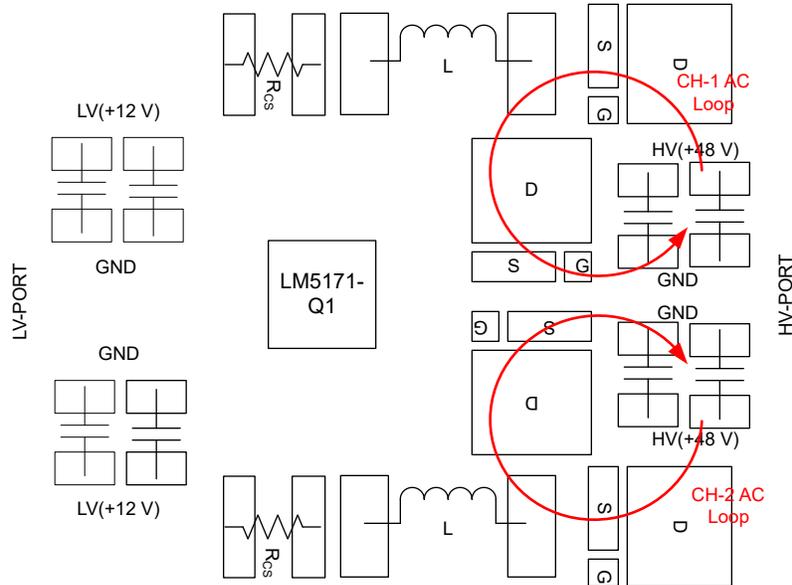


Figure 8-24. A Layout Example of Dual-Channel Power Circuit Placement

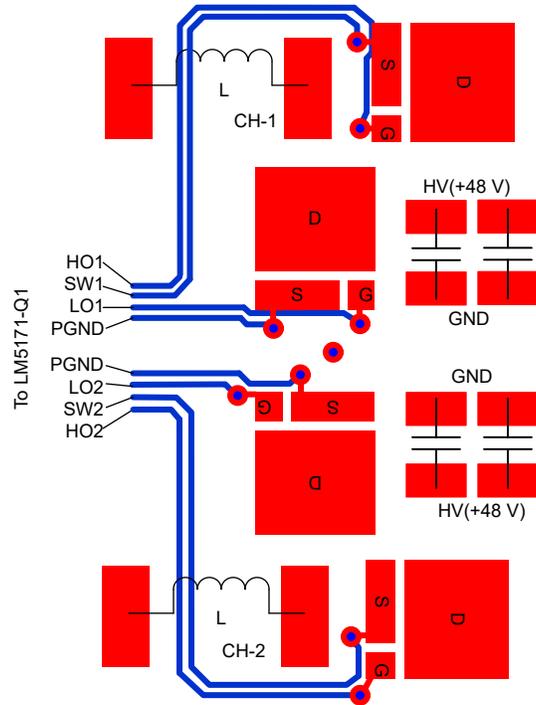
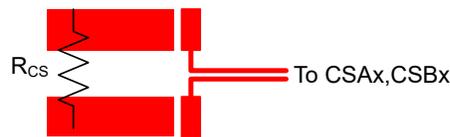


Figure 8-25. A Layout Example of MOSFET Gate Drive Routing



(a) Kelvin Connect of Resistor without Sense Pins



(b) Kelvin Connect of Resistor with Sense Pins

Figure 8-26. A Layout Example of Current Sense Routing

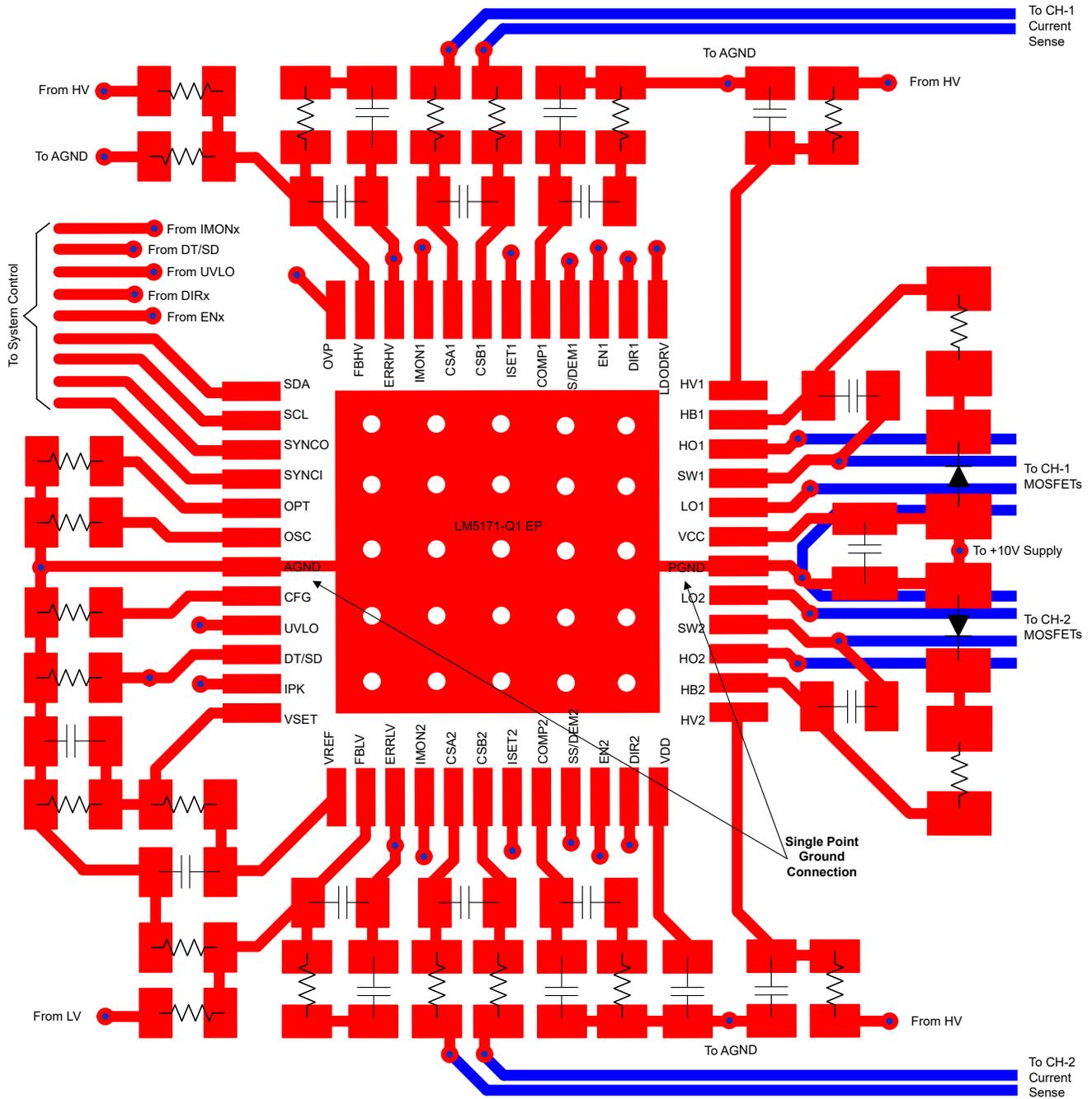


Figure 8-27. A Layout Example of LM5171-Q1 Critical Signal Routing

ADVANCE INFORMATION

9 Device and Documentation Support

9.1 Device Support

9.1.1 Development Support

For development support, see the following:

- [LM5170-Q1](#)
- [LM25118-Q1](#)
- [LM5118-Q1](#)
- [LM5001-Q1](#)
- [LM5160-Q1](#)
- [LM5161-Q1](#)

9.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on [ti.com](#). Click on *Subscribe to updates* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

9.3 Support Resources

[TI E2E™ support forums](#) are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

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9.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

9.6 Glossary

[TI Glossary](#) This glossary lists and explains terms, acronyms, and definitions.

10 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
XLM5171QPHPRQ1	ACTIVE	HTQFP	PHP	48	2500	TBD	Call TI	Call TI	-40 to 150		Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSELETE: TI has discontinued the production of the device.

(2) **RoHS:** TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (Cl) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "-" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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GENERIC PACKAGE VIEW

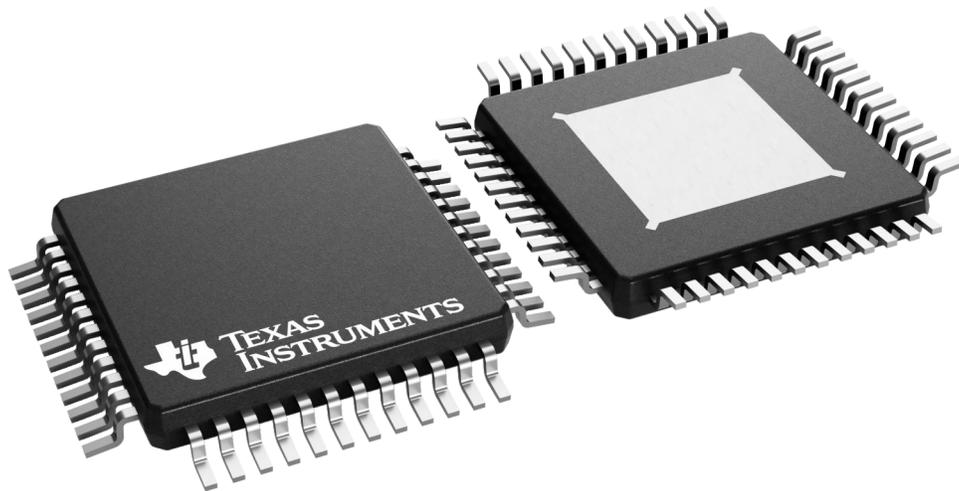
PHP 48

TQFP - 1.2 mm max height

7 x 7, 0.5 mm pitch

QUAD FLATPACK

This image is a representation of the package family, actual package may vary.
Refer to the product data sheet for package details.



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